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NLO Materials Workshop

DERA Malvern UK

20-21 September 1999

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NLO Materials Workshop

Woodward Building, DERA Malvern 20-21 September 1999

Monday 20 September

09.15	Registration and Coffee
09.45	Introduction and Welcome Jayne Ackroyd Manager EOP Dept DERA
10.00	NLO Materials – Key Technical Issues A W Vere DERA
10.15	ZGP – The DERA Programme C J Flynn DERA
10.35	ZGP annealing studies L L Chng DSO Singapore
10.50	Non-linear absorption and damage measurements in chalcopyrite crystals Shekar Guha AFRL/MLPO
11.05	ZGP –crystals: homogeneity region, real defects and optical quality V Voevodin R&D Center 'ATOM Tomsk
11.25	Break
11.45	Secondary ion mass spectrometry analysis of CdGeAs ₂ J Solomon University of Dayton
11.55	Refractive Index measurements and phase-matching calculations in chalcopyrites D Zelmon AFRL/MLPO
12.10	Analysis of CGA using Thermal admittance spectroscopy Steven Smith University of Dayton, Research Institute
12.15	High Frequency ZGP Tandem OPO J A C Terry DERA

We would like to thank the following for their contribution to the Workshop:

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Defence Evaluation and Research Agency

12.45	Buffet Lunch
14.00	Recent Advances in chalcopyrites for mid to far IR frequency conversion P Schunemann
14.20	NLO materials at IOM A Gribenyukov. Institute of Optical Monitoring Tomsk
14.35	ZGP Growth and thermal treatment G Verozubova IOM Tomsk Russia
14.50	Optical and electron transport properties of ZnGeP ₂ andCdGeAs ₂ B Bairamov Ioffe Institute St Petersburg Russia
15.20	Tea
15.50	Identification of defects in ZGP by EPR/ENDOR L Halliburton University of West Virginia
16.10	Theory of defects in chalcopyrites R Pandey University of Michigan
16.40	Defect energy and band structure of ZGP Keith Nash / Mike Fearn DERA Malvern
16.50	Tellurium-selenium alloys M Ohmer Materials Labs WPAFB Dayton Ohio
17.00	Discussion – Calcopyrites II
19.30 (coac	Workshop Dinner h collection from hotels at approx 19.00)

Tuesday 21 September

09.00	Non-linear Optical Crystal development at AFRL materials directorate N Fernelius AFRL/MLPO
09.30	Non-linear crystals for IR region in DTIM L. Isaenko Institute of Monocrystals Novosibirsk
10.00	Spectroscopic properties of Pure and Rare-Earth-ion-doped Non-linear Crystals for the mid IR A Elisseev Institute of Monocrystals Novosibirsk
10.15	LiNbO ₃ H Gallagher U. of Strathclyde
10.30	Growth and Characterisation of photorefractive materials C Finnan University of Strathclyde
10.45	Coffee
11.00	Laboratory visits (or free discussion period)
12.30	Lunch
13.30	Developments in PPLN fabrication P Smith University of Southampton
13.50	Growth of phosphates and arsenates for periodic poling R Ward/K Hutton University of Oxford
14.10	Tunable quasi-phase-matched SHG of a CO ₂ laser in GaAs Shekar Guha AFRL/MLPO
14.30	Periodically –poled BaTiO ₃ P Schunemann Lockheed Martin, Nashua
14.50	Panel discussion - Quasi-phase matching
15.20	Tea and informal discussion session on issues arising from he workshop and debate on future research
16.00	Workshop closes. (The room will be available for informal discussion groups until 17.00)

21/09/99

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Bulk Optical Materials at DERA Malvern

CaWO₄ Ruby YAG Laser materials 1965

LiNbO₃ LiTaO₃ **NLO Materials** 1966

New NLO programme -wide materials survey 1967

tungsten bronzes BSN SBN, KLN and others

Chalcogenides Ag₃AsS₃ AgGaSe₂ AgGaS₂

Solution growth KDP, KTN Expanding programme 1970's

Bulk growth (CZ and Bridgman) CdTe CdSeTe

DERA

Welcome

To the

Non-inear Optical aterials Workshop

DERA Malvern 20 September 1999

Jayne Ackroyd
Business Group Manager EO Protection

DERA

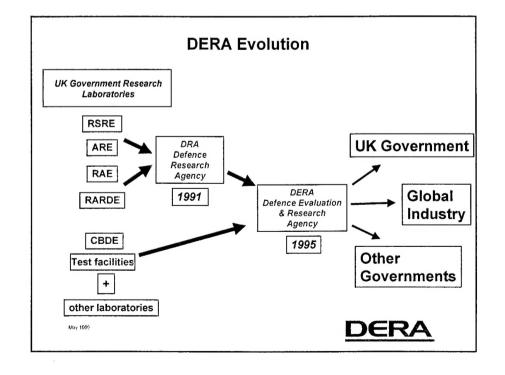
Workshop Benefits

- **ℜ Collaboration**
- ⊞ Best use of funding and resources



DERA

What is DERA? The largest Research and Technology organisation of its kind in Europe £1 billion turnover Owned by the UK Government Our mission is: to be the main advisor to the UK Government on technology issues to create wealth by technology transfer to industry



Bulk Optical Materials at DERA Malvern

Laser growth concentrated on eye-safe lasers Slow contraction of programmes Alternatives to YAG e.g YAP YLF and related materials 1985-90

Declining interest in NLO Materials Too difficult and limited markets 1985-90

Improved growth technology and emergence of ZGP, AgGaSe₂ as potential high power OPO and SHG materials reinvigorates NLO programme

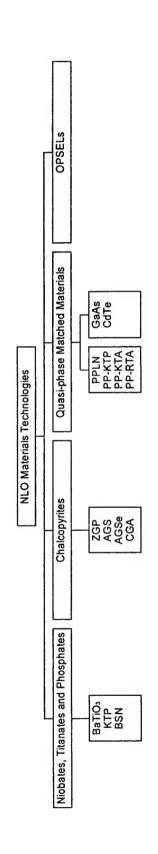


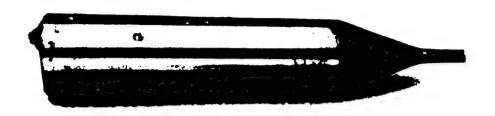
NLO Materials - What Next?

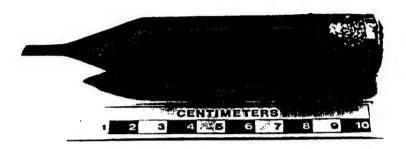
A short Introduction to the range, content and key issues for discussion at the Workshop and beyond

A W Vere DERA Malvern

NLO Materials





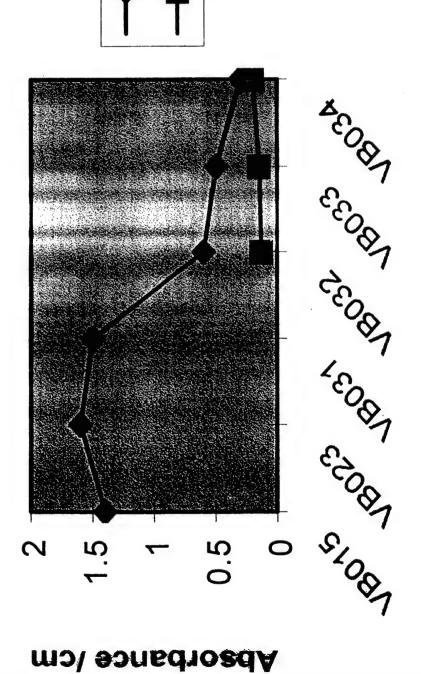








2 micron absorbance



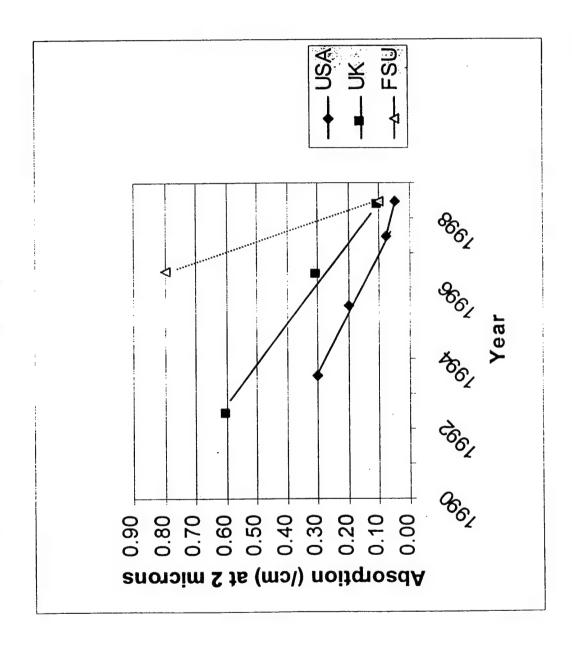
Post-anneal

Pre-annea

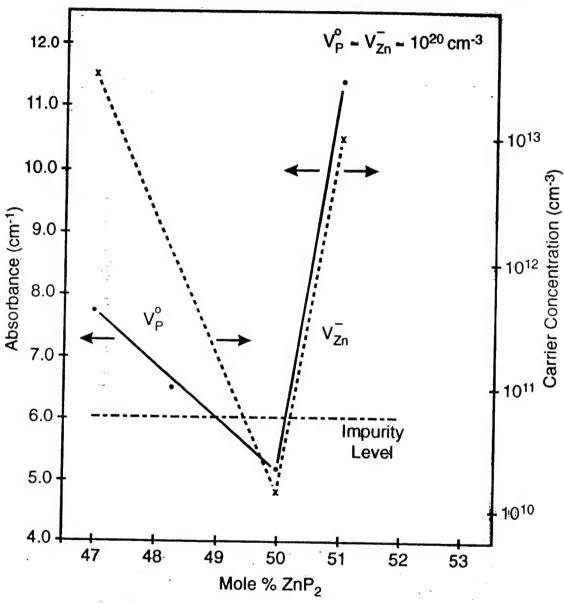
Crystal No.

2 micron absorption in ZGP

8



Variation of Absorbance and Carrier Concentration with Stoichiometry



P G Schunemann, Control of Stoichiometry in Semiconductor Heterostructures (Workshop – Bad Suhl, Germany, 1995)

V S Grigor'eva et al, Sov Tech Phys Lett 1 No 2 (1975) 61

Impurity Level (Hypothetical)



ZnGeP2: DERA Malvern Programme

Tony Vere, Colin Flynn, Phil Smith DERA Malvern



Key Properties of ZingeP₂

High vapour pressure ($P_{p_2} \sim 10^{10}$ over melt)

High melting point (1028 °C)

Brittle fracture mode

Thermal expansion coefficient (5.0-6 \parallel c, 7.8-6 \perp c)

Potential precipitation problems

Band edge optical absorption tail



Growth programme: OBJECTIVE

Grow single crystal ZGP

Low absorption ($< 0.1 \text{cm}^{-1} \text{ at } 2.128 \mu\text{m}$)

Understand optical absorption/scattering mechanisms

Fabricate optical parametric oscillator (OPO) element for use in mid IR.

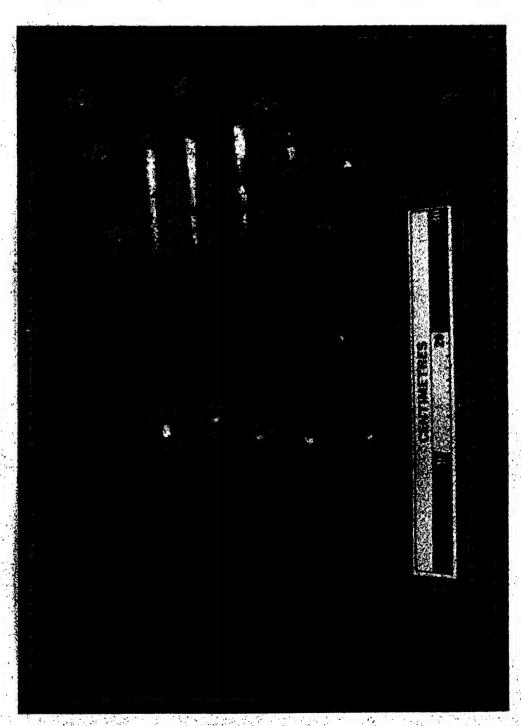


Growth programme: HISTORY

- Initially, starting material produced by Wafer Tech
- produced crystals with mosaic cracking for a few years Vertical Bridgman (VB) & Horizontal Bridgman (HB)
- VB now producing good single crystal (PBN crucibles, [016] seed, insulation around seed holder)
- HB improving but abandoned due to VB success
- Collaboration with Institute of Optical Monitoring (IOM), Tomsk
- Starting material now obtained from IOM





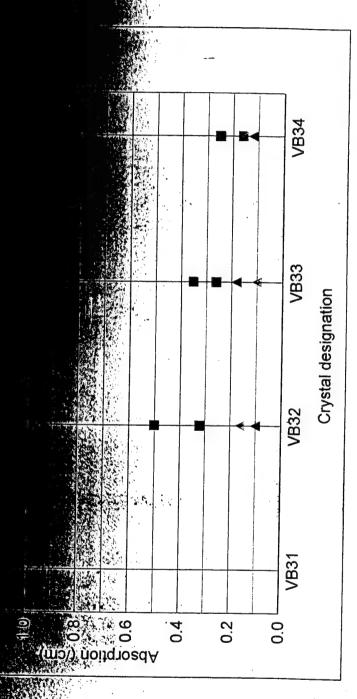


Comparison of starting materials

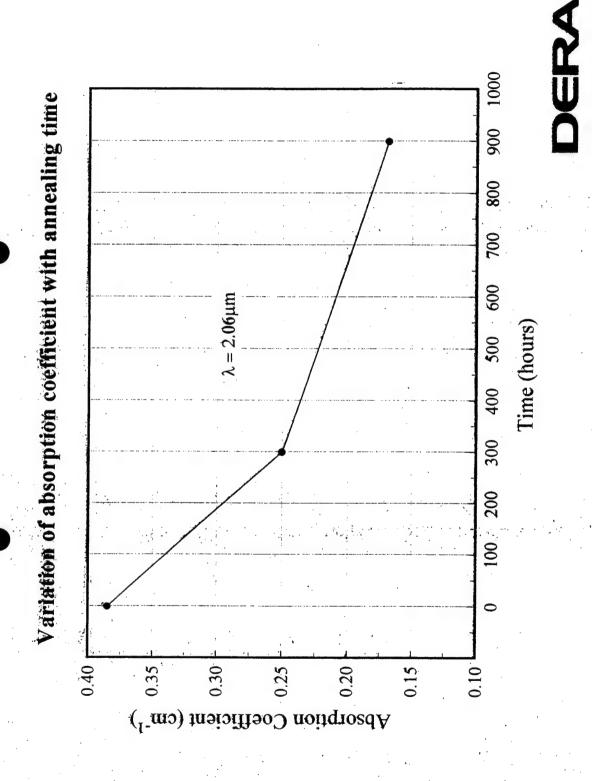
Glow Discharge Mass Spectrometry (GDMS) data for IOM and Wafer Tech starting material.

	mota ddd	' atom
Element	MOI	Wafer Tech
S	120	<20
Mn	29	200
Fe	24	280

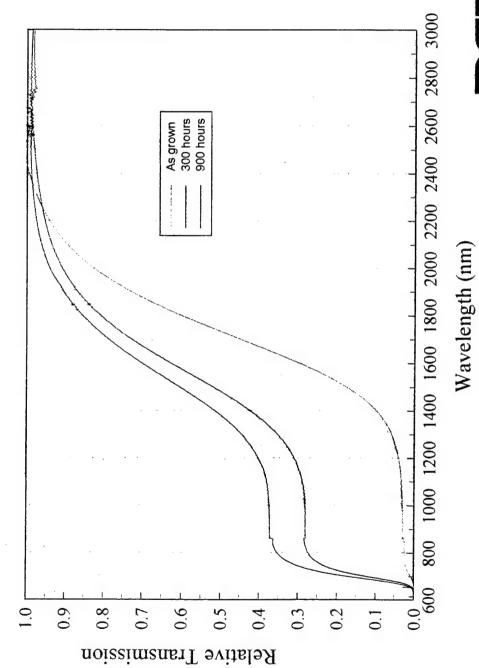




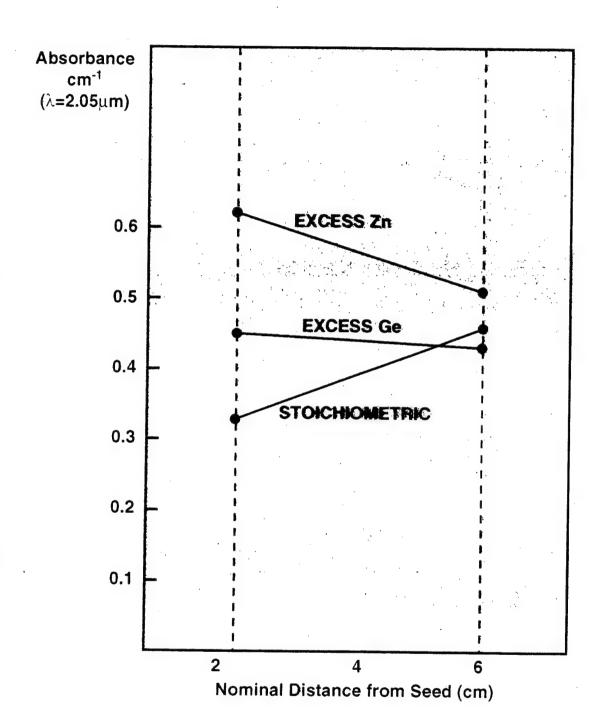




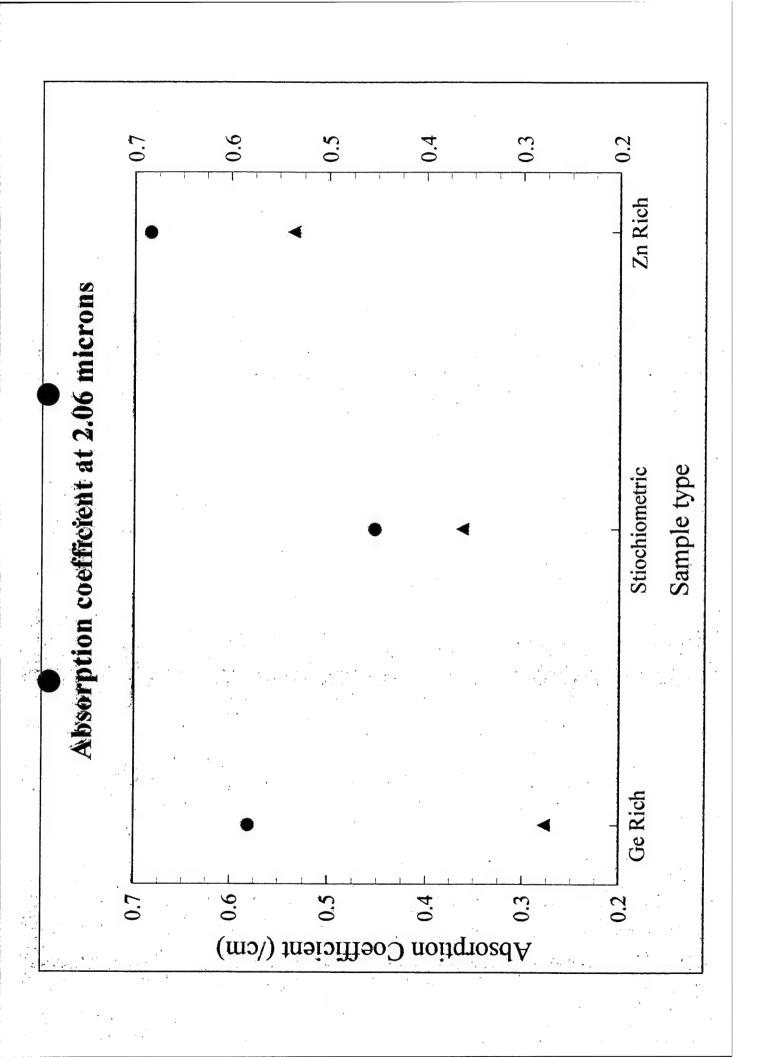
Effect of annealing on the transmission of ZGP



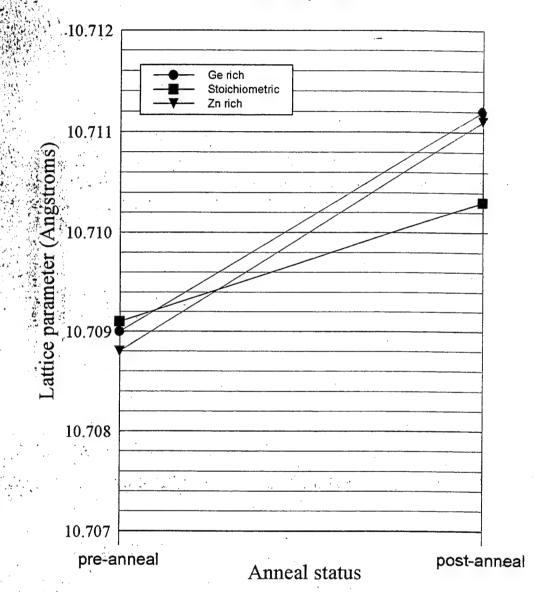






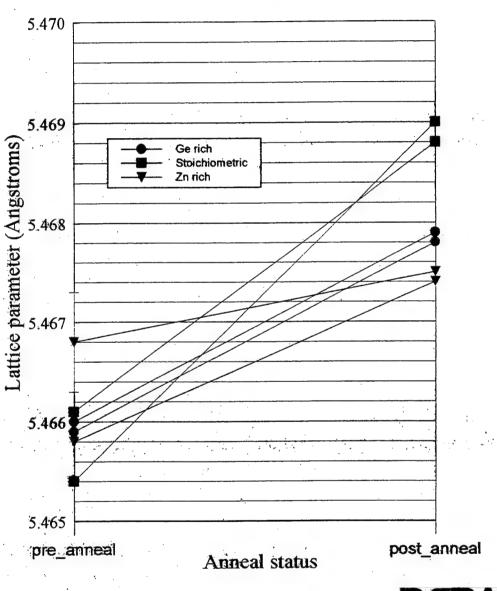


Lattice parameter for <001> direction in first-to-freeze, c-axis slices

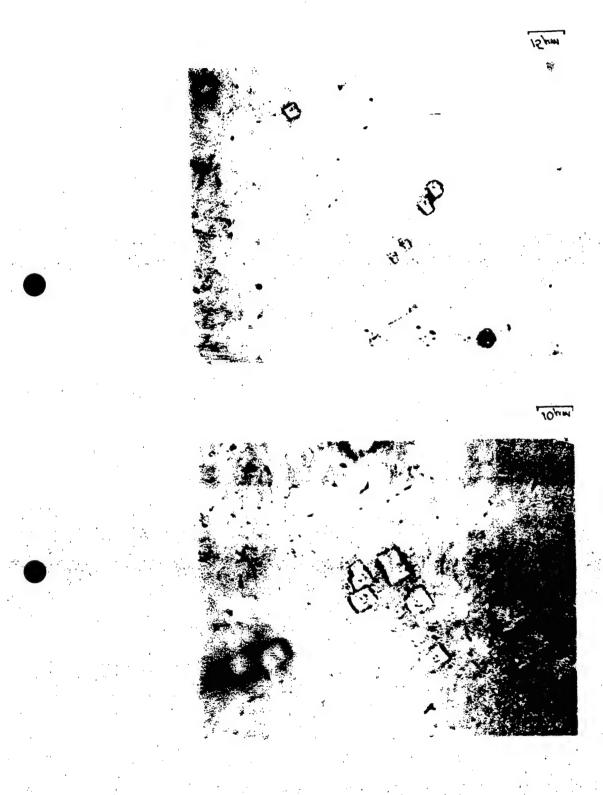




Lattice parameter for <100> & <010> directions in first-to-freeze, c-axis slices







Summary

- Growing good quality single crystal ZGP
- Need to control stoichiometry of starting charge to avoid precipitation
- Absorption coefficient 'bottoming out' but still worthwhile pursuing annealing studies
- Now need to concentrate programme on identifying causes of absorption



ZGP Annealing Studies

L L Chng, Y-W Lee and H-G Ang

DSO National Laboratories, Singapore

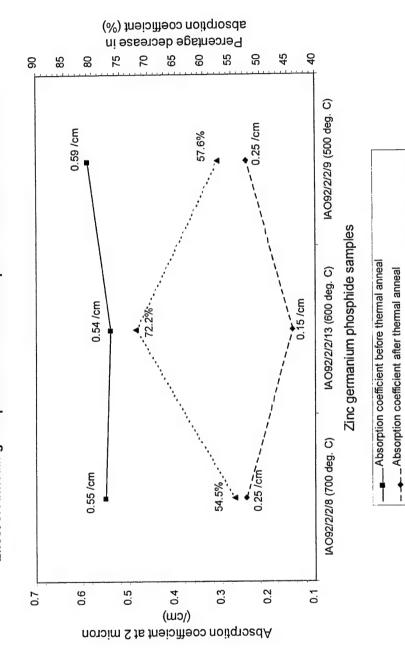
C J Flynn, P C Smith and A W Vere

DERA Malvern UK



Absorption of IAO Zinc Germanium Phosphide Samples Effect of Annealing Temperature on the Optical

Effect of Annealing Temperature on the Absorption Coefficient at 2 micron

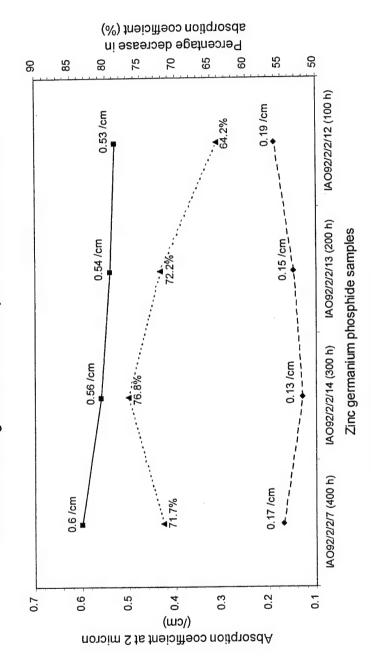


DSO NATIONAL LABORATORIES

...▲... Percentage decrease in absorption coefficient after thermla anneal

Effect of Annealing Time on the Optical Absorption of IAO Zinc Germanium Phosphide Samples

Effect of Annealing Time on the Absorption Coefficient at 2 micron



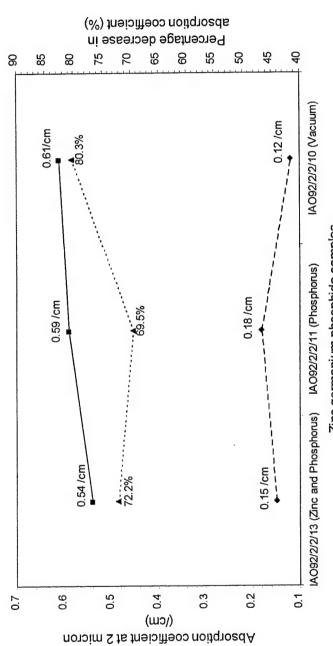


....

Absorption coefficient before thermal anneal

Absorption of IAO Zinc Germanium Phosphide Samples Effect of Annealing Vapour Pressure on the Optical

Effect of Annealing Vapour Pressure on the Absorption Coefficient at 2 micron



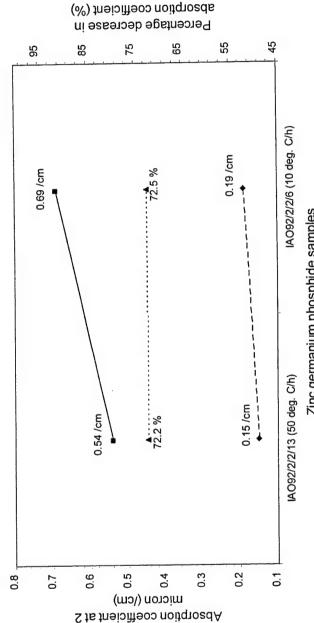
Zinc germanium phosphide samples





Absorption of IAO Zinc Germanium Phosphide Samples Effect of Annealing Heating/Cooling Rate on the Optical

Effect of Annealing Heating/Cooling Rate on the Absorption Coefficient at 2

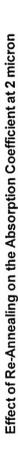


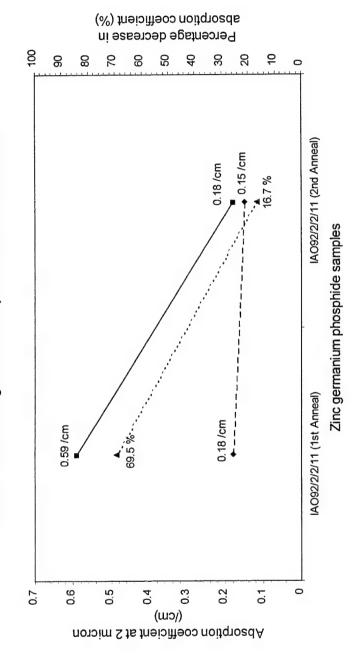
Zinc germanium phosphide samples

...▲... Percentage decrease in absorption coefficient after thermal anneal Absorption coefficient before thermal anneal ----Absorption coefficient after thermal anneal



Effect of Re-Annealing on the Optical Absorption of IAO Zinc Germanium Phosphide Samples





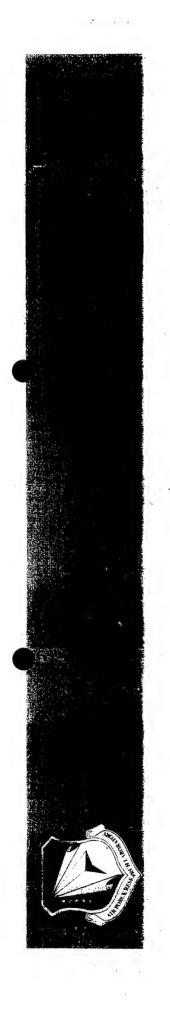


Absorption coefficient before thermal anneal

Reduction on the Near-Infrared Absorption of Zinc Germanium Phosphide Through Post-Growth Annealing Treatment

- Optimal annealing temperature of ZGP is 600°C.
- Optimal annealing time should be 200 400 h.
- Optimal annealing atmosphere is vacuum.
- Thermal annealing of zinc germanium phosphide decreased the 2-µm optical absorption by at least
- Rate of heating and cooling ZGP did not affect the percentage decrease in the 2 µm absorption coefficient.
- Re-annealing ZGP reduced further the 2 µm absorption coefficient.

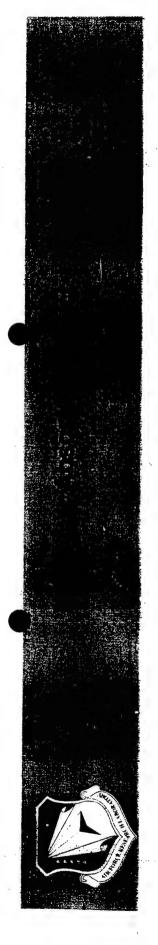


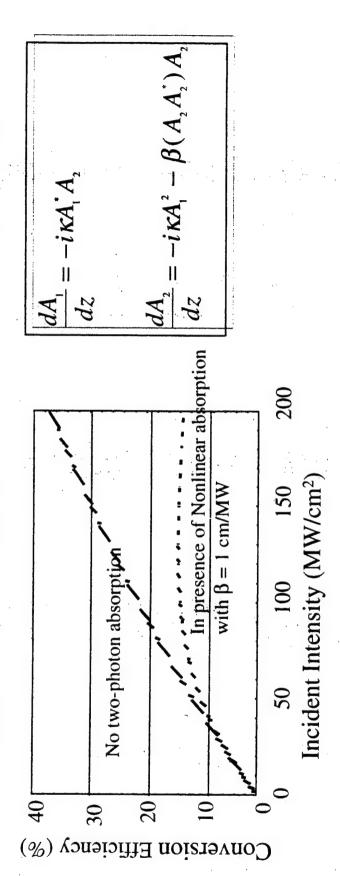


Shekhar Guha, Michael Eaton, F. Ken Hopkins and Melvin C. Ohmer AFRL/MLP Wright Patterson Air Force Base, OH 45433-7702

shekhar.guha@afrl.af.mil

NLO99 Workshop, DERA, Malvern, UK, 20 - 21 September, 1999



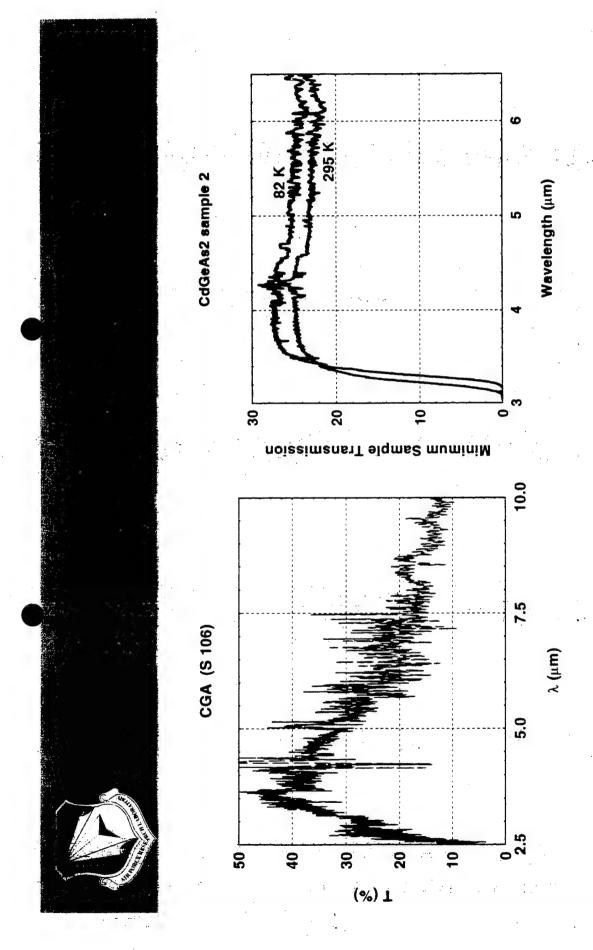


Presence of two-photon absorption limits high power generation



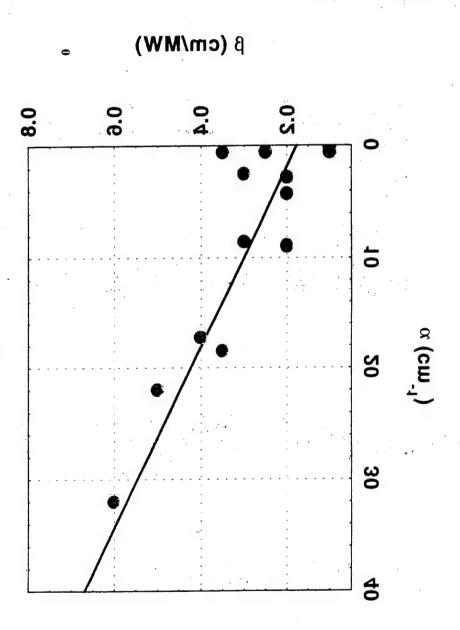
Sample name	Sample thickness (μm)	Carrier concentration (10 ¹⁶ cm ⁻³)	Absorption coefficient (cm ⁻¹)	tion coeffici (cm ⁻¹)	ent
			300 K)6	90 K
			-	==	\dashv
2G	974	0.4	2.5 2.8	9.0	0.1
40	912	4.9	19 9	8.5	4.2
4M	934	6.9	22 9	=	9.0
40	296	7.8	32 18	10	9.0

Sample size: ~ 1 cm x 1 cm x 1 mm c axis in the polished face



Bandgap of CGA increases with temperature increase



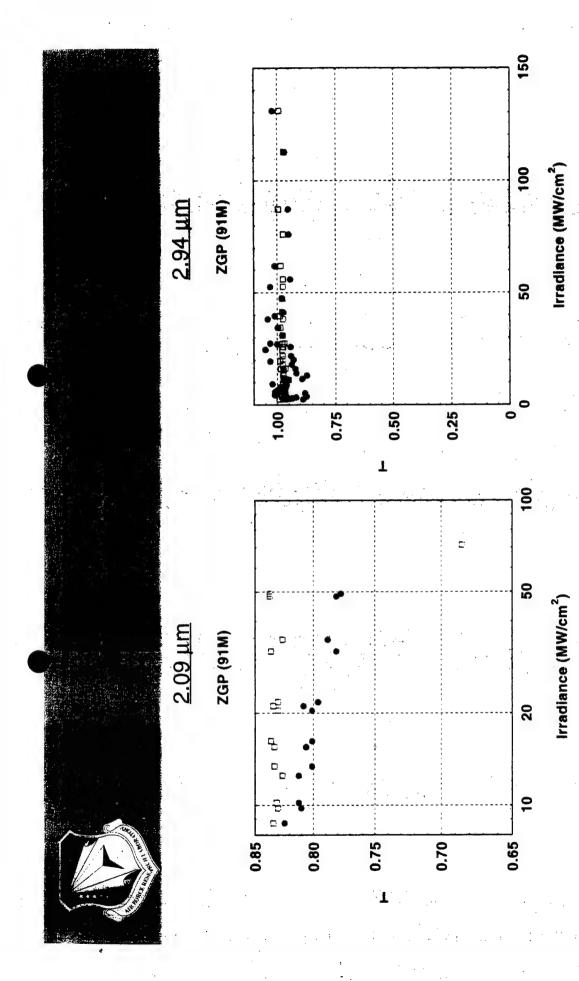




⅓ (cm/MW)

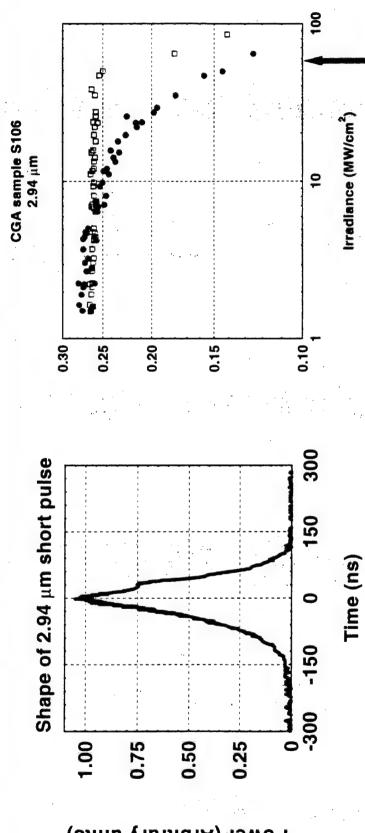
Sample		SG	4Q	4W	40
JE		0.3	0.35	3.0	9.0
300 K	4	0.2	2.0	2.0	0.4
90 K	=	0.25	0.2	7.5	-
ス	4	1.0	0.3	1.0	0.35

Anisotropy Temperature Dependence



Nonlinearity and damage in $ZnGeP_2$ observed at 2.09 μm but not at 2.94 μm





Effective Nonlinearity < 0.05 cm/MW

Damage at 52 MW/cm²



Sample Number	Coating status	Linear Abs	Linear Absorption (cm-1)	Nonlinear	Nonlinear Absorption >
		Ordinary	Extraordinary	Ordinary	Extraordinary
92H	Uncoated	0.29	1.04	0.04	0.12
92N	Standard AR	0.33	0.70	0.08	0.35
92P	Standard AR	0.32	0.69	0.06	0.20
920	ARD052x98	0:30	0.75	0.12	0.25

Strong anisotropy in the NLA of ZnGeP2 is observed

ZGP - crystals: homogeneity region, real defects and optical quality

R@D Center ATOM
(Advanced Technologies for Optical Materials)

Semiconductor Material Science Laboratory Siberian Physico-Technical Institute at Tomsk State University

Crystals	GaSe	ZnGeP ₂	CdGeAs ₂	Tl ₃ AsSe ₃
Transparency region, μm	0.7-16	2.1 2.5-8 10	2.5-16	2-17
Optical losses in transparency region, cm ⁻¹	< 0.1	< 0.2< 0.1 0.2	< 0.2	< 0.1
Monocrystals size				
diameter, mm	30	30	20	40
length, mm	100	80	50	80
Nonlinear elements size, mm×mm×mm	≤ 20×20×20	≤ 15×15×25	≤ 10×10×15	-

MOLTECH Corp. (USA), EKSMA (Lithuania), ELAN (St.-Petersburg, Russia) and other.

Chronology of ZnGeP₂ researches in Siberian Physico-Technical Institute

- 1973 1975 Coping the ZnGeP2 technology developed in Ioffe PTI
- 1978 beginning the works on development new technology of ZnGeP₂ growing (V.G. Voevodin)
- 1980 producing large ZnGeP₂ single-crystal ingots of high optical quality (α < 0.1 cm⁻¹ @ 2.5 8.5 mkm)
- 1982 1986 the cycle of main publications on PFC in ZnGeP₂ (SPTI, IAO, IGP, IAP)
- 1986 1988 transfer the ZnGeP₂ technology to SD**3** "Optika" (now IOM) together with the equipment and part of servicing staff
- 1990 present together with R&D Centre "ATOM" team-work on the solving of the following problems:
 - thermodynamical calculations of ZnGeP₂ homogeneity region;
 - clearing up the nature of defects in ZnGeP₂;
 - search the reliable ways of reduce the optical losses in the range λ < 2.5 mkm

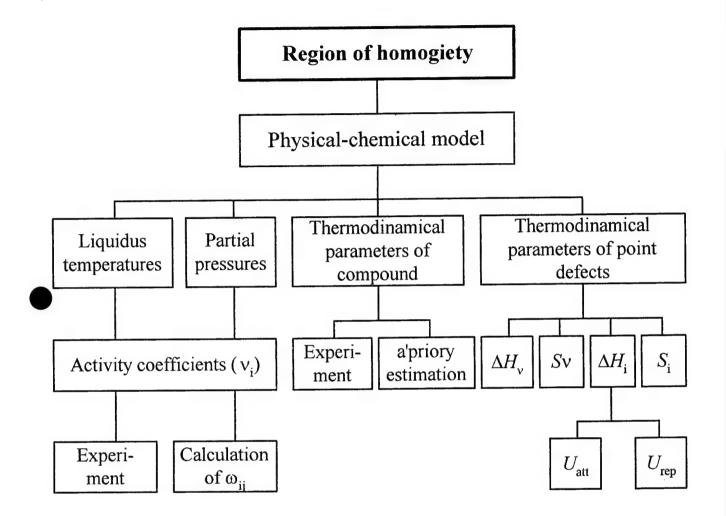


Table II.Entropies and enthalpies of neutral vacancies in ZnGeP2

Element	Zn	Ge	P
Entropy in J/(mol K)	41.6	54.4	52.4
Enthalpy in kJ/mol	18.3	28.9	16.8

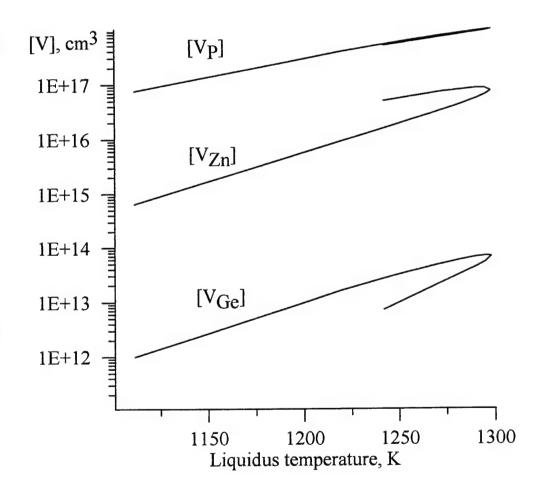


Fig. 3. The neutral vacancies concentration in $ZnGeP_2$ as a function of liquidus temperature; cut Ge - ZnP_2 .



Ionisation energy
$$E_{tM} = I_{M}(m^{*}/m)(z/\epsilon + 5C/6)^{2}$$
, $C = 1/\epsilon_{0} - 1/\epsilon$ (11)

where I_M is first ionisation potential of atom M, z is effective charge, ϵ is static dielectric constant, ϵ_0 is high-frequency dielectric constant.

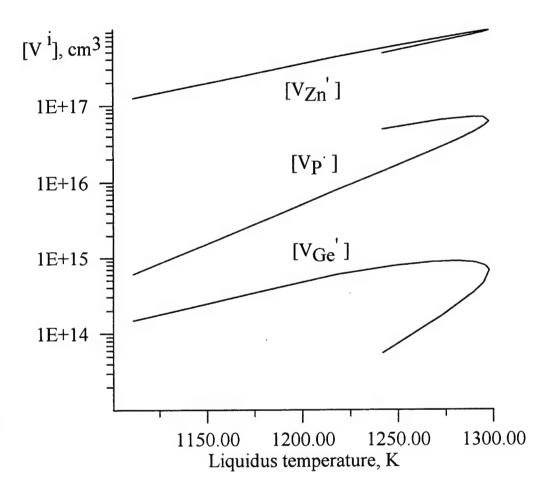


Fig. 4. The ionised vacancies concentration in $ZnGeP_2$ as a function of liquidus temperature; cut $Ge - ZnP_2$.



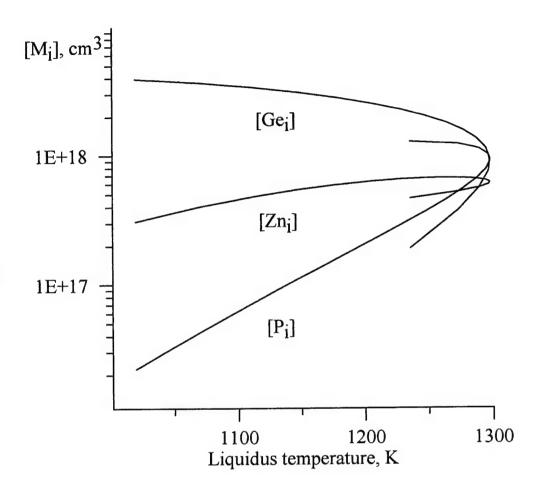


Fig. 5 Interstitials concentration in $ZnGeP_2$ as a function of liquidus temperature; $Ge-ZnP_2$ - cut

19

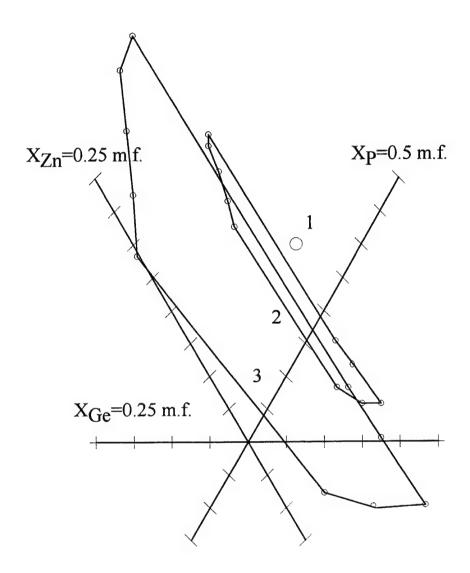


Fig. 6. ZnGeP₂ region of homogietity, estimated as deviation of corresponding concentrations of point defects.

T, K: 1 - 1298; 2 - 1270; 3 - 1210.

Axes correspond to

 X_{Zn} =0.25 mol fractions, X_{Ge} =0.25 mol fractions, X_P =0.5 mol fractions.

Value of scale deviation is 0.0003 mol %.

14

Optical losses in ZGP at λ < 2.5 μ

Versions of main reason for the losses

A: photoionization of deep acceptors (Vzn?) [Brudnyi ao]

B: light scattering by microinclusions of Zn and Ge [Voevodin ao]

C: light scattering by β -ZGP clusters or photoionization of Zn_{Ge} -Ge_{Zn} antisite pairs [Shimony ao, J. Cryst. Growth, <u>198/199</u> (1999) 583-587

Post-growth treatment of ZGP for losses decreasing

1.	Annealing at 500-550°C	[Rud' ao]	A. B?
2.	Electron (e-) irradiation	[Brudnyi ao]	C?
3.	Laser & 1.06 µ annealing	[Voevodin ao]	B.
4.	γ-irradiation	[Shuneman ao]	A. B?
5.	Ultrasonic treatment	[Voevodin ao]	B. C?

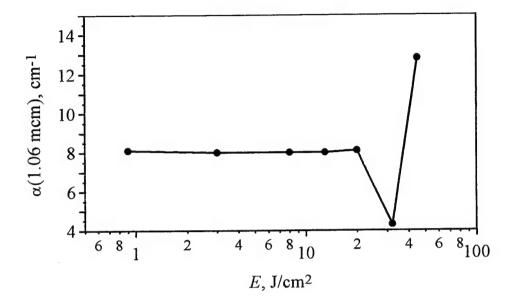
LT-annealing of ZGP crystals

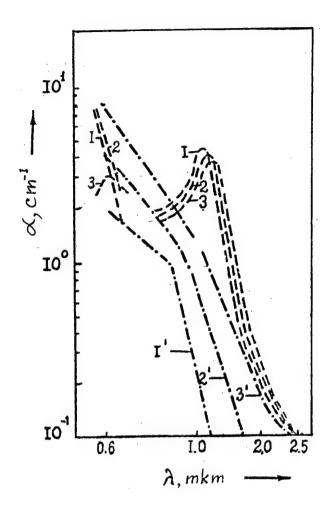
Sample	As	s-grown	Condition		Annealed			
#	α , cm ⁻¹ $(\lambda=2.5 \mu)$	cm ⁻¹ α , cm ⁻¹ N 2.5 μ) $(\lambda=5 \mu)$ cm		of LTA	α , cm ⁻¹ $(\lambda=2.5 \mu)$	α , cm ⁻¹ $(\lambda=5 \mu)$	$N_{\rm d}$, cm ⁻²	
187	0.5	0.3	10 ⁶	550°C 150 h ZGP powder	0.2	0.01	3·10 ⁵	
165	1.0	0.7	5·10 ⁴	550°C 150 h 2 at P ₄	0.3	0.07	10 ⁵	
282	0.8	0.3	10 ⁵	550°C 150 h 1.3 at P ₄	0.3	0.1	8·10 ⁴	
273	1.8	1.8	5·10 ⁴	550°C 150 h 2 at P ₄	0.05	0.04	3·10 ⁴	

Ultrasonic treatment of ZGP crystals

Sample		As-grov	vn		A	After treatm	nent	
#	α , cm ⁻¹ (λ =2.5 μ)	α , cm ⁻¹ $(\lambda=5 \mu)$	$N_{\rm d}$, cm ⁻²	$N_{\rm i}$, cm ⁻²	α , cm ⁻¹ $(\lambda=2.5 \mu)$	α , cm ⁻¹ $(\lambda=5 \mu)$	$N_{\rm d}$, cm ⁻²	N_{i} , cm ⁻²
188	1.8	1.8	10 ⁵	2·10 ²	1.3	1.3	7·10 ⁴	10 ²
306	0.8	0.6	6·10 ⁴	2·10 ³	0.5	0.4	4·10 ⁴	10 ³

Absorption coefficient of ZnGeP₂ at wavelength $\lambda = 1.06$ mcm versus energy density of pulsed laser radiation ($\tau = 1$ ms)

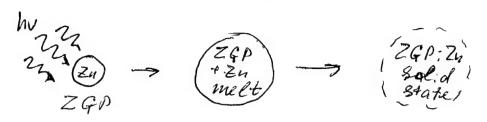


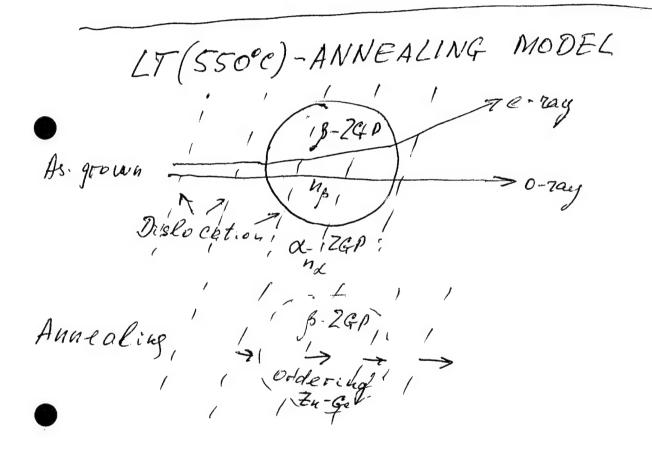


Calculated spectra of light losses in $ZnGeP_2$ with microinclusions of Zn (1-3) and Ge (1'-3').

Diameter of inclusions is : 1, 1' - 200 Å; 2, 2' - 400 Å; 3, 3' - 600 Å; Volume fraction is $C=10^{-6}$

LASER@1.06p ANNEALING MODEL





Post-annealed

X-ZGD

>e-ray

na

na

SIMS Analysis of CdGeAs2

J. S. Solomon* University of Dayton Research Institute Dayton, OH 45469-0167 USA



* Work supported by the Materials and Manufacturing Directorate Air Earna Dannarch I aharatan, United States Air Force



lain Features of SIMS

Information depth in the "monolayer range"

Detection of all elements and isotopes

Extremely high elemental sensitivity for many elements

Quantitative (with standards)

Large differences in sensitivity for many elements NEGATIVE:

No unified model to explain process.

Process highly dependent on

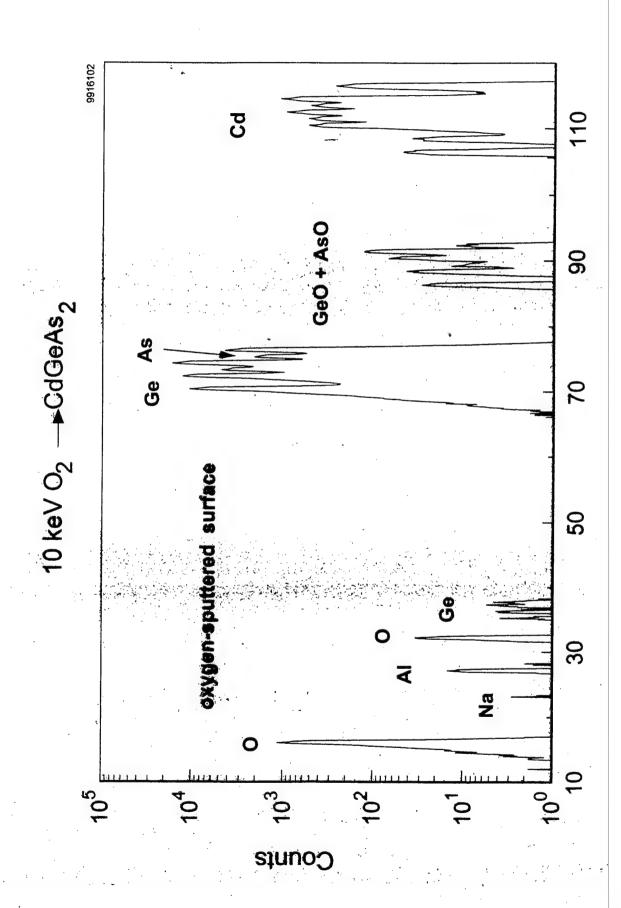
Instrumental Parameters

Matrix composition

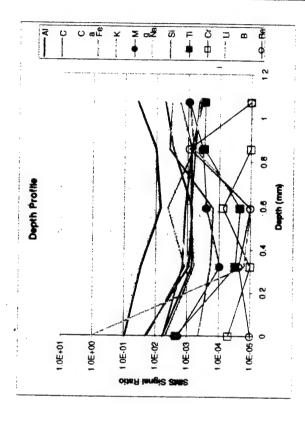
Quantification difficult in mixed matrixes

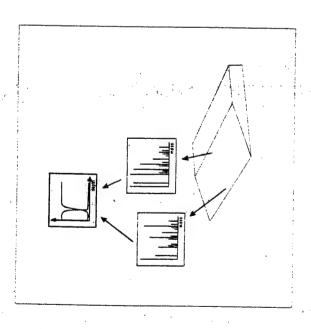
Destructive



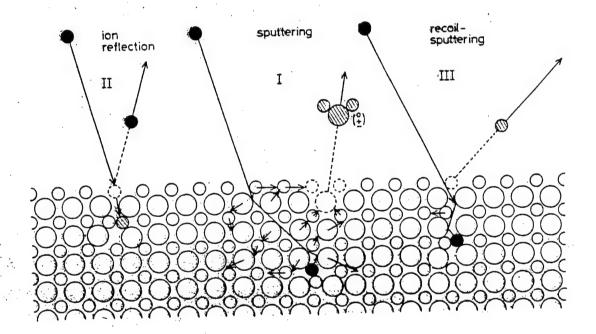


SIMS Analysis of ZnO









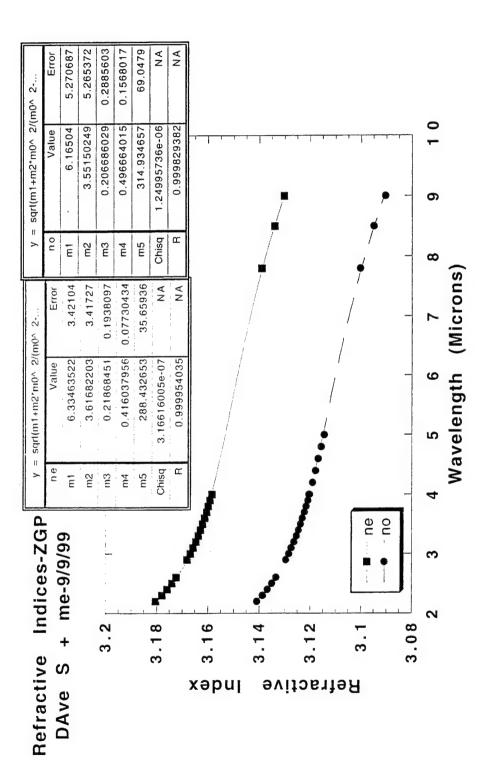


Materials and Manufacturing Directorate Sensor Materials Branch AFRL/MLPO

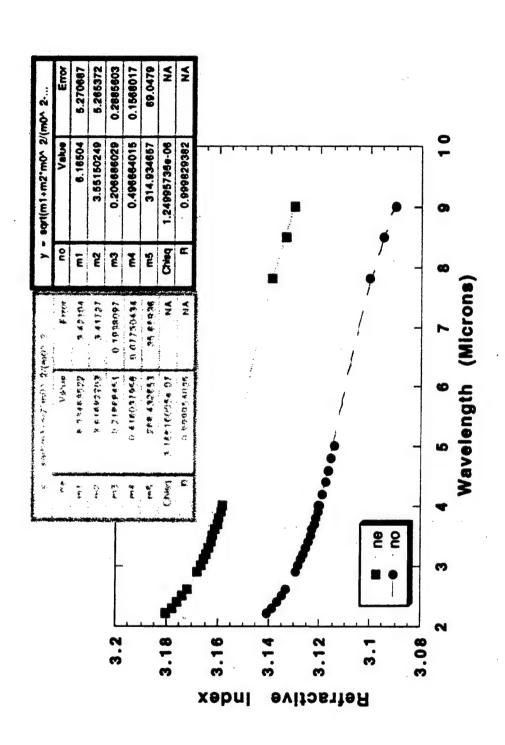
Phosphide from 2-9 Microns and Implications for Phase Matching in Optical Parametric Refractive Indices of Zinc Germanium Oscillators

David E. Zelmon, David L. Small, and

Peter G. Schunemann

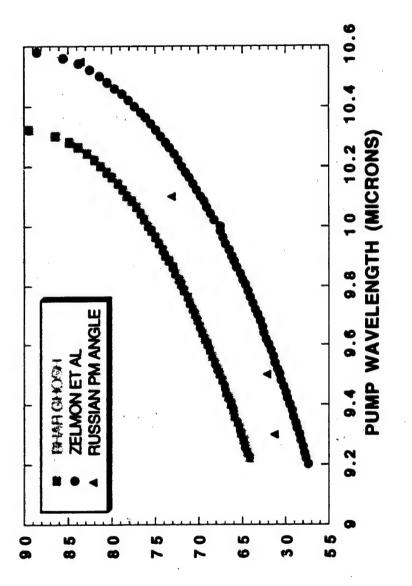


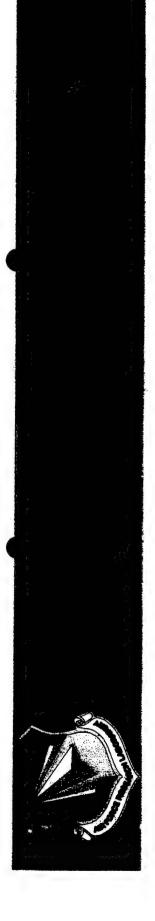


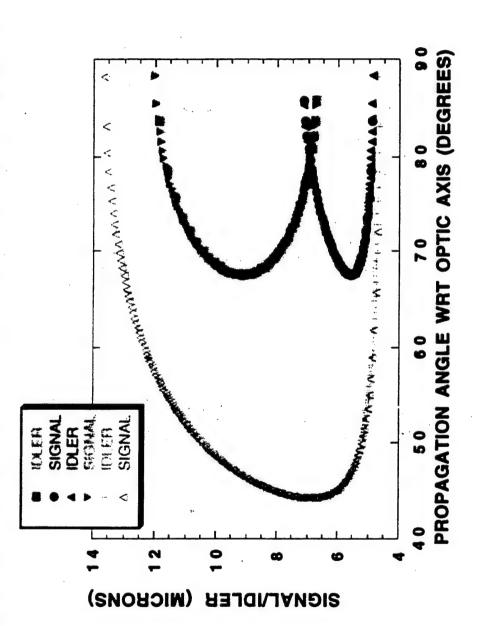




PHASE MATCHING ANGLE (DEGREES)

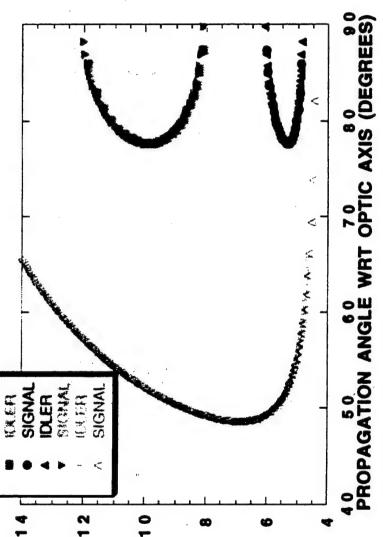




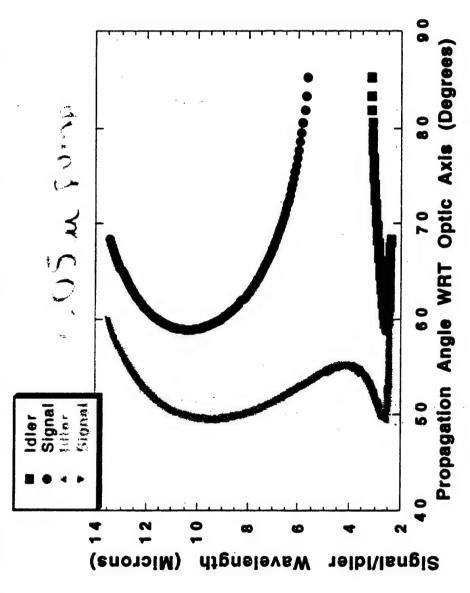








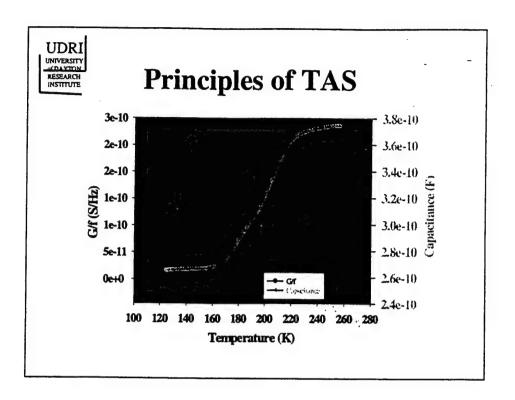




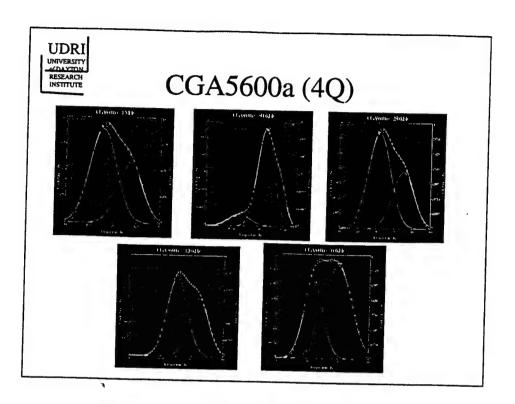
Analysis of CdGeAs₂ using thermal admittance spectroscopy

Steven Smith

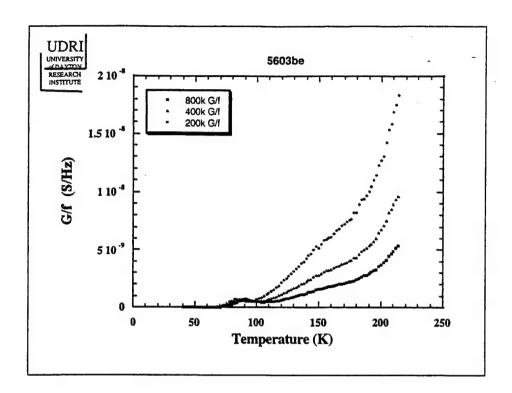
University of Dayton Research Institute



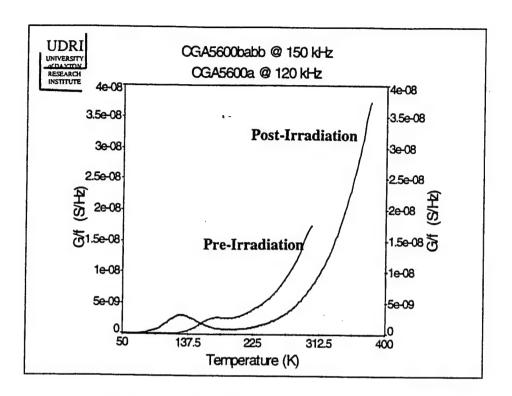
Thermal Admittance Spectroscopy (TAS) measures the response of a Schottky diode as a function of frequency and temperature. The resulting peaks in the conductance spectrum, or inflection points in the capacitance spectrum, can be used to determine the thermal activation energy(s) of the defects (impurities). Both spectra are shown in this slide.



Fitting the peak in the TAS spectrum of specimen 5600 (4Q) demonstrates that more than one defect is responsible for the peak. The evolution of the shape demonstrates the relative response of the defects as a function of frequency.



TAS spectra of specimen 5603 (4N) differs significantly from those of 5600 and 5601. A deeper level is evidenced by the broad 'bump' in the spectra around 150 K.



Comparison of the TAS spectra before and after electron irradiation of specimen 5600. A slight shift to lower energy is noted by the postion of the peak in the post-irradiation spectrum.

High rep rate Tandem OPO

NLO Materials Workshop

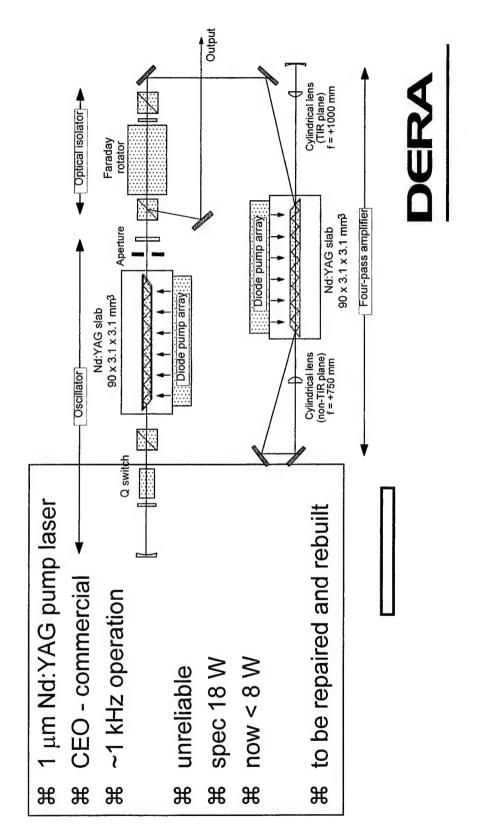
20 - 21 September 1999 DERA Malvern

JAC Terry

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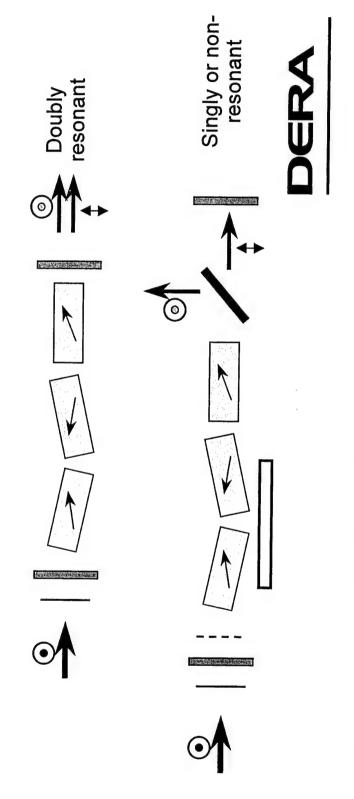


Experimental - 3



Experimental - 4

第 1st OPO - wavelength doubler (3 KTP crystals)



Experimental - 5

器 WD power and efficiences

第 Doubly resonant

₩2.2 W (both polarisations)

 $\Re P_{th}$ - 3.9 W, s.e. - 45 %, σ - 7 %

器 Singly resonant

₩2.3 W ('single' polarisation)

 $\#\,P_{th}$ - 3.7 W, s.e. - 36 %, σ - 11 %

器 Non-resonant

₩2.4 W ('single' polarisation)

ж P_{th} - 4.5 W, s.e. 44 %, σ - 14 %

第 Beam quality

₩ M² ~[1.5 x 2.3 (befter in walk-off plane)



10

Experimental - 6

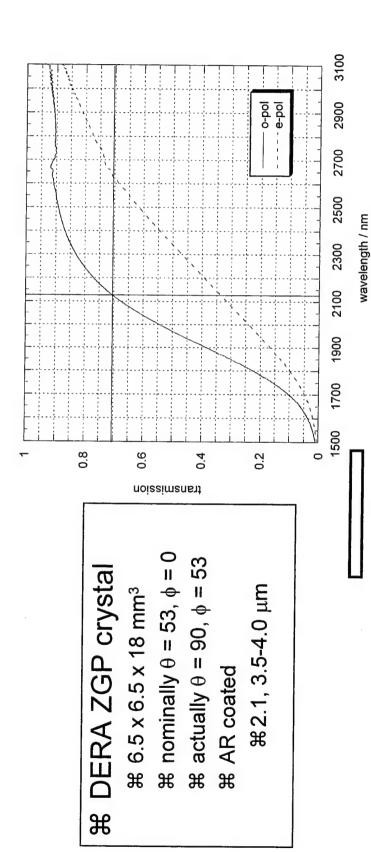




NLO materials workshop - High rep rate Tandem OPO

Experimental - 7

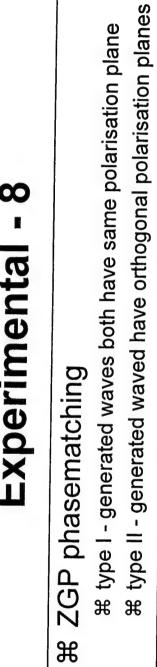
Polarised transmission of coated ZGP sample VB34/2/2/2/3

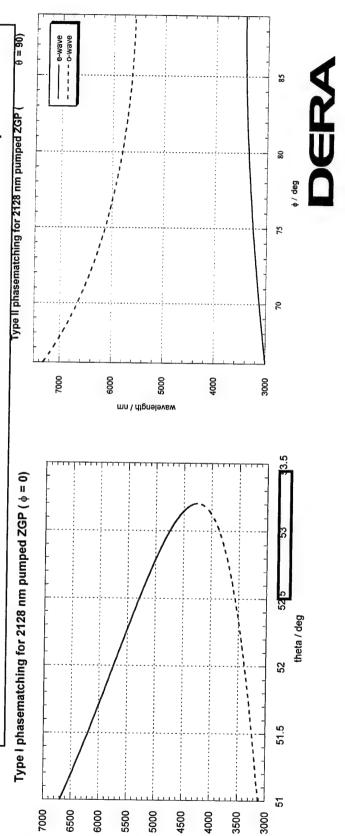


NLO materials workshop - High rep rate Tandem OPO

20-21/9/99

Experimental - 8



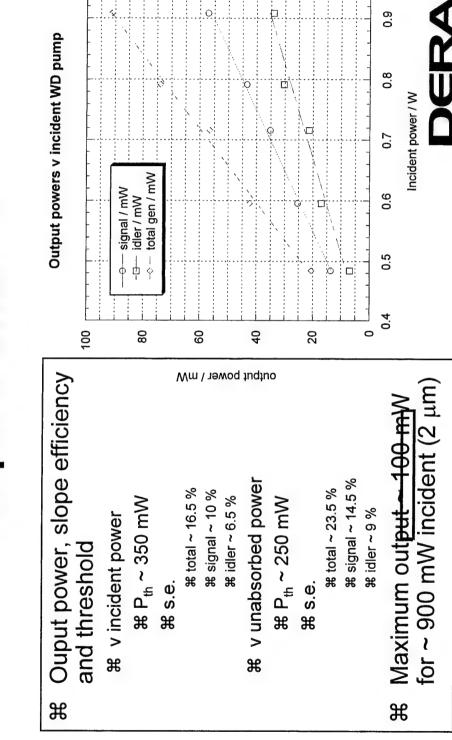


wavelength / nm

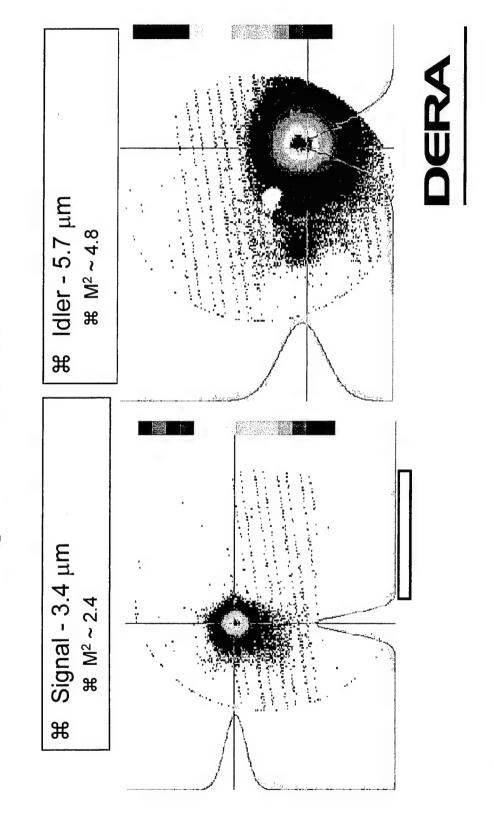
20-21/9/99

NLO materials workshop - High rep rate Tandem OPO

Experimental - 9



Experimental - 10



Summary

器 Operation of a tandem OPO system has been demonstrated at ~1 kHz rep rate

demonstrated to operate with ~ 10 mJ energy per pulse 第 Device (wavelength doubler) with bulk NLO material

Demonstration of the utility of DERA ZGP

第 In this case wrongly orientated, but reasons for this understood

第 Target of 1 W in band 4 not met

Further experiments required to understand the limitations of this technology, especially thermal effects



Far-IR Frequency Conversion Chalcopyrites for Mid- to Recent Advances in

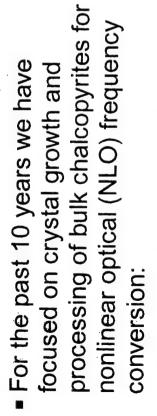
P. G. Schunemann and T. M. Pollak

SANDERS
A Lockheed Martin Company

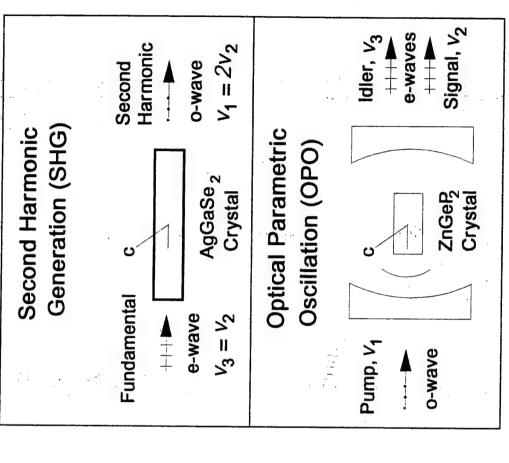
Workshop, (NLO 99), DERA, Malvern, UK, Sept. 20, 1999 Presented at the 1999 Nonlinear Optical Materials

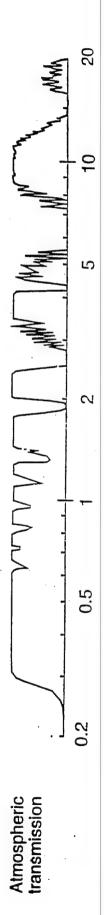
Work supported L.N. Durvasula at DARPA (via the Air Force Research Laboratory Materials Directorate contract No. F33615 -94-C-5415) and Sanders Internal R&D Funding

Chalcopyrite Crystal Growth at Sanders



- Frequency doubling of CO₂
 Lasers (SHG)
- "Wavelength doubling" of 2um solid state lasers (OPO)
- The Goal:
- Produce efficient mid-IR lasers operating in regions of high atmospheric transmission
- Applications:
- Laser radar, remote sensing, etc.





Strategies for Improved Infrared NLO Materials

2um-pumped OPO's

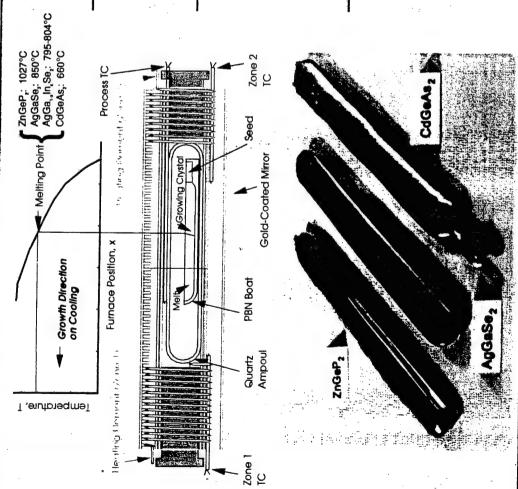
- Material of Choice: ∠nGeP
- Highest NLO Coefficient with sufficient band gap (d₁₄=75 pm/V)
 - High Thermal Conductivity (0.35W/cmK)
- Reduced Losses ----> Efficient, High Power Output
- Alternatives for better performance:
- None: Continue to Reduce ZnGeP₂ Near-IR Absorption

CO₂ Doubling

- Material of Choice: AgGaSe,
- Respectable NLO Coefficient (39 pm/V)
- Wide transparency and phase-matching range (.78-18um)
- Low absorption Losses
- Alternatives for better performance:
- CdGeAs₂: Highest Nonlinearity (d₁4=236 pm/V)

 ► Reduce Absorption Loss
- Ag(Ga,In)Se2: Adjust Birefringence for Noncritical Phase-Matching (NCPM)
- ABX₂: Continue Search for New Materials

Horizontal gradient freeze growth led to advances in NLO chalcopyrites



HGF Approach: Key Aspects

Low thermal gradients

- Minimize vapor transport
- Eliminate cracking due to anisotropic thermal expansion

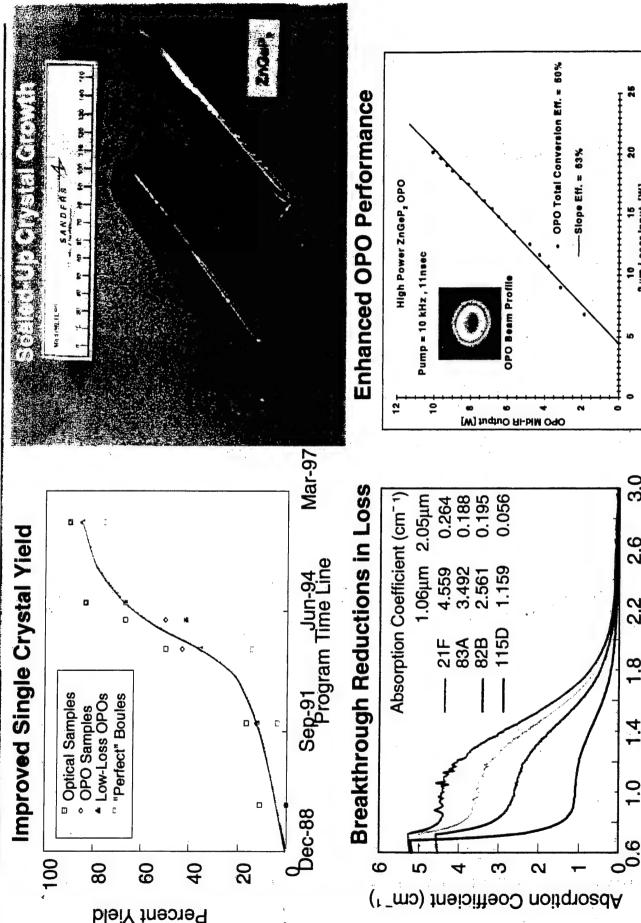
Transparent Furnace

- Simplifies the seeding process
- Allows in situ monitoring of the S/L interface shape & position
- Facilitates interactive growth (secondary grains can be re-melted)

Seeded growth

- Eliminates initial polycrystallinity due to supercooling
- Optimizes orientation to accommodate negative c-axis thermal expansion
- Enables growth along phase matching direction for max. device length & yield





25

20

2 µm Leser Input [W]

3.0

2.6

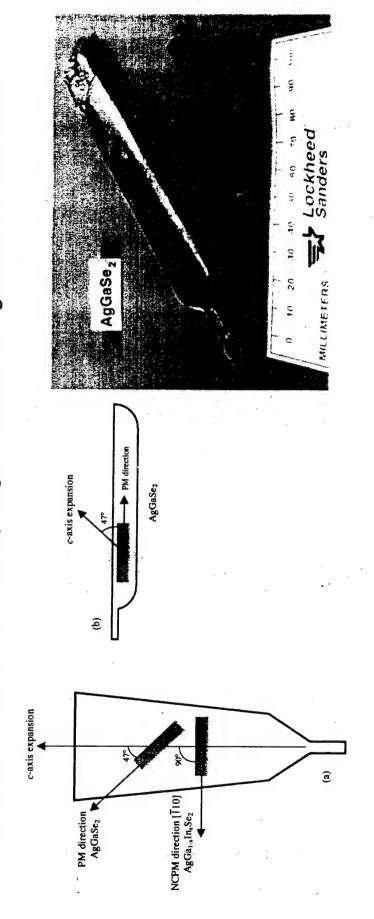
2.2

ω.

Wavelength (Microns)

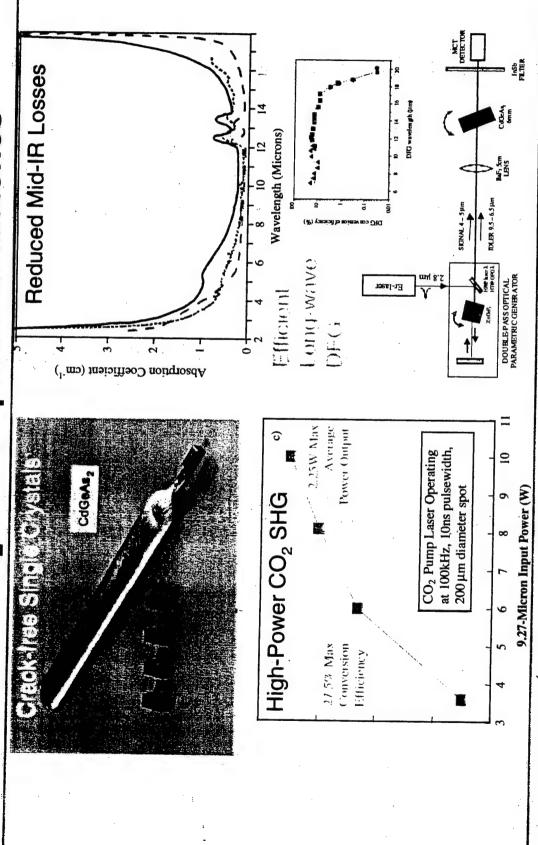
"Phase-Matched" Crystal Growth of AggaSe2

- Vertical Bridgman growth of AgGaSe₂ requires seeding along c-axis for unconstrained thermal expansion during cool-down
- The Horizontal Gradient Freeze (HGF) technique allows "phase-matched" growth along device orientation, yielding longer interaction lengths and minimal waste





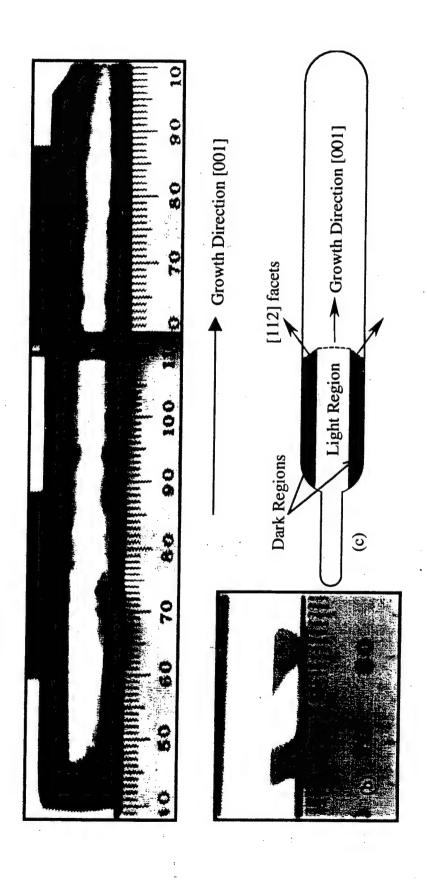
CdGeAs₂: Development Milestones



A Lockheed Martin Compony

N. Ody py

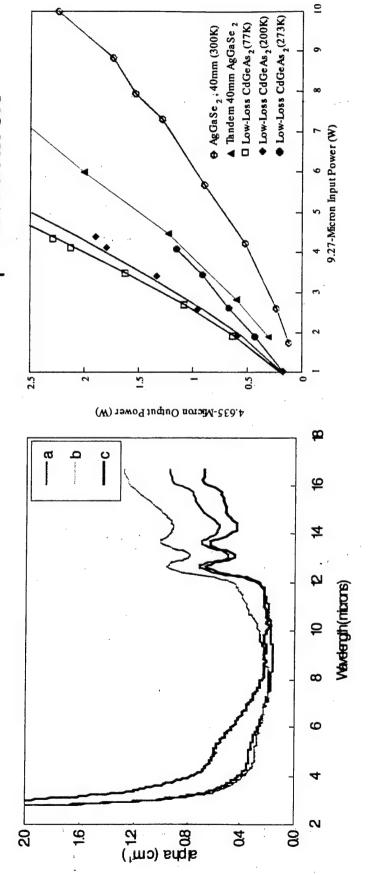
Segregation of Absorbing Defects in CdGeAs₂

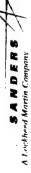


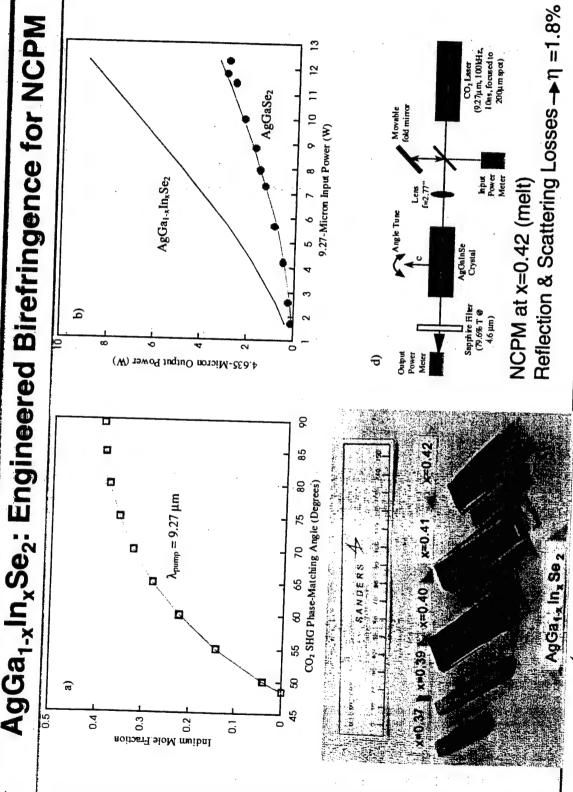


Reduced Mid-IR Absorption (Low-Loss Central Core)

Efficient CO_2 -Doubling: $\eta = 53\%$ at 77K $\eta = 28\%$ at 273K



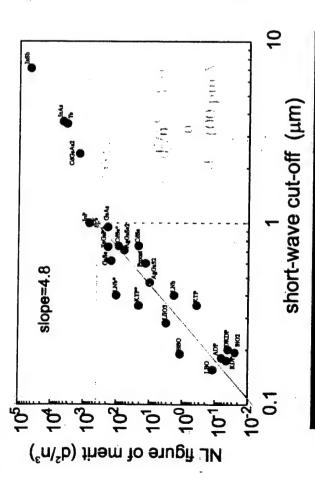




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AgGaTe₂: a promising new nonlinear optical crystal



Motivation:

- Telluride analog of AgGaS₂ & AgGaSe₂
- Substitution by Te should triple the NL coefficient and shift the transparency range further into the IR (~1-20μm)
- Objectives of Research:
- Produce large, crack-free single crystals
- Determine if birefringence is sufficient for phasematching

• Approach:

- HGF Growth in Transparent Furnace
- Fabricate prism, measure ∆n

Boule #4

Summary

- Recent crystal growth advances have established chalcopyrites as the NLO materials of choice for mid- to far-IR laser frequency conversion:
 - Large crack-free single crystals (up to 16x28x140mm³) of ZnGeP2, AgGaSe2, and CdGeAs₂ can be reproducibly grown by the HGF technique
- achieved by feed purification, compositional control, & post-growth annealing Substantial reductions in absorption and/or scattering losses have been
- Improved crystal quality has resulted in outstanding NLO device performance
- The birefringence of mixed crystals (AgGa_{1-x}In_xSe₂) can be engineered to achieve non-critical phase-matching (NCPM)
- The search for new materials has led to promising NLO crystals such as AgGaTe2, CdGa2S4, and CdGa2Se4
- Dy^{3+} :CaGa₂S₄ was demonstrated as the first sulfide mid-IR laser host



Development of Technology of ZnGeP2 Single Crystal at

Institute for Optical Monitoring SD RAS

By Alexander I. Gribenyukov, Galina A. Verozubova, and Valentina V. Korotkova

Laboratory of Optical Spectroscopy

Institute for Optical Monitoring

Tomsk Branch of Siberian Division

Russian Academy of Sciences

|--|

First Long-term Program

High priority problems related to ZnGeP2 technology

reproducible temperature profiles. The equipment could be working growth equipment ensured high Creation (development) of the with high reliability.

Creation(development) of a new moderated (modified) synthesis technique which could assure a production of as-synthesis ZnGeP₂ with controllable (managed) composition.

single crystal technology of Development of high yield ZGP growth Choice of container material

1989 - 1994

- Choice of seed orientation
- Computer calculations of temperature profiles
 - K_L/K_S ratio evaluation
- Calculations & measurements of real growth rate

1987 - 1988

- First prototype

Temperture of reaction start

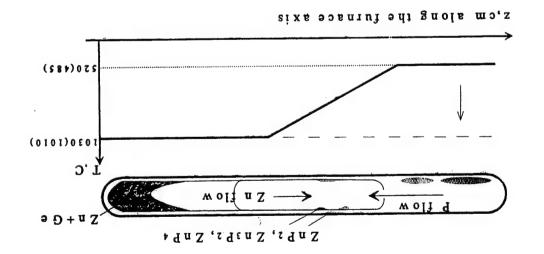
Intermediate phases

Reaction velocity

1988 - 1991

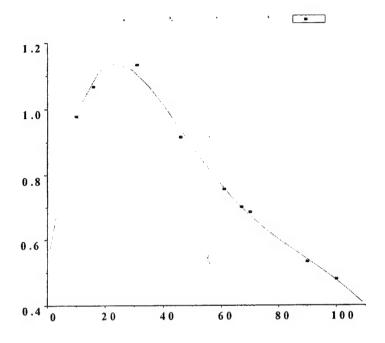
- Series of 6 VB furnaces

TR9. P_4 and Zn flows in non-isothermal closed synthesis system.

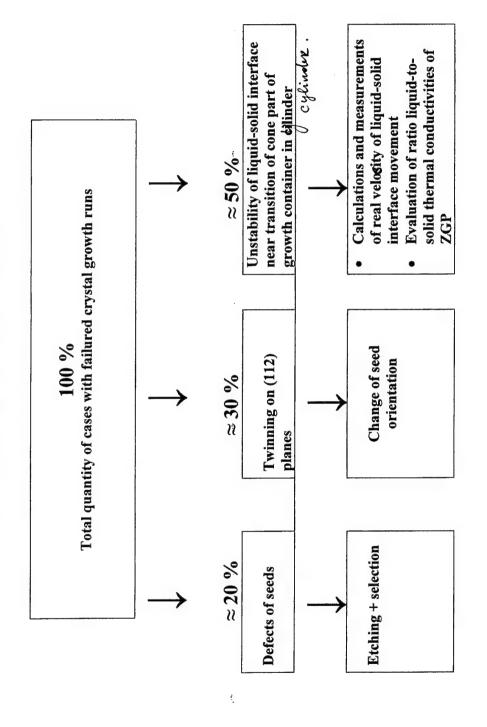


 $TR10-Time\ dependence\ of\ expenditure\ velocity\ of\ P4\ vapour\ under\ pressure\ of\ 10-12\ atm\ \ with\ Zn-Ge\ melt\ at\ 1010\ C$.

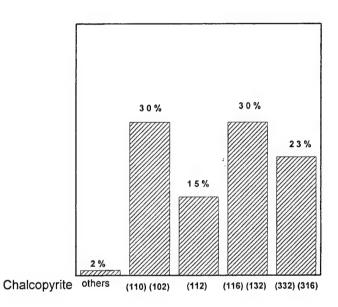
Hot zone temperature - 1010 °C Cold zone temperature - 515 °C (P_{P4} = 10 atm)



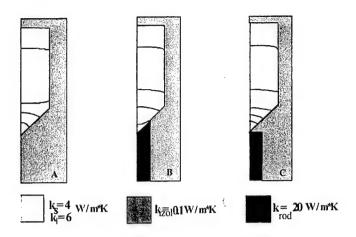
Distribution of growth failures on causes

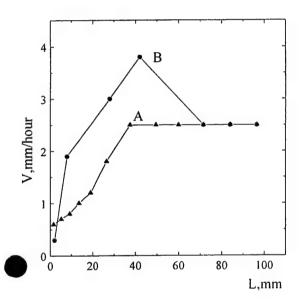


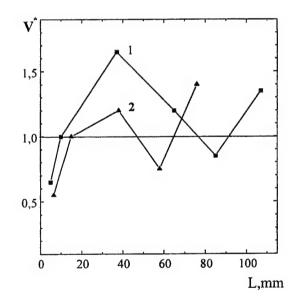
TR12 – Probability distribution of ZGP crystalline blocks enlarged along growth axis in VB-method with spontaneous nucleation.



TR14 – The image of growth container surrounding structure for computer calculations.







GF method: The isotherm crystallization rate for container with A and B surrounding structure. Cooling rate -1 $^{\circ}$ /hour.

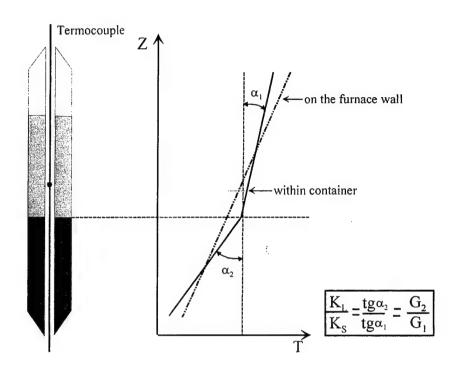
VB method:

Distribution of isotherm crystallization rate (in units of mechanical movement rate) along crystal axis.

A-type of surrounding structure ,Ø furnace=6@m;

- 1 calculation's data , Ø ampoule = 3 &m;
- 2 experiment's data, Øampoule=2@m;

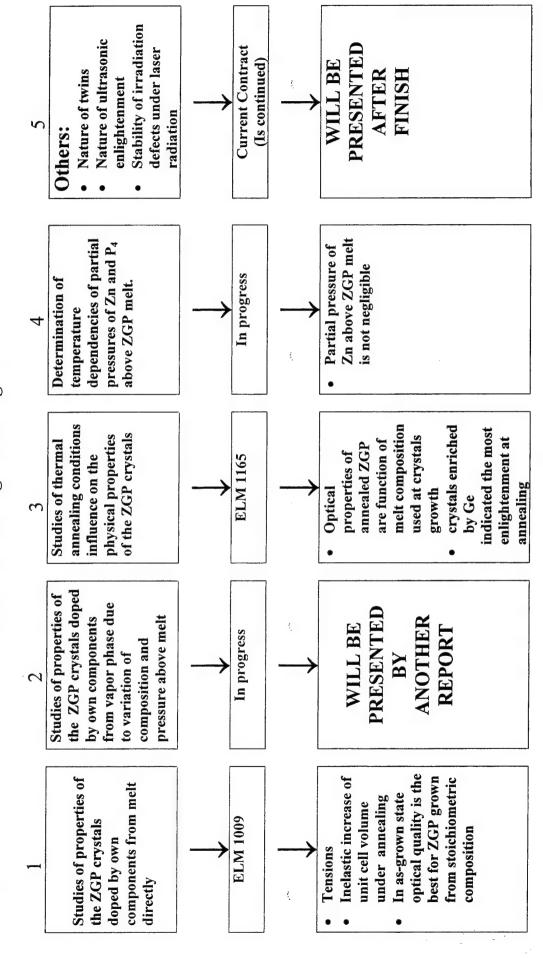
rR15. Diagram of stady state temperature distribution



Material	Linear regression coefficients				Calculated values	
,	Ts	Gs	TL	GL	T _{mel}	KL/Ks
Ge	942.42	4.6	940.51	2.7	937 ± 1	1.7 ± 0.1
GeP ₂	2009.9	16.24	1807.53	12.9	1027 ± 1	1.3 ± 0.1

Literature data for Ge: KL/Ks = 2.93 [3] Corrected ratio for $ZnGeP_2$: KL/Ks = 2.3

The Second Long-term Program



TR17 Some Results of investigations of ZGP crystals doped from melt. Measurements were made in DERA. The crystals were grown in IOM

Crystal	Dopant	Temperat	Unit cell	Unit cell	Absorpt.	Absorpt.	Derivative	Unit cell	Absorpt.
	ļ	. gradient	volume,	volume	coeff.	coeff.	dα/dV,	volume	coeff. after
	(P4-pres.	DT/dx,	r	difference	at 2.06 µm	difference	,	after	annealing
	atm)	.C/cm	Ą	(Virt - Vrr)	cm-1	altf - altf	ст-1 Å-3	annealing	cm ⁻¹
				A.		wo		Å ³	
	4								0.27 –meas.
89/3 ftf	0.2	5.2	319.94861		0.431			320,234	
	wt%Ge			-0.03872		0.016	-0.465		0.298-calc
89/3 ltf	(7.5)	15.4	319.90989		0.449				
									0.36 –meas.
91/2 ftf	Stoich	1.5	319.92818		0.332			320,332	
	ţ			1			+1.07		0.764- calc.
ŧ	(7.1)	,	1	+0.12000		0.129			4.
91/2 ltf		7.5	320.04824	9	0.461				:
373 67 60	•	,			1				0.53-meas.
95/5 111	0.7	2.5	319.98361		0.615			320,190	
	wt%Zn						+2.4		1.11-calc
				-0.04372		- 0.105			
93/3 ltf	(3.8)	>20	319.93989		0.510				

Seeds orientation is (116) for all grown crystals.

Annealing result in an increase of unit cell volumes, but expected change of absorption coefficient with the unit cell volume indicated only for sample enriched by Ge.

ZGP GROWTH FROM MELT: THE VAPOUR PHASE COMPOSITION AND CRYSTAL PROPERTIES

G.A. Verozubova A.I. Gribenyukov Yu. F. Ivanov*

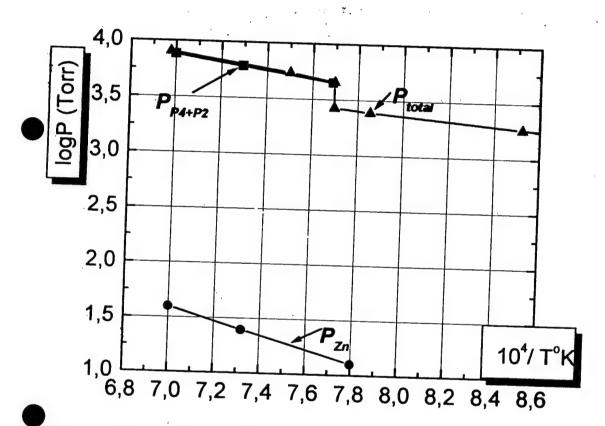
Institute for Optical Monitoring SD RAS
*Tomsk Polytechnical University

in collaboration with A.Vere, DERA, Malvern

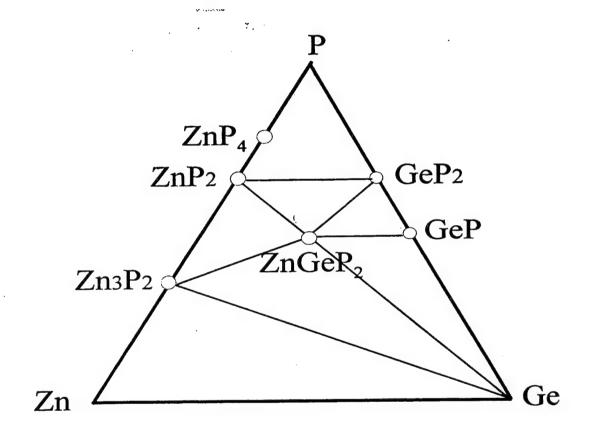
The work was fulfilled under financial support DERA, United Kindom

327°C - ZnGeP₂ starts to decompose

1038°C - ZnGeP₂ melting point (Seb Fiechter, 1996)



The total pressure above $ZnGeP_2 - P_{total}$ (Buehler, 1971) and partial pressures of $Zn - P_{Zn}$ and $P - P_{P4+P2}$ calculated from the regular solution theory (Roenkov, 1975): $P_{Zn} = 18$ Torr at 1068C



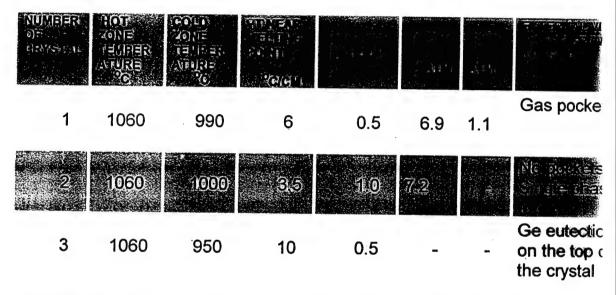
The Zn-Ge-P phase triangle

Experimental details

<u>Synthesis:</u> modified two-temperature technique, allowing to produce more then 500 gms of the material in one process

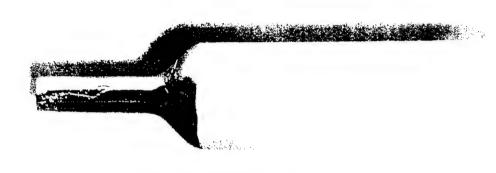
Growth: vertical Bridgman technique, (100) seeds

TABLE 1. Crystal growth conditions.



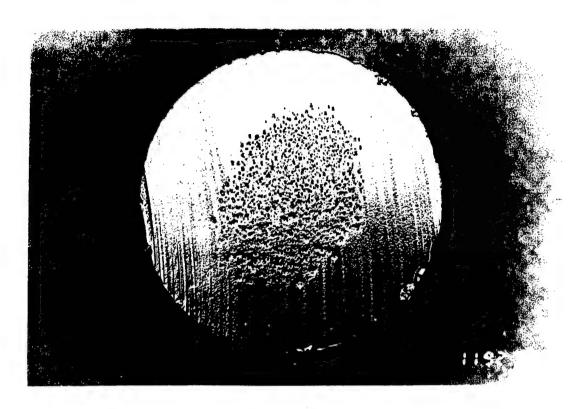
^{*} $P_{P4}\left(P_{Zn}\right)$ - pressures of phosphorus (zinc), created by additional charges of P (Zn), and calculated from the ideal gas law.



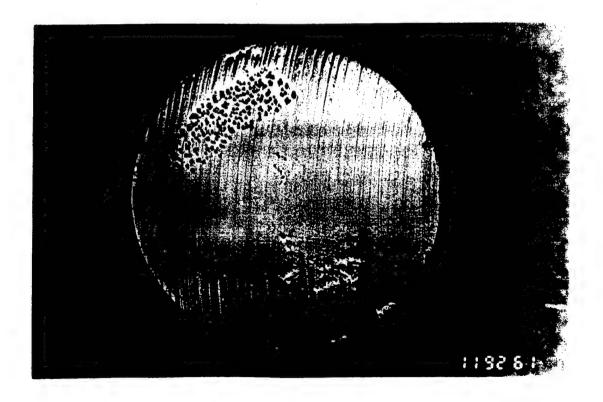




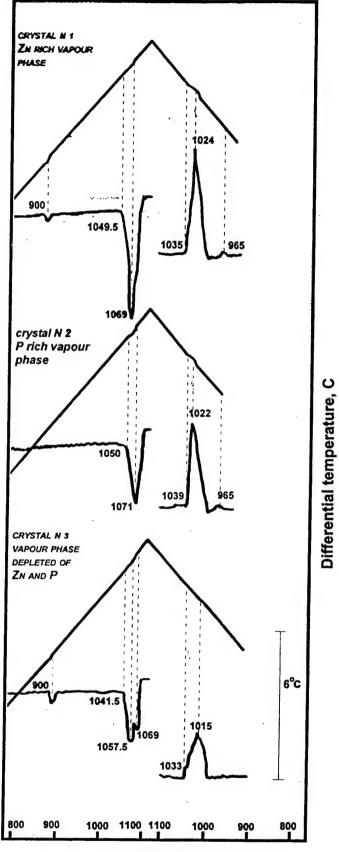




1 cm

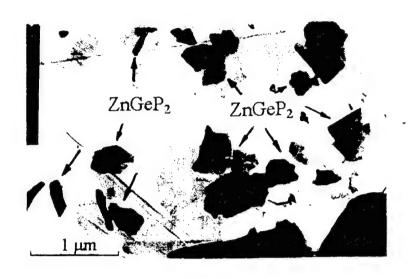


ZnGeP₂ slices after chemichal etching



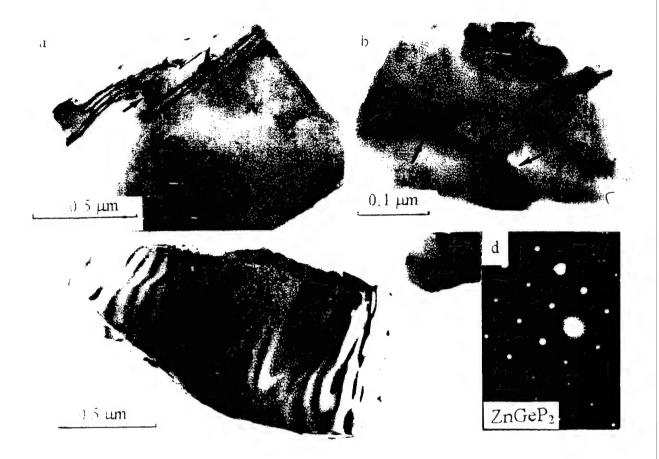
temperature, C
DTA curves of ZGP grown under various pressures of Zn and P

Experimental details: the weight of the studied samples-0.5 g , heating and cooling rates - 7.5deg/min reference material - AI2O3, speed of the paper movement - 1mm/mm

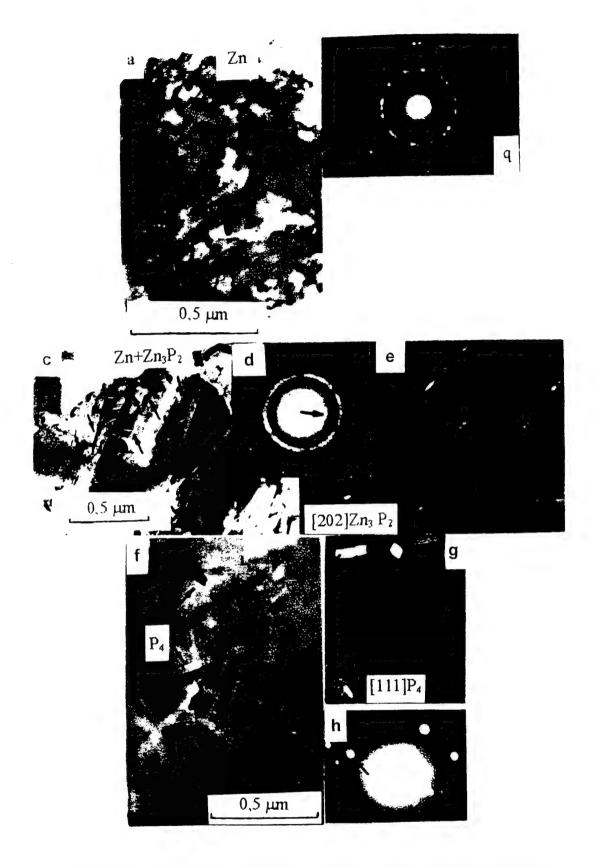


Fragments of failure (damage) of the bulk ZGP specimen arranged on the carbon substrate

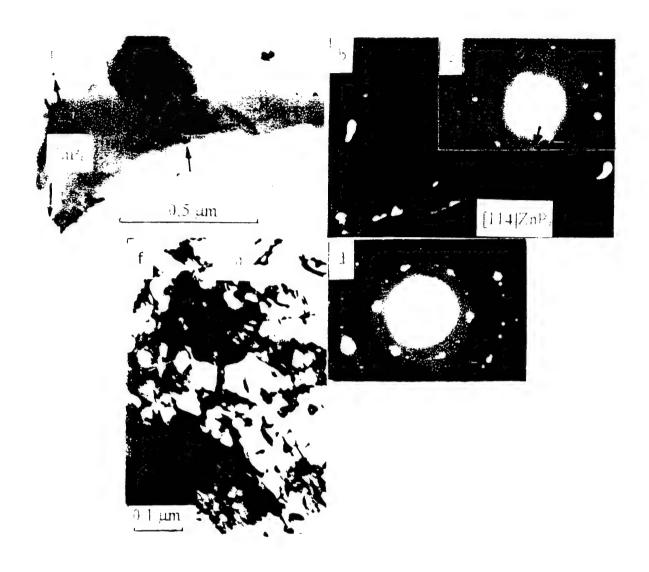
Electron microscope EM-125 Accelerating voltage 125 kV Working Magnification 65-85 000 Resolution 7-10Å



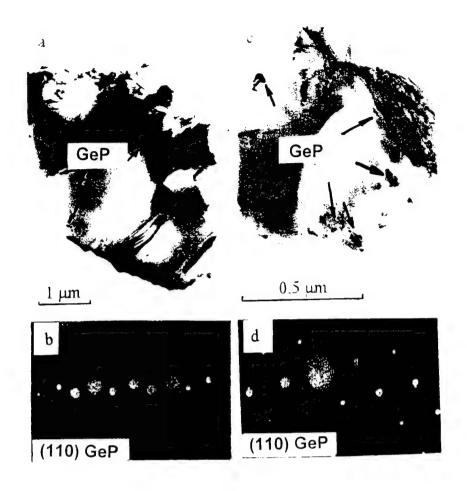
Microscopic image of ZnGeP₂



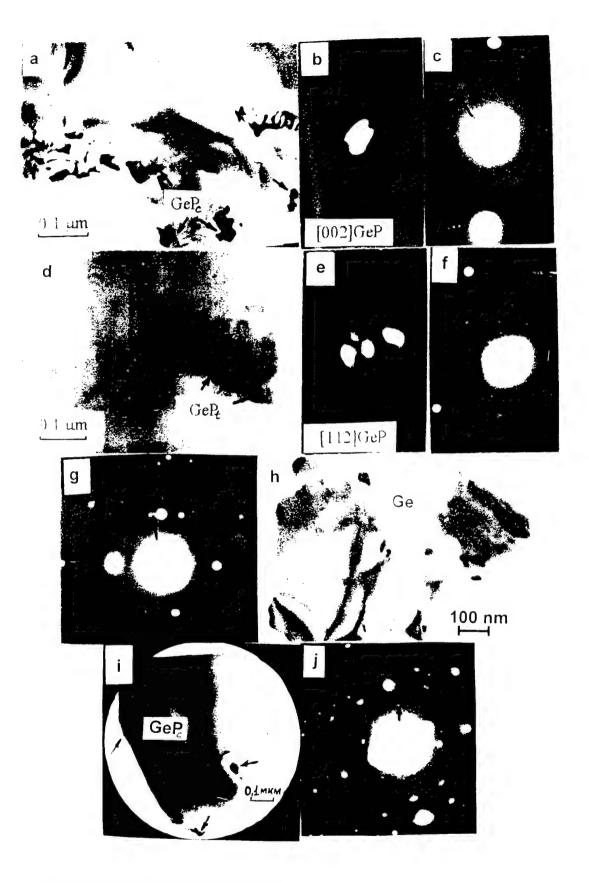
Microscopic image of ZnGeP₂ grown under Zn rich vapour phase (as- grown crystal N1)



Microscopic image of ZnGeP₂ grown under Zn rich vapour phase (annealed crystal N1)



Microscopic image of ZnGeP₂ grown under the phosphorus pressure of 7.2 atm (crystal N2)



Microscopic image of ZnGeP₂ grown under the vapour phase depleted of volatile components (crystal N3)

TABLE 2. The vapour phase composition during growth and the phase composition of precipitates.

NUMBER OF GRYSTAL	P _{P4}	Pag AUN	EXTERNAL VIEW OF THE GROWN CRYSTAL	1331483 133148 133	SIZES OF PRECIPITATES
1	6.9	1.11	Gas pockets	Za .	Ø 1-1-5 mkm
				ZingPaZinPa	10 nm×1 mkm
				P	25×300 nm
			No	Ger cubic	Ø 0.2-0.3 mkm
	7.2		pockets Single phase top		ø 80-90 nm
			Ge	GeP cubic *	Ø 5 nm
.3 	-		eutectic on the top of the	GeP tetrogonal	15×45 nm
			crystal	Ge:	Ø 8 nm

^{*} P_{P4} (P_{Zn}) - pressures of phosphorus (zinc), created by additional charges of P (Zn), and calculated from the ideal gas law.

Chemichal point of view:

Dissociation reaction for the melted ZGP (Seb. Fiechter, 1996)

$$ZnGeP_{2(melt)} \Leftrightarrow Zn_{(gas)} + (1-x)Ge_{(cond)} + xGeP_{(cond)} + (0.5-0.25x) P_{4(gas)} + (0.$$

Mass action law for the dissociation reaction of the melted ZGP:

$$K_P(T) \sim P_{Zn} P_{P4}^{(0.5-0.25x)}$$

TABLE 2. The vapour phase composition during growth and the phase composition of precipitates.

NUMBER OF	P _{P4}	P	EXTERNAL .	RHASE COMPOSITION	SIZES OF PRECIPITATES
CRYSTAL	ATM	ATM	OF THE GROWN CRYSTAL	OF PREGIPT/ATES	
		- 243	Gas	.Zn⊬	Ø 1-1.5 mkm
: - 3.1 - 3 853	6.9	1.1:	pockets		
				Zn ₃ P ₂ ZnP ₂	10 nm×1 mkm
				P	25×300 nm
			No	GeP cubic	Ø 0.2-0.3 mkm
2	7.2	2.3	pockets		
			Single		Ø 80-90 nm
			phase		
			top		
			Ge	GeP cubic	Ø 5 nm
3	-	7.1.2	eutectic		
			on the	GeP	15×45 nm
			top of the	tetrogonal ::	
			crystal	Ge	ø8nm

^{*} P_{P4} (P_{Zn}) - pressures of phosphorus (zinc), created by additional charges of P (Zn), and calculated from the ideal gas law.

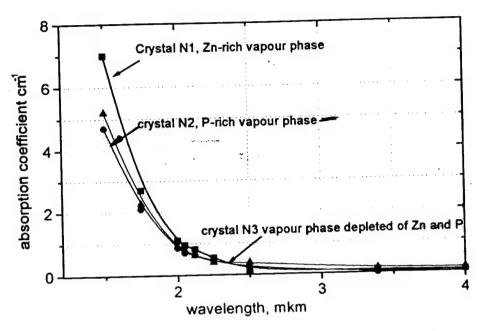
Chemichal point of view:

Dissociation reaction for the melted ZGP (Seb. Fiechter, 1996)

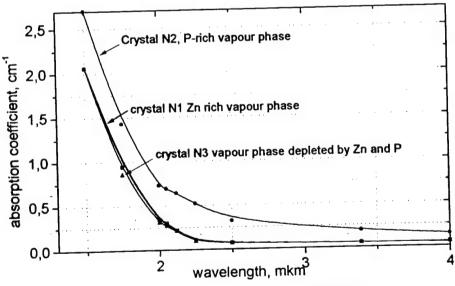
$$ZnGeP_{2(melt)} \Leftrightarrow Zn_{(gas)} + (1-x)Ge_{(cond)} + xGeP_{(cond)} + (0.5-0.25x) P_{4(gas)}$$

Mass action law for the dissociation reaction of the melted ZGP:

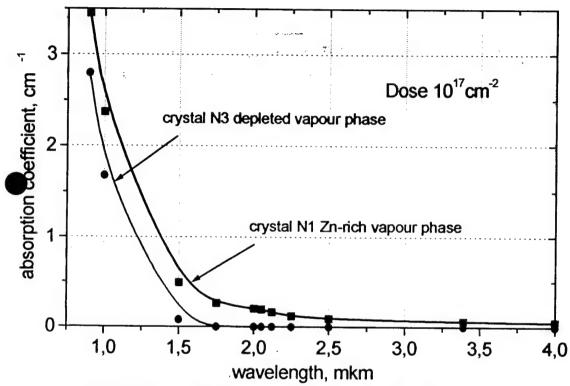
$$K_P(T) \sim P_{Zn} P_{P4}^{(0.5-0.25x)}$$



Absorption coefficient spectra for as-grown crystals Slices were cut from the middle part of the ingot



Optical absorption spectra after annealing (vacuum, T=600°C, duration 300 hours)
Slices were cut from the middle part of the ingots



Absorption coefficient spectra of ZnGeP₂ after irradiation slices were cut from the middle part of ingots, thickness is 6 mm

Conclusions

To study the influence of the vapour phase composition during growth on crystal properties three single crystals were grown from one starting material but under varied vapour phase composition.

- 1. DTA have shown the different composition of these crystals: their melting points are different. For the Zn and Ge rich crystals it is lowered as compared to the crystal grown with the P excess only.
- All three crystals have the second phase particles. The second phase composition correletes with the vapour phase composition.
- 3. For the most part the second phase particles have a drop (splintery) form and nanometer sizes. In individual cases the second phase precipitations as the submicron micron's areas (Zn or Zn+ Zn_xP_y) are found.
- 4. As a rule, the nanodimensional particles are located along boundary of areas of the crystal fracture, being responsible for the brittle cracks in ZGP.
- 5. ZnGeP₂ fragments free from the second phase particles have high elastic stress fields whereas fragments containing the latter particles are free from stresses. This could possibly indicate that the crystal areas having a high level of elastic stress fields are the places of the second phase particle formation.
- 6. The different improvement of the crystals grown with Zn-rich vapour phase and vapour phase depleted of volatile components on irradiation is apparently related to the different volume fraction of the second phase particles or their sizes. The lowest absorption at 2 μm attained by irradiation is < 0.01 cm⁻¹.

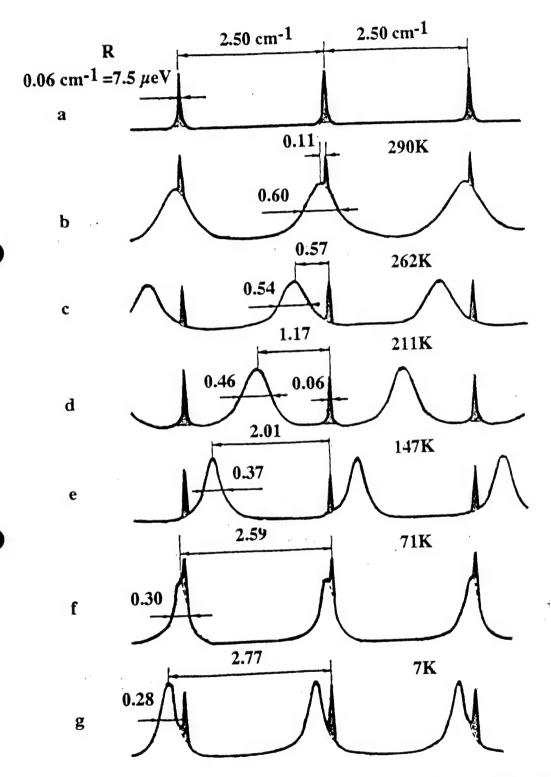
Inelastic Light Scattering by Free Electron Gas and Coupled Electron-Phonon Excitations in Advanced Semiconductor Structures

Bahish H Bairamov

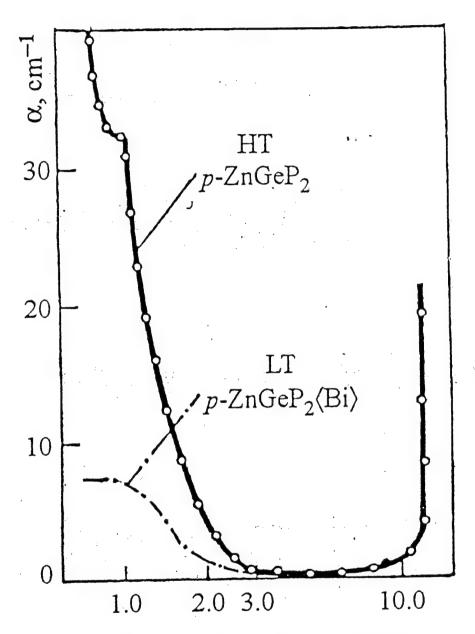
A F Ioffe Physico-Technical Institute
Academy of Sciences of the Russia

194021, St Petersburg, Russia

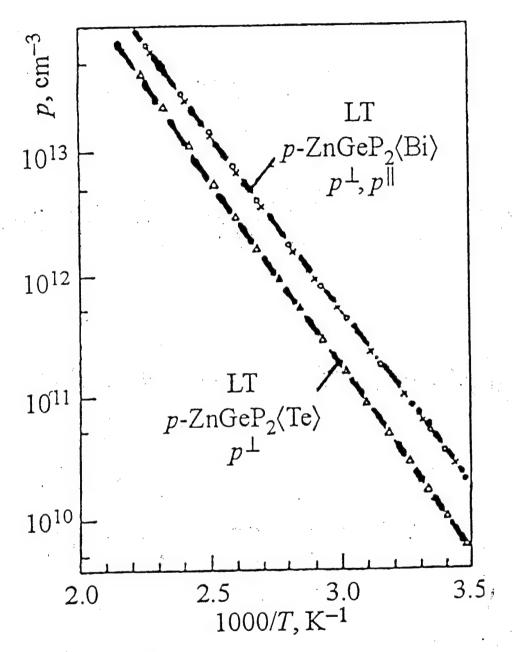
High resolution light scattering by LO phonons in semi-insulating GaP ($n < 10\ 12\ cm$ -3) in the temperature range 7 - 290K



a) instrumental profile with a spectral resolution of 0.06 cm⁻¹ b-g) interference spectra of the light scattering by LO-phonons various temperatures

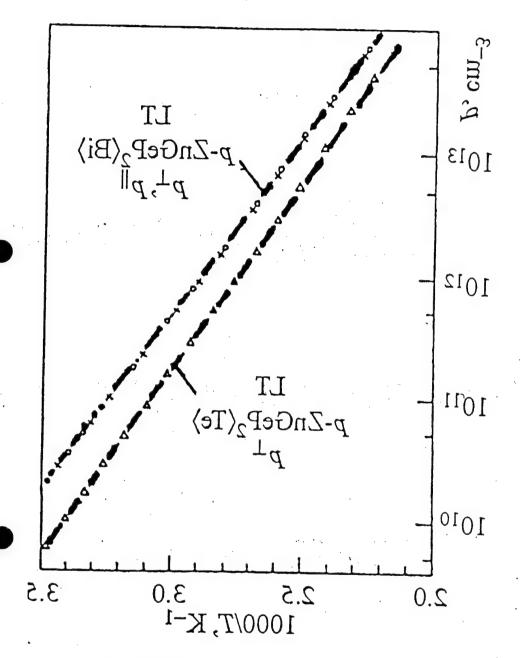


Optical absorption spectra
of the LT grown ZnGeP₂ <Bi>
and HT grown p-ZnGeP₂ single crystal
obtained by standard technique.



Temperature dependence of the hole concentrations of the two LT grown *p*-ZnGeP₂ <Bi> and <Tl> samples.

Symbols: \times and Δ for p^{\parallel} , o for p^{\perp} .



Temperature dependence of the hole concentrations of the two LT grown p-ZnGeP₂ <Bi> and <Tl> samples. Symbols: \times and Δ for p^{\parallel} , o for p^{\perp} .

Raman intensity(a.u.)

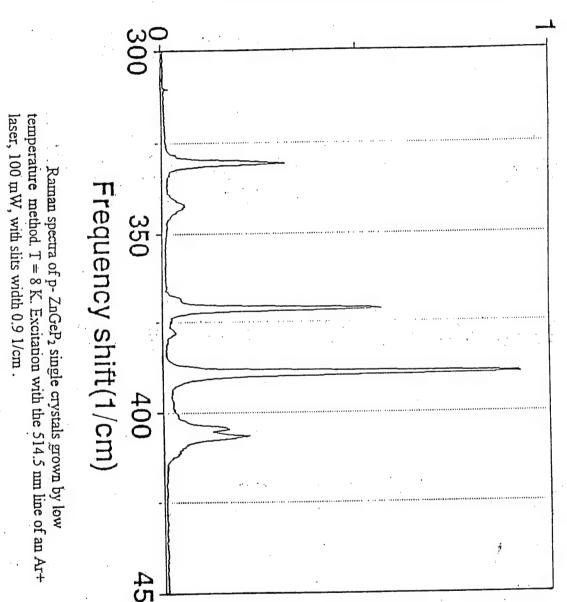


Table IV. Symmetry assignments and frequencies of the optical phosing (in cm⁻¹) in Zm = 2 obtained from the Raman scattering (RS) and infrared reflection (IR)

RS	2							
[X ₃] 94 (TO+LO) 96 (TO+LO) 94 (TO+LO) 121 118.2 118.3 119.3	of the	mode	RS"	RSh	RS ^c	IR ^d	RS	
X ₄ 94 (TO+LO) 96 (TO+LO) 121 118.2 118.2 119 142 (TO+LO) 143 (TO) 144 (LO) 144 (LO) 142.5(LO) 141.3 118.2 119 142 (TO+LO) 144 (LO) 144 (LO) 142.5(LO) 142.5(LO) 142.5(LO) 144 (LO) 142.5(LO) 143.5(LO) 143.5(LO	CP	ZB	T = 300 K	T = 300 K	T = 300 K		T = 300 K	T = 8 K
[K ₃ 94 (TO+LO) 96 (TO+LO) 121 (TO+LO) 141 (LO) 141 (LO) 142 (TO+LO) 144 (LO) 142 (TO+LO) 144 (LO) 144 (LO) 142 (TO+LO) 142 (TO+LO) 144 (LO) 142 (TO+LO) 198 (TO+LO) 203 (TO+LO) 204 (TO+LO)	1							
[W ₄] [112 119 121 142(TO) 142(TO) <td>٢</td> <td>[Xc]</td> <td>94 (TO+LO)</td> <td>96 (TO+LO)</td> <td>94 (TO+LO)</td> <td></td> <td>93.2</td> <td>95.4</td>	٢	[Xc]	94 (TO+LO)	96 (TO+LO)	94 (TO+LO)		93.2	95.4
[W ₄ 142 (TO+LO) 143 (TO) 142 (TO) 141 (TO) 142 (TO) 143 (TO) 143 (TO) 144 (TO)	<u>.</u> د	[W]	112	611	121		7.81	142.4
[W ₄]	<u> </u>	[W4]	142 (TO+LO)	142 (TO+LO)	143 (TO) 144 (LO)	142(TO) 142.5(LO)		<u>.</u>
[W ₁ 204 (LO) 203 (TO+LO) 205 (TO+LO) 206 (LO) 206 (L			302 (TO)	201 (TO)	204 (TO)	205 (TO)	198	
W ₂ 327 328 329 329 327.4 W ₁ 327 328	· •	E &	204 (LO)	202 (TO+LO) 203 (LO)	205 (TO+LO) 206 (LO)	208 (LO)	206.5	
[W ₁ 327 328 329 326.5 (TO) 326.5 (TO) 334 334 (W ₂ 339 (TO) 338 (TO) 338 (TO) 340 (LO+TO) 357 (LO) 357 (LO) 369 (TO) 369 (TO) 369 (TO) 369 (TO) 369 (TO) 369 (TO) 377 (LO) 37	Ľ	[W:]		248	249			0000
[W ₂ 339 (TO) 328 F ₃ (TO+LO) 338 F ₄ (LO) 340 (LO+TO) 340 (LO+TO) 354.5 (LO) 356 (LO+TO) 350 (LO+TO) 350 (LO+TO) 350 (LO+TO) 361 (LO) 360 (LO+TO) 361 (LO) 362 (LO) 357 (LO) 377 (ت <u>د</u>	[w]	327	328	329	i i	327.4	97676
[W ₂] 339 (TO) 338 (TO) 340 (TO) 340 (TO) 354.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 356.5 366.5 <td>-</td> <td></td> <td></td> <td>328 F_s(TO+LO)</td> <td>328 F_s(TO)</td> <td>326.5 (TO)</td> <td>£00</td> <td></td>	-			328 F _s (TO+LO)	328 F _s (TO)	326.5 (TO)	£00	
[W ₂] 339 (TO) 338 (1D) 341 (1D) 351 (LO) 357 (LO) 361 (LO) 364 (LO) 364 (LO) 367 (LO) 367 (LO) 367 (LO) 377 (LO) 405 (241 (TO)	342 (TO)	340	341.6
The color of the	7	[W ₂]	339 (TO)	338 (10)	341 (10) 350 (1 O+TO)	. ()	354.5	360
(W ₄ 368 (TO) 369 (TO) 369 (TO) 369 (TO) 368.5 (TO) 375 (TO) 374 (LO) 377 (LO) 377 (LO) 377 (LO) 377 (LO) 377 (LO) 387 (TO) 395 [qF ₄ (TO)]**** [F ₁₅ 399 (TO) 401 (TO) 401 (TO) 411 (LO) 414.5 (LO) 408 [qF ₄ (TO)] 408 [qF ₄				337 (EO) 346 (TO+LO)	361 (1.0)	364.5 (LO)		
[W ₄] 368 (TO) 369 (TO) 369 (TO) 377 (LO) 387 (TO) 387 (TO) 387 (TO) 387 (TO) 387 (TO) 405 (LO) 406 (LO) 400.3? 401 (TO) 411 (LO) 414.5 (LO) 405 (LO) 406 F ₅ + F ₄ (TO) 408 (LO) 408 F ₇ + G ₄ (TO) 408 (LO) 408 F ₇ + G ₄ (TO) 408 (LO) 408 F ₇ + G ₄ (TO) 408 [G ₇ + G ₇ +				357 (LO)	(CH) CV	165 5 (TO)	368.5	371.8
X ₃ 385 (TO) 377 (LO) 377 (LO) 377 (LO) 377 (LO) 377 (LO) 387 (TO) 387.5 (TO) 402.8 (LO) 402.8 (LO) 401 (TO) 401 (TO) 411 (LO) 414.5 (LO) 412? (A06 T ₅ + F ₄ (TO) 408 (LO) 408	ī,	[W4]	368 (TO)	369 (TO)	309 (10)	(01) (***)	375	377.8
[X ₃] 385 (TO) 387 (TO) 387 (TO) 387.5 (TO) 384.7,385.5 [Γ ₁₅] 385 (TO) 397.5 (TO) 402.8 402 (LO) 402.8 402 (LO) 401 (TO) 401 (TO) 401 (TO) 401 (TO) 401 (TO) 402.8 403.5 (LO) 403.5 (· :	3/4 (LU)	377 (LO)	377 (LO)	376 (LO)	377	377?
F ₁₅ 385 (TO)	۲	[X ₃]		390		10T) 3 FOC	184 7 185 5	389
402 (LO) 393 F ₅ + F ₄ (TO) 395 [qF ₄ (TO)]*** 400 (LO) 401 (TO) 401 (TO) 401 (TO) 401 (TO) 401 (TO) 402 (LO) 403 F ₅ (LO) 403 F ₅ (LO) 406 F ₅ + F ₄ (TO) 408 [qF ₄ (TO)] 408 F ₄ (TO)	Ľ	[7]	385 (TO)	387 (TO)	387 (10)	387.3 (10)	402.8	404 3
[F ₁₅] 399 (TO) 401 (TO) 401 (TO) 401 (TO) 400.3? 408 (LO) 403 F ₅ (LO) 403 F ₅ (LO) 396 [qF ₄ (TO)] 408 [qF ₄ (TO)] 408 F ₄ (TO)			402 (LO)	393 F ₅ + F ₄ (TO)	405 (LO)	406 (LO)	407.0	
414.5 (LO) 403 F ₃ (LO) 406 F ₃ + F ₄ (TO) 406 F ₃ + F ₄ (TO) 408 F ₄ + G ₄ (TO)	L	0.11	399 (TO)	401 (TO)	395 [q1 <(10)]*** 401 (TO)	397.5 (TO)	400.3?	405.2
396 [q\(\text{q}(TO))] 408 [a\(\text{L}(LO))]	4	61.1	408 (LO)		411 (LO)	414.5 (LO)	407	
				403 F ₅ (LO)			: 714	
		: ·		406 F ₅ + F ₄ (TO) 408 F ₂ (LO)	396 [qF4(TO)] 408 [qF4(LO), qF4(LO)]			

^{*}References 53.

*References 52 and 56.

*References 50.

d References 49 and 5).

cour results.

EPR AND ENDOR CHARACTERIZATION OF DONORS AND ACCEPTORS IN ZnGeP₂

Larry E. Halliburton Kevin T. Stevens Nancy C. Giles

Physics Department West Virginia University

Nonlinear Optical Materials Workshop DERA Malvern, UK September 20 – 21, 1999

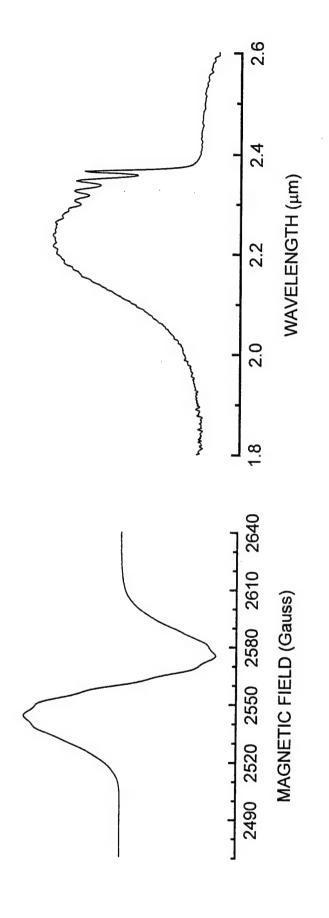
Work supported by Air Force Office of Scientific Research (in conjunction with the Materials Directorate at Wright-Patterson AFB) and by the National Science Foundation.

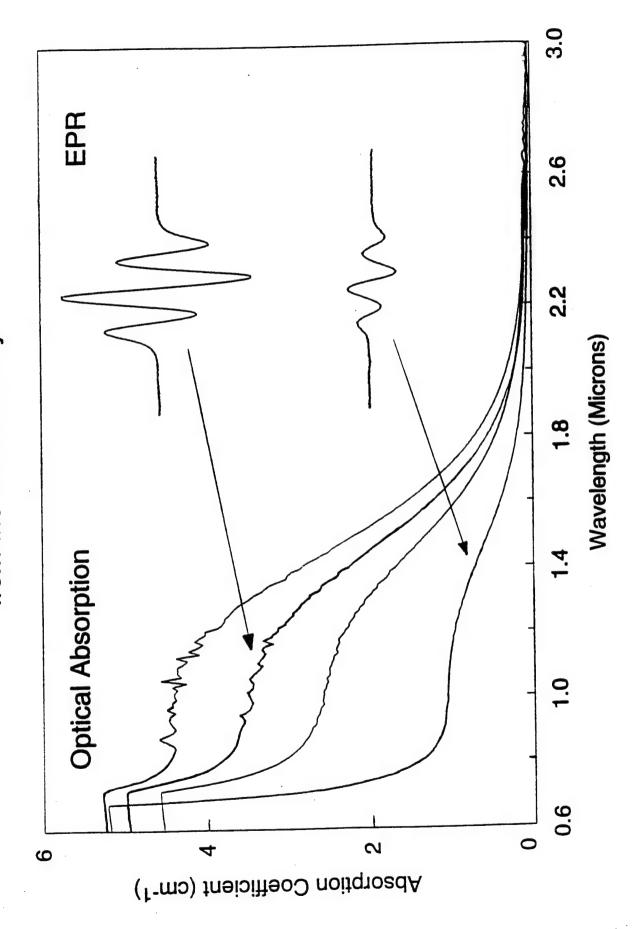
Work performed in cooperation with Lockheed Sanders.

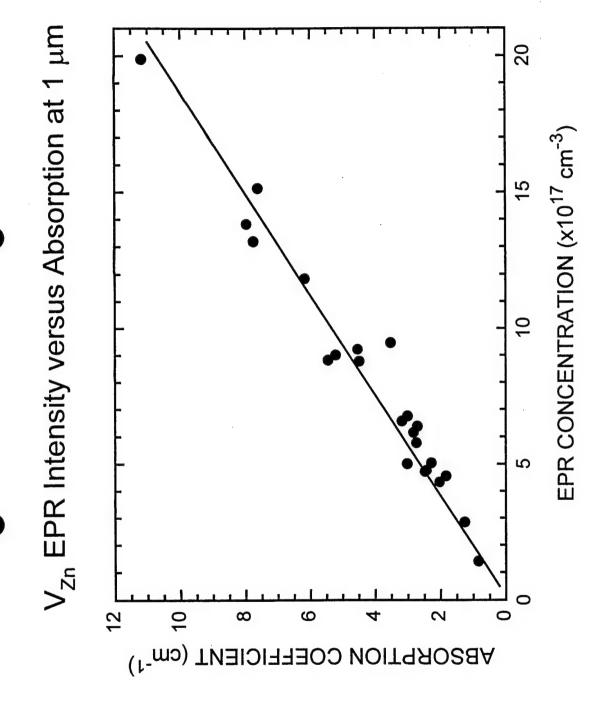
Ni⁺ in AgGaSe₂

Electron Paramagnetic Resonance





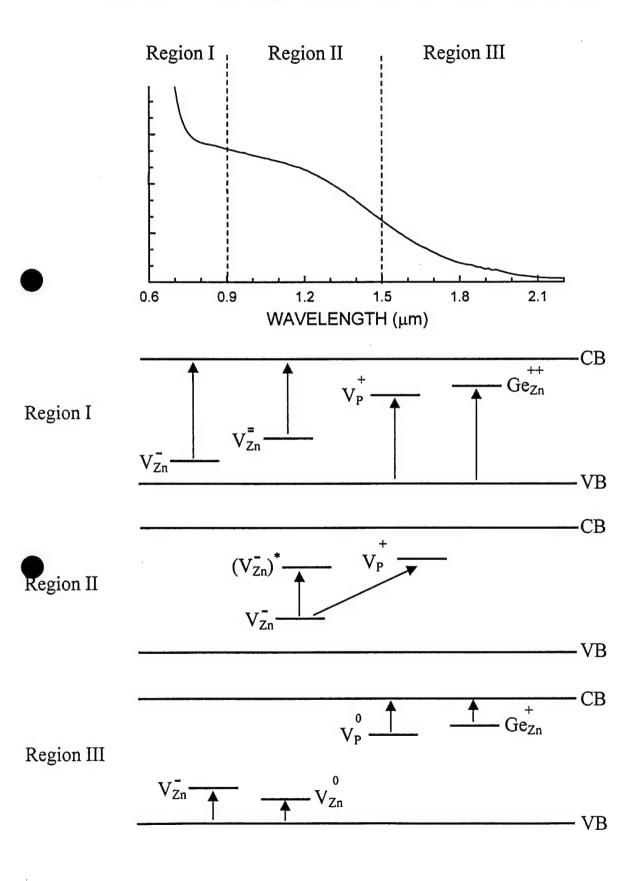




SUMMARY OF DONOR AND ACCEPTOR PROPERTIES

- 1. Zinc vacancies are the dominant acceptor in ZnGeP₂.
 - Both V_{Zn}^- and V_{Zn}^- charge states are present.
 - There is no spectroscopic evidence to date for $V_{Z_n}^{0}$ in as-grown crystals.
- 2. Dominant donors are phosphorus vacancies and germanium antisites.
 - $V_{\rm p}^{+}$ and $Ge_{\rm Zn}^{++}$ in the dark.
 - $V_{\rm p}^{0}$ and $Ge_{\rm Zn}^{+}$ with light.
- 3. Effect of laser light:
 - 633 nm -- increases $V_{\rm Zn}$ signal creates $V_{\rm p}^{\ 0}$ and $Ge_{\rm Zn}^{\ +}$ signals
 - 1064 nm -- decreases $V_{\rm Zn}$ signal creates $V_{\rm P}^{\ 0}$ does not create $Ge_{\rm Zn}^{\ +}$

Possible Optical Absorption Mechanisms



Far-IR Frequency Conversion Chalcopyrites for Mid- to Recent Advances in

P. G. Schunemann and T. M. Pollak

SANDERS

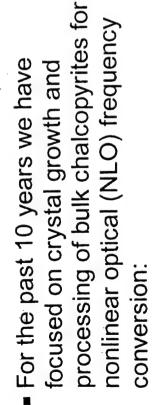
A Lockheed Martin Company

Workshop, (NLO 99), DERA, Malvern, UK, Sept. 20, 1999 Presented at the 1999 Nonlinear Optical Materials

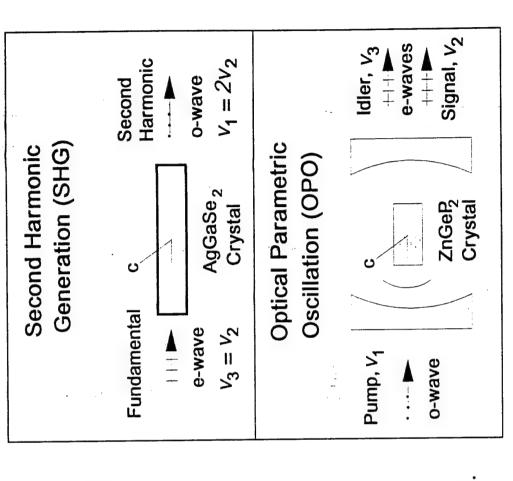
Work supported L.N. Durvasula at DARPA (via the Air Force Research Laboratory Materials Directorate contract No. F33615 -94-C-5415) and Sanders Internal R&D Funding

A lookhood Martin's ampone

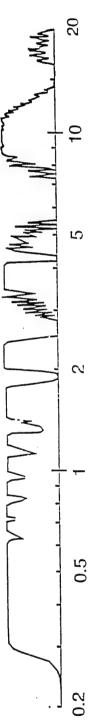
Chalcopyrite Crystal Growth at Sanders



- Frequency doubling of CO₂ Lasers (SHG)
- "Wavelength doubling" of 2um solid state lasers (OPO)
- The Goal:
- Produce efficient mid-IR lasers operating in regions of high atmospheric transmission
- Applications:
- Laser radar, remote sensing, etc.







Strategies for Improved Infrared NLO Materials

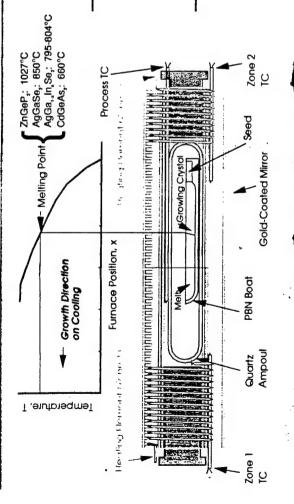
2um-pumped OPO's

- Material of Choice: ∠n(ord).
- Highest NLO Coefficient with sufficient band gap (d₁₄=75 pm/V)
- High Thermal Conductivity (0.35W/cmK)
- Reduced Losses ----> Efficient, High Power Output
- Alternatives for better performance:
- None: Continue to Reduce ZnGeP₂ Near-IR Absorption

CO₂ Doubling

- Material of Choice: AgGaSe.
- Respectable NLO Coefficient (39 pm/V)
- Wide transparency and phase-matching range (.78-18um)
- Low absorption Losses
- Alternatives for better performance:
- CdGeAs₂: Highest Nonlinearity (d₁₄=236 pm/V) → Reduce Absorption Loss
- Ag(Ga,In)Seg: Adjust Birefringence for Noncritical Phase-Matching (NCPM)
- ABX2: Continue Search for New Materials

Horizontal gradient freeze growth led to advances in NLO chalcopyrites



HGF Approach: Key Aspects

Low thermal gradients

- Minimize vapor transport
- Eliminate cracking due to anisotropic thermal expansion

Transparent Furnace

- Simplifies the seeding process
- Allows in situ monitoring of the S/L interface shape & position
- (secondary grains can be re-melted) Facilitates interactive growth

Seeded growth

- Eliminates initial polycrystallinity due to supercooling
- Optimizes orientation to accommodate negative c-axis thermal expansion
- direction for max. device length & yield Enables growth along phase matching





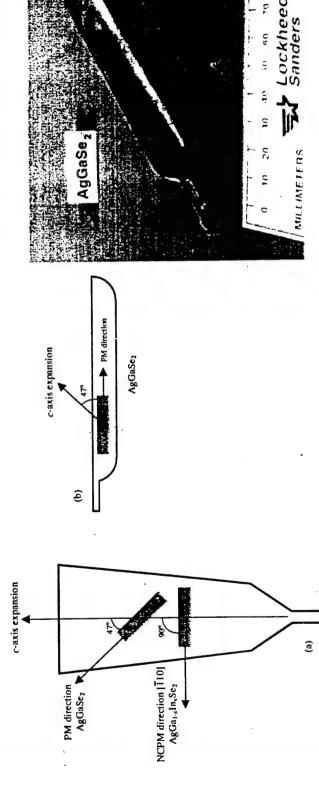
dvances

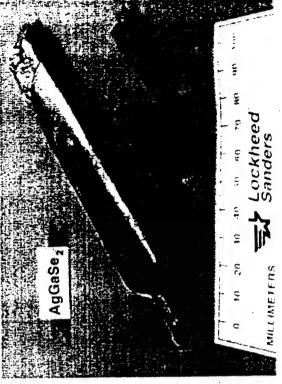
ZnGeP₂: Recent

SANDERS

"Phase-Matched" Crystal Growth of AgGaSe₂

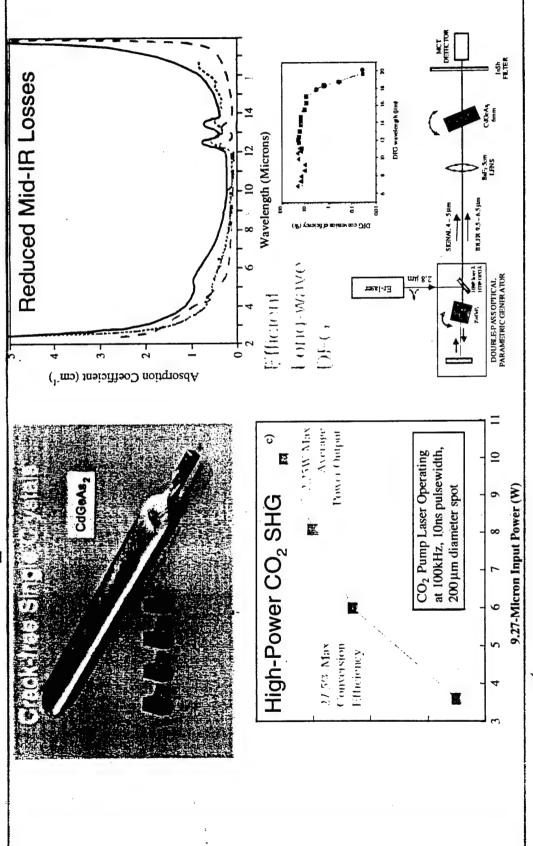
- Vertical Bridgman growth of AgGaSe₂ requires seeding along c-axis for unconstrained thermal expansion during cool-down
- The Horizontal Gradient Freeze (HGF) technique allows "phase-matched" growth along device orientation, yielding longer interaction lengths and minimal waste







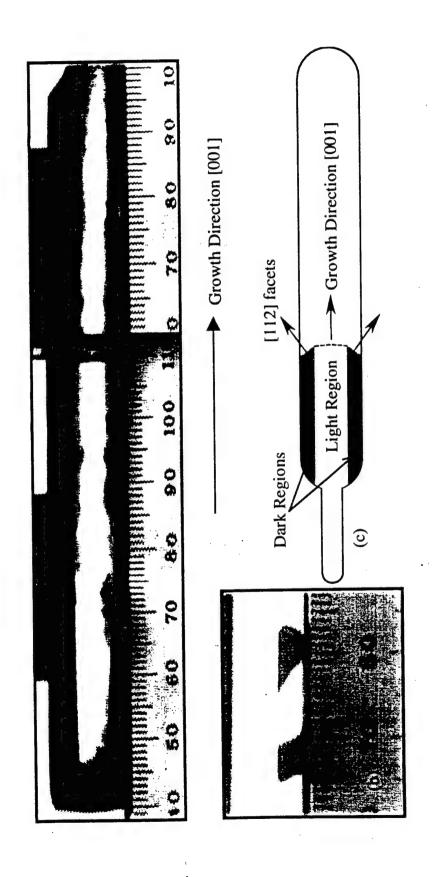
CdGeAs2: Development Milestones



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Segregation of Absorbing Defects in CdGeAs₂

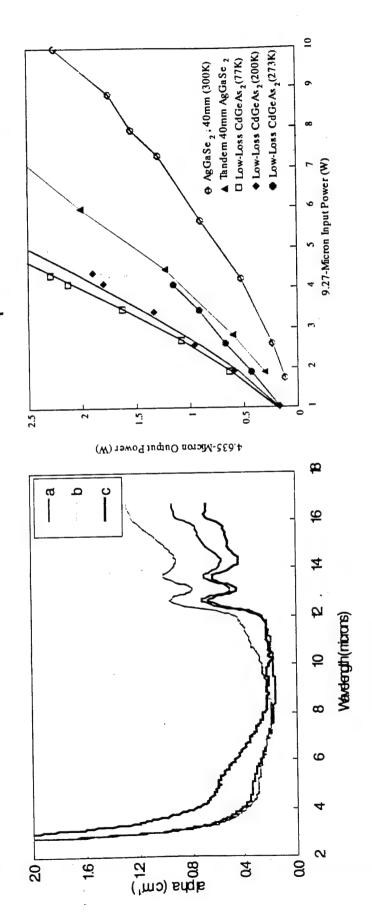




CdGeAs₂: Recent Advances

Reduced Mid-IR Absorption (Low-Loss Central Core)

Efficient CO_2 -Doubling: $\eta = 53\%$ at 77K $\eta = 28\%$ at 273K

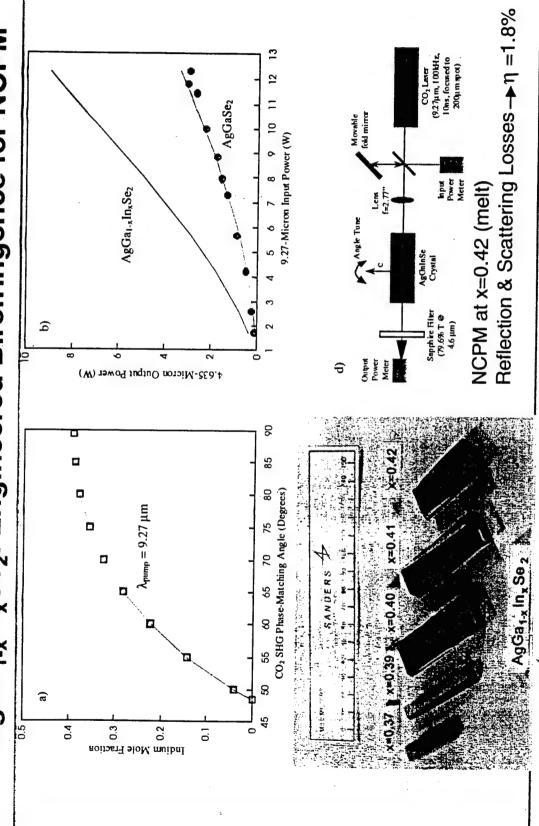




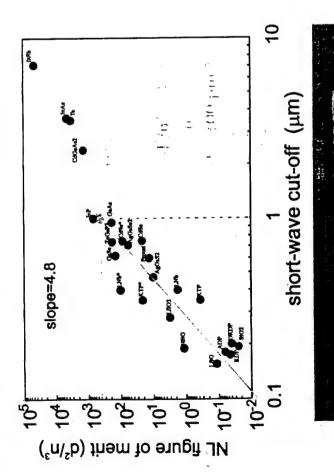
File Order 1977

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AgGaTe₂: a promising new nonlinear optical crystal



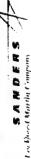
Motivation:

- Telluride analog of AgGaS₂ & AgGaSe₂
- shift the transparency range further into the IR (\sim 1- 20μ m) triple the NL coefficient and Substitution by Te should
- Objectives of Research:
- Produce large, crack-free single crystals
- sufficient for phasematching Determine if birefringence is

Approach:

P. INC.

- **HGF Growth in Transparent** Furnace
- Fabricate prism, measure ∆n



Summary

- Recent crystal growth advances have established chalcopyrites as the NLO materials of choice for mid- to far-IR laser frequency conversion:
- Large crack-free single crystals (up to 16x28x140mm³) of ZnGeP2, AgGaSe2, and CdGeAs₂ can be reproducibly grown by the HGF technique
- achieved by feed purification, compositional control, & post-growth annealing Substantial reductions in absorption and/or scattering losses have been
- Improved crystal quality has resulted in outstanding NLO device performance
- The birefringence of mixed crystals (AgGa_{1-x}In_xSe₂) can be engineered to achieve non-critical phase-matching (NCPM)
- The search for new materials has led to promising NLO crystals such as AgGaTe2, CdGa2S4, and CdGa2Se4
- Dy³⁺:CaGa₂S₄ was demonstrated as the first sulfide mid-IR laser host



Development of Technology of ZnGeP2 Single Crystal at

Institute for Optical Monitoring SD RAS

By Alexander I. Gribenyukov, Galina A. Verozubova, and Valentina V. Korotkova

Laboratory of Optical Spectroscopy

Institute for Optical Monitoring

Tomsk Branch of Siberian Division

Russian Academy of Sciences

	The main directions	• Theoretical and experimental investigations of climatic and ecological
	of IOM activity &	changes under effect of natural and human factors
	interests	
	The basic theme of	 Development of new techniques and technologies for environment
IOM	the noted direction	remote sounding
	of IOM's activity	
	Divisions of the	 Development of optical monitoring systems based on new generation of
-	basic theme	tunable coherent radiation sources working in the middle IR spectral
		range.
	The main task	Provision of IOM works on development and multiplication of the new
	£	optical systems by optical materials needed
FOS		
IOM	The basic theme	Development of high yield and reliable technologies for production
		optical materials with controllable physical properties
	The main points of	1. Development of high yield technology of single crystal growth
	contents of basic	2. Investigations of possibilities of controllable manage by physical
	theme	properties of material due to purposeful changes (variations) of
		technological parameters on all stages of crystals production – at
		synthesis, at crystal growth, at postgrowth annealing

First Long-term Program

High priority problems related to ZnGeP2 technology

reproducible temperature profiles. The equipment could be working growth equipment ensured high Creation (development) of the with high reliability.

Creation(development) of a new moderated (modified) synthesis technique which could assure a production of as-synthesis ZnGeP₂ with controllable (managed) composition.

single crystal technology of Development of high yield ZGP growth

1987 - 1988

- First prototype
 - Series of 6 VB furnaces

Temperture of reaction start

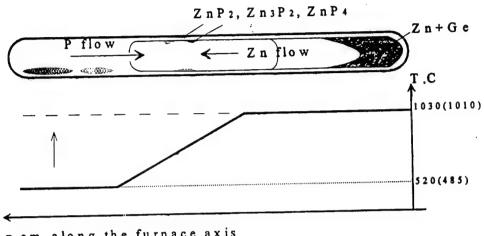
1988 - 1991

- Intermediate phases
- Reaction velocity
- Choice of container material

1989 - 1994

- Choice of seed orientation Computer calculations of
- K_L/K_S ratio evaluation temperature profiles
- Calculations & measurements of real growth rate

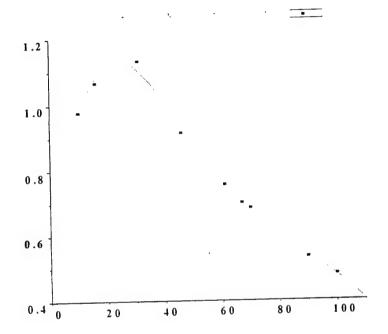
TR9. P4 and Zn flows in non-isothermal closed synthesis system.



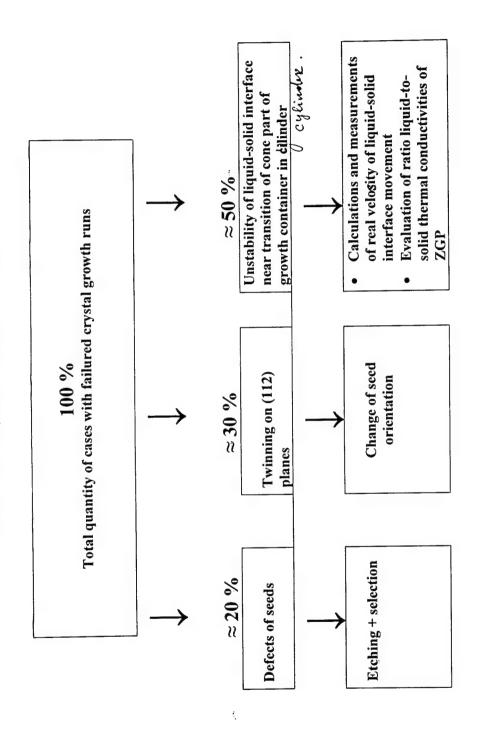
z,cm along the furnace axis

 $TR10-Time\ dependence\ of\ expenditure\ velocity\ of\ P4\ vapour\ under\ pressure\ of\ 10-12\ atm\ \ with\ Zn-Ge\ melt\ at\ 1010\ C$.

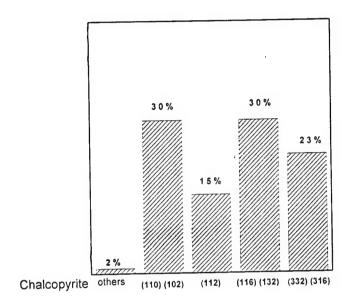
Hot zone temperature - $1010 \, ^{\circ}\text{C}$ Cold zone temperature - $515 \, ^{\circ}\text{C}$ ($P_{P4} = 10 \, \text{atm}$)



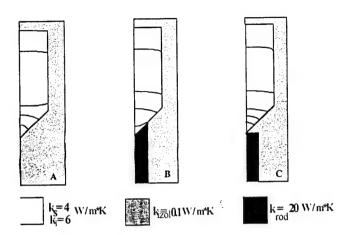
Distribution of growth failures on causes

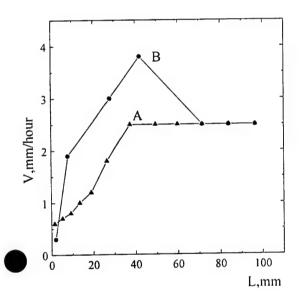


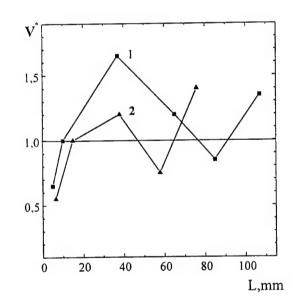
TR12 - Probability distribution of ZGP crystalline blocks enlarged along growth axis in VB-method with spontaneous nucleation.



TR14 – The image of growth container surrounding structure for computer calculations.







GF method:

The isotherm crystallization rate for container with A and B surrounding structure.

Cooling rate - 1 °/hour.

VB method:

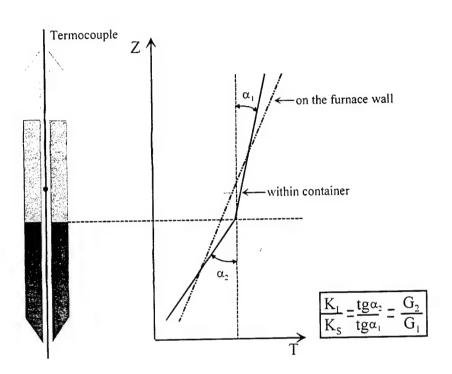
Distribution of isotherm crystallization rate (in units of mechanical movement rate) along crystal axis.

A-type of surrounding structure , Ø furnace=6 \$m;

1 - calculation's data ,Ø_{ampoule}=3 €m;

2 - experiment's data, Ø ampoule = 2 cm;

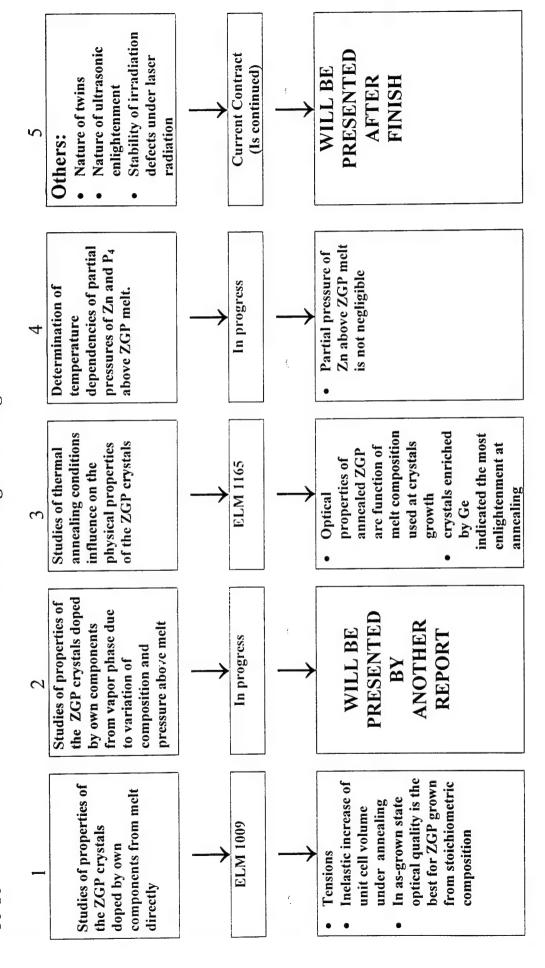
દુર્ત હતું યુ R15. Diagram of stady state temperature distribution



Material		Linear regres	Calculated values			
Material	Ts	Gs	TL	GL	\mathbf{T}_{mel}	KL/Ks
Ge	942.42	4.6	940.51	2.7	937 ± 1	1.7 ± 0.1
GeP ₂	2009.9	16.24	1807.53	12.9	1027 ± 1	1.3 ± 0.1

Literature data for Ge: $K_L/K_S = 2.93$ [3] Corrected ratio for $ZnGeP_2$: $K_L/K_S = 2.3$

The Second Long-term Program



TR17 Some Results of investigations of ZGP crystals doped from melt. Measurements were made in DERA. The crystals were grown in IOM

Crystal	Dopant (P4-pres. atm)	Temperat . gradient DT/dx, °C/cm	Unit cell volume, Å ³	Unit cell volume difference (Virt - Vrt)	Absorpt. coeff. at 2.06 μm cm ⁻¹	Absorpt. coeff. difference a _{llf} - a _{llf} cm - 1	Derivative dα/dV, cm ⁻¹ Å ⁻³	Unit cell volume after annealing	Absorpt. coeff. after annealing cm ⁻¹
89/3 ftf	0.2 wt%Ge	5.2	319.94861	-0.03872	0.431	0.016	-0.465	320,234	0.27 –meas.
89/3 ltf 91/2 ftf	(7.5) Stoich (7.1)	1.5	319.92818	+0.12000	0.332	0.129	+1.07	320,332	0.36 –meas.
91/2 ltf 93/3 ftf 93/3 ltf	0.2 wt%Zn (3.8)	2.5	319.98361	-0.04372	0.615	- 0.105	+2.4	320,190	0.53-meas. 1.11-calc

Seeds orientation is (116) for all grown crystals.

Annealing result in an increase of unit cell volumes, but expected change of absorption coefficient with the unit cell volume indicated only for sample enriched by Ge.

ZGP GROWTH FROM MELT: THE VAPOUR PHASE COMPOSITION AND CRYSTAL PROPERTIES

G.A. Verozubova A.I. Gribenyukov Yu. F. Ivanov*

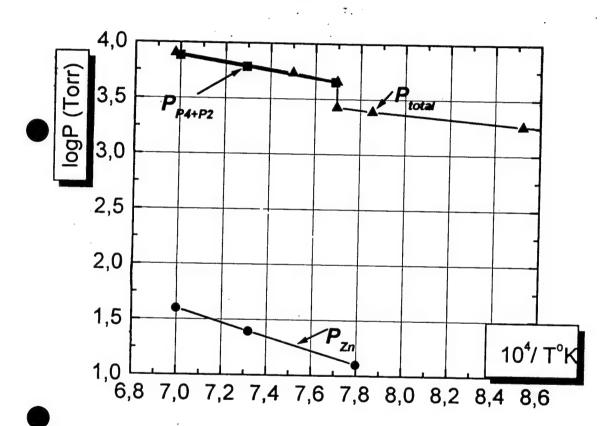
Institute for Optical Monitoring SD RAS
*Tomsk Polytechnical University

in collaboration with A.Vere, DERA, Malvern

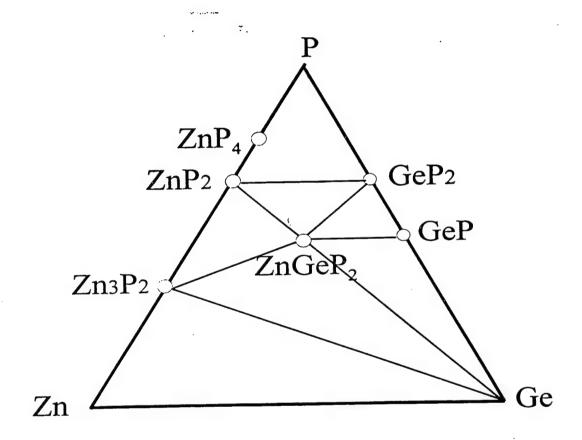
The work was fulfilled under financial support DERA, United Kindom

327°C - ZnGeP₂ starts to decompose

1038°C - ZnGeP₂ melting point (Seb Fiechter, 1996)



The total pressure above $ZnGeP_2 - P_{total}$ (Buehler, 1971) and partial pressures of $Zn - P_{Zn}$ and $P - P_{P4+P2}$ calculated from the regular solution theory (Roenkov, 1975): $P_{Zn} = 18$ Torr at 1068C



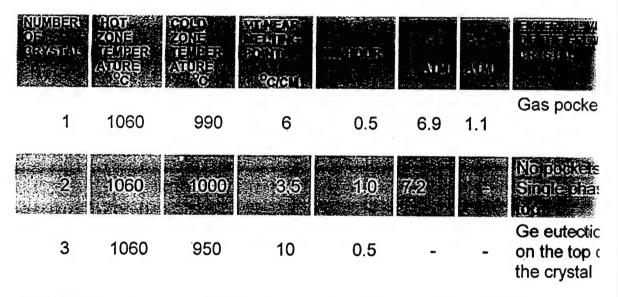
The Zn-Ge-P phase triangle

Experimental details

<u>Synthesis</u>: modified two-temperature technique, allowing to produce more then 500 gms of the material in one process

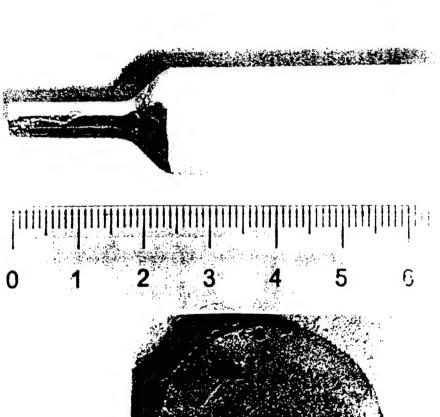
Growth: vertical Bridgman technique, (100) seeds

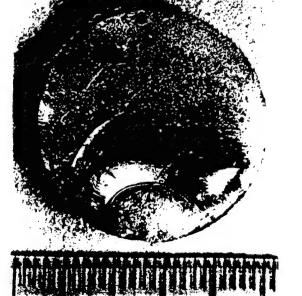
TABLE 1. Crystal growth conditions.

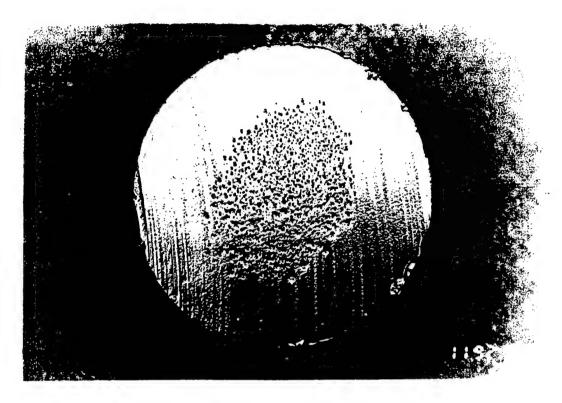


^{*} P_{P4} (P_{Zn}) - pressures of phosphorus (zinc), created by additional charges of P (Zn), and calculated from the ideal gas law.

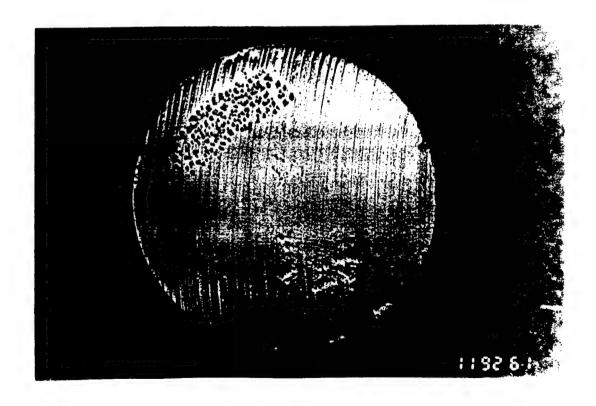




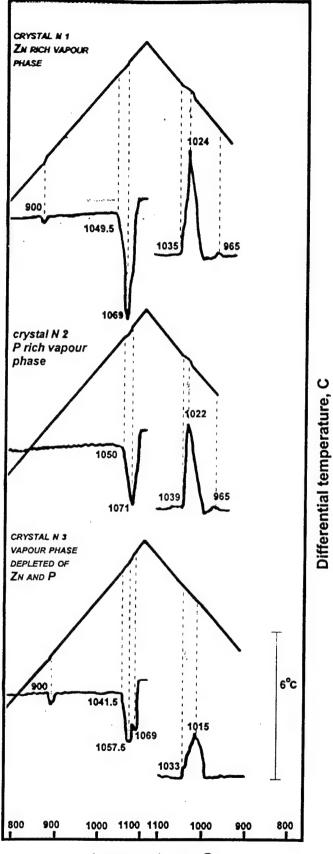




1 cm

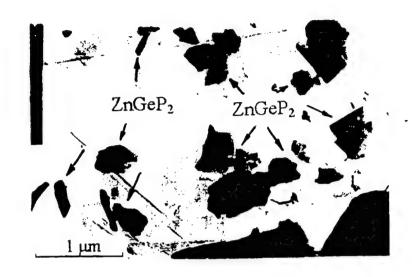


ZnGeP2 slices after chemichal etching



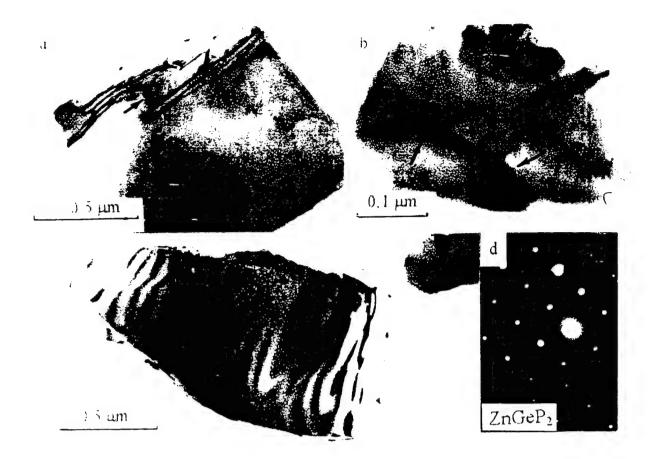
temperature, C
DTA curves of ZGP grown under various pressures of Zn and P

Experimental details: the weight of the studied samples-0.5 g , heating and cooling rates - 7.5deg/min reference material - AI2O3, speed of the paper movement - 1 mm/mm



Fragments of failure (damage) of the bulk ZGP specimen arranged on the carbon substrate

Electron microscope EM-125 Accelerating voltage 125 kV Working Magnification 65-85 000 Resolution 7-10Å



Microscopic image of ZnGeP₂

A Theoretical Study of Defects in ZnGeP₂ and CdGeAs₂

Ravi Pandey

Michigan Tech., Houghton, MI 49931 (pandey@mtu.edu) (AFOSR-F49620-96-1-0319)

Approach: calculations of defect configurations and energetics in the framework of the atomistic model.

Results:

- dominant native defect in both ZnGeP₂ and CdGeAs₂. (i) Cation sublattice disorder is predicted to be the
- (ii) The nature of defects responsible for the near-IR absorption band in ZnGeP2 and CdGeAs2 appears to be different -

ZnGeP₂: zinc vacancy (localized hole)

CdGeAs₂: cadmium antisite (delocalized hole)

Defect-induced lattice distortion plays a key role in stabilizing the hole states in the lattice.

expected to introduce significant lattice distortion while Based on the size argument, antisites in ZGP are not those in CGA would be expected to cause significant distortion in the lattice.

$$R_{z_n} = 1.23 \text{ Å}, R_{g_e} = 1.23 \text{ Å}, R_{cd} = 1.41 \text{ Å}$$

Dopant Binding Energies in ZnGeP₂ and CdGeAs₂

concentration of the dominant native acceptor level selective doping of ZnGeP2 to reduce the via charge compensation in the lattice.

ZnGeP₂

Se, Ga, In: acceptor (Gigoreva 73) » Au, Cu: inactive

^

» Au, Cu, Ga, In, Se, Pt: acceptor

(Rud 97)

^

CdGeAs₂

In, Te: donor » Cu, Ga : acceptor

(Bairamov 98)

Summary

- Both Cu and Ag always act as acceptors.
- for Cu and Ag at the Zn site. small hole binding energies
- group III dopants at the Ge site except B which shows a distinct - large hole binding energies for the behavior.
- donor levels for B, Al, Ga, In predicted to be near middle of the gap.

DEFECT IDENTIFICATION IN ZnGeP2

K. J. Nash DERA Malvern

Discussions, exchange of unpublished results, with

M. Fearn, A.W. Vere (DERA)
L.E. Halliburton, K.T. Stevens
(Will, Morgantown)

SYMMETRY THEORY

Which defect symmetry groups are possible in the ZGP structure?

- Determination of symmetry from experiments.
- . Which defects have a particular symmetry?

• the spin Hamiltonian?

DEFECT SYMMETRY IN ZGP

4 possibilities

- tetragonal
- monoclinic (Czlla or b)

ENDOR on the main defect in ZGP (Halliburton et al)

> monoclinic symmetry (Calla or b)

suggested identity: Vzn

But the Zn site has tetragonal symmetry

Eetragonal 54

monoclinic Celle reduction

of symmetry

triclinic

So Vzn does not have the right symmetry

Other Mudels

where D is a defect site that is close to one P atom and D, E are related by the Cz symmetry axis

4 unpaired spin localised on X; two P atoms related by symmetry

SPECULATION

PGe EPRI?

PGe FRI?

- no evidence for this! but ...
 - · Pae has already been found in ZGP
 - · Pae-Ger-Pae would explain the
 - EPRI signed, if the unpaired spin 15 localised on Gep.

Optical Properties of Tellurium Rich Te_xSe_(1-x) Nonlinear Optical Semiconductors

G.J. Brown*, Cindi L. Dennis*, M. C. Ohmer*, and Arnold Burger**

*Air Force Research Laboratory, Materials & Manufacturing Directorate, AFRL/MLPO, Wright-Patterson AFB, OH 45433-7707

** Fisk University, 1000 17th Ave., N, Nashville, TN 37208-3051

ASC-99-1822

Outline

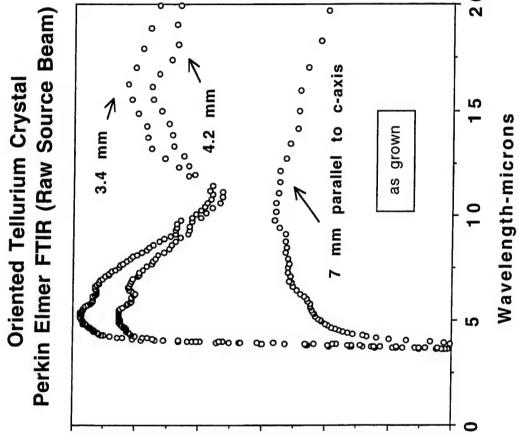
- rich oriented crystals of the form $Te_xSe_{(1-x)}$ for x=1,0.9, Infrared photoresponse and the energy gaps of tellurium and 0.8 are reported.
- Band gaps are comparisoned

3.76 microns	3.26	2.48	0.73
0.33 eV	0.38	0.498	1.7
- Te	$- Te_{0.9}Se_{0.1}$	$- Te_{0.8}Se_{0.2}$	- Se

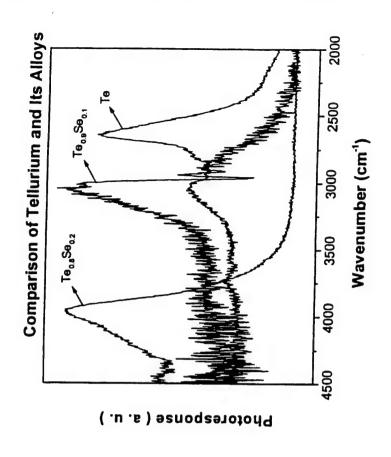
energy gap of 1 eV or 1.24 microns from literature data The composition Te _{0.286} Se _{0.714} is estimated to have an

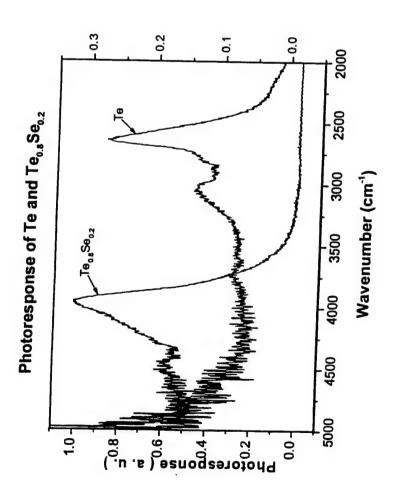
WHAT IS A LARGE SECOND ORDER NONLINEAR SUSCEPTIBILITY (a.k.a. CHI2)?

- The largst reported value for a birefringent element is 650 pm/V for Te. The value for Se is 97 pm/V.
- The largest reported value for a birefringent compound is 470 pm/V for CdGeAs₂
- usefully large for optical signal processing applications The value of 11 pm/V for lithium niobate (LiNbO₃) is
- Two state of the art IR materials, AgGaS₂ and AgGaSe₂ have Chi2 values of respectively 36 pm/V and 66 pm/V
- ZnGeP₂ has a very respectable value of 150 pm/V, but not birefringnent
- The above numbers are normalized to GaAs at 180 pm/V
- Upper limit for bound electrons is 4000-5000 pm/V



Transmission-arb.





AFRL Materials Directorate Efforts in Nonlinear Optical Laser Wavelength Shifting Crystal Development for

NILS C. FERNELIUS*, F.K. HOPKINS, Wright Patterson Air Force Base, Air Force Research Laboratory, Materials Directorate, Dayton, Ohio 45433 & M.C. OHMER

DESIRED PROPERTIES FOR NLO UNOBTAINIUM

BROAD WAVELENGTH OPTICAL TRANSMISSION LARGE NONLINEAR SUSCEPTIBILITY or d LOW LOSS: ABSORPTION & SCATTER

rather dent/ n3

NEED LARGE BIREFRINGENCE FOR PHASE MATCHING

OF USE QUASI-PHASE-MATCHING STRUCTURES)

(or USE QUASI-PHASE-MATCHING STRUCTURES)

TOO LARGE LEADS TO DEAM WALK-OFF PROBLEMS

NEED UNIFORM REFRACTIVE INDEX THROUGHOUT

CRYSTAL

LASER DAMAGE RESISTANCE

WANT SMALL dn/dT TO AVOID SELF-FOCUSSING

WANT STRONG MECHANICAL PROPERTIES

STABLE CHEMICAL PROPERTIES

CRYSTALS EASY TO GROW **INEXPENSIVE**

PROGRAM THRUSTS OF BULK CRYSTAL **CRYSTALS: BIREFRINGENT**

KTP (KTIOPO4) ISOMORPHS- KTA (KTIOA8O4), RTA (RbTIOA8O4), CTA (CSTIOA8O4), KRTA (K_{1-x}Rb_xTiOA8O₄) KTP GREY TRACK

CHALCOPYRITES- ZnGeP₂, CdGeAs₂, AgGaS₂, AgGaSe₂, AgGa_{1-x}In_xSe₂, AgGaTe₂

GaSe

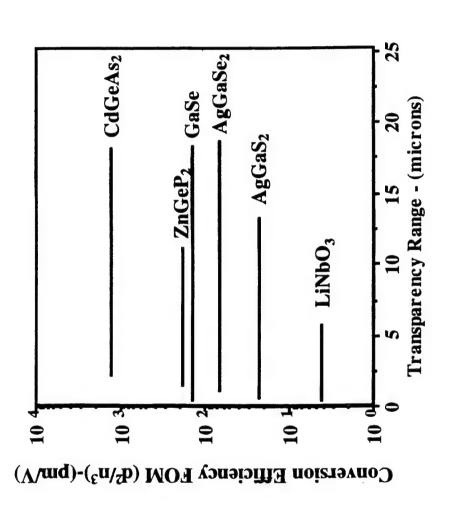
HgGa₂S₄ CGC {CsGeCl₃} CGB {CsGeBr₃}

UV MATERIALS(borates) - LBO {LiB₃O₅},

BBO { β-BaB 2O4}, CLBO { CSLiB 6O10},

KBBF {KBe₂BO₃F₂}, CsLaB₇O_{1,3}, low birefrigence: SBO {SrB₄O₇} & PBO {PbB₄O₇} MM'(B₃O₅)₃ where M = Sr, Ba, Pb; M' = Li, Na

Figure of Merit for Many Common NLO Materials



(%) NOISSIMENART

5.2

GRAY TRACKS IN KTP

Nd:YAG laser produces 355 nm photons (third harmonic generation or sum of fundamental & second harmonic)

KTP room temperature band edge at 350 nm.

Many recombine but a portion are trapped at stabilizing defects such as vacancies or impurities to form "stable" gray tracks. When these complexes contain an unpaired electron, they can be studied by ESR and ENDOR. The above-band-gap photons generate electron-hole pairs.

Flux grown KTP: formation > Fe³⁺ + h⁺ < decay Fe⁴⁺

Ti⁴⁺-V_o + e⁻ < decay Ti³⁺-V_o

Hydrothermal grown KTP: formation

Fe3+-OH- + h+ < decay Fe4+-OH

formation > Ti3+-OH + e' < decay Ti3+-OH

Halliburton & Scripsick, SPIE Proc. 2379 235 (1995)

CHALCOPYRITES

A"BIVCV2 or A'B"CV12

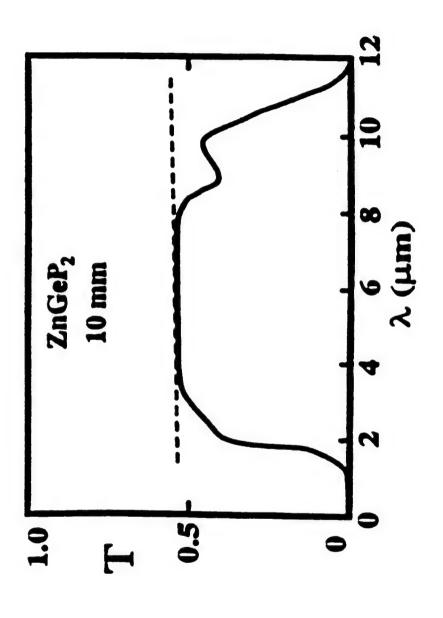
Some examples for IR NLO:

ZnGeP2, AgGaS2, AgGaSe2, CdGeAS2, AgGaTe2

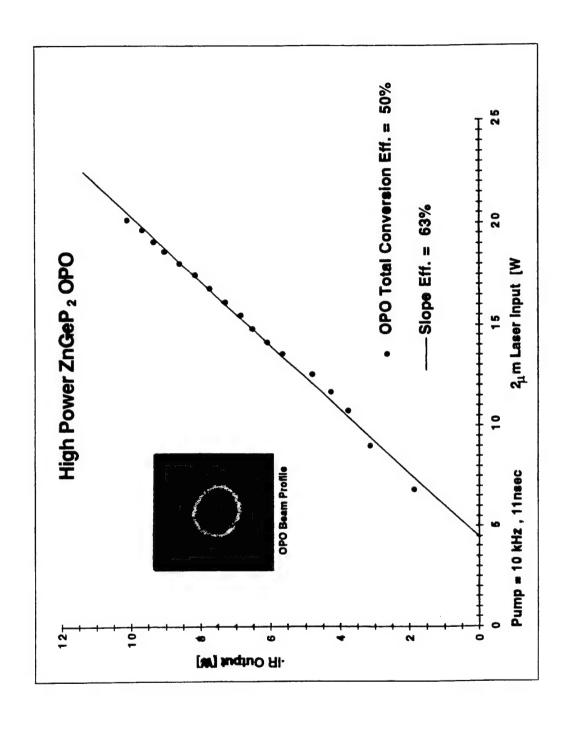
See July, 1998 issue MRS Bulletin 23(7)

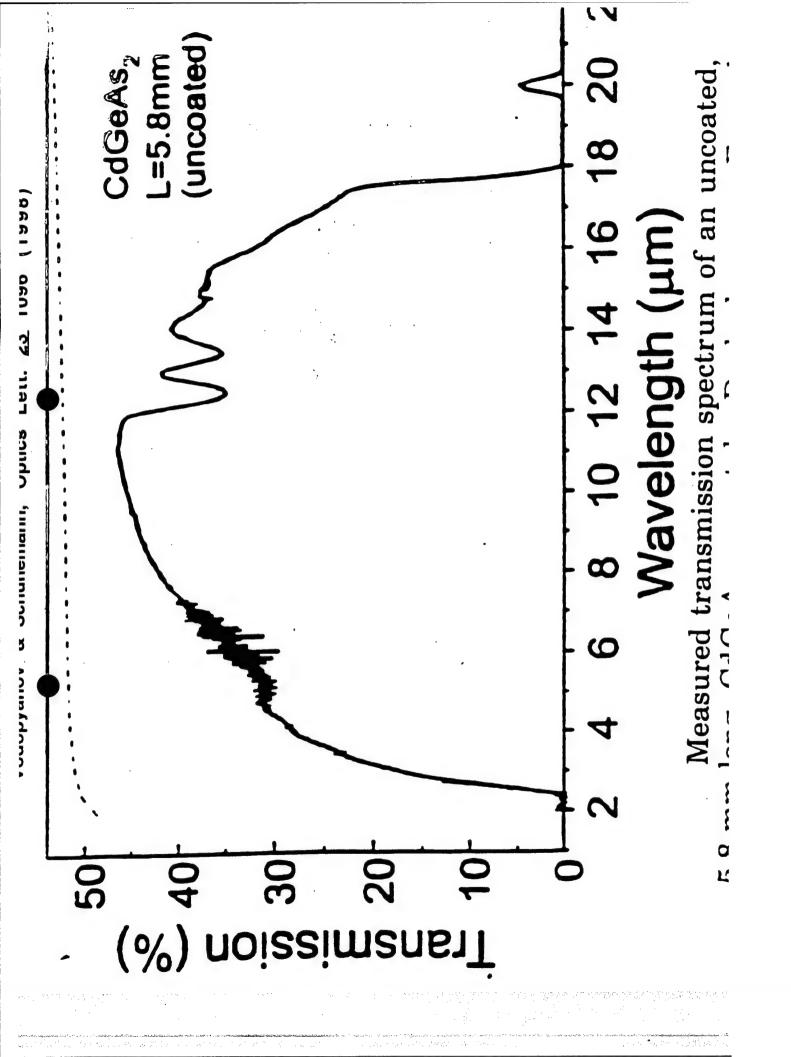
K. L. Vodopyanov

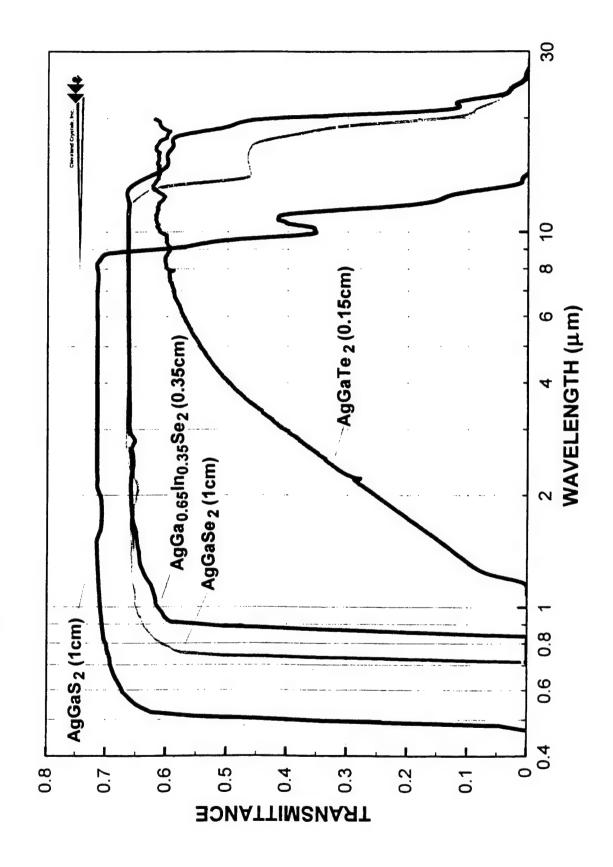
J. Opt. Soc. Am. B/Vol. 10, No. 9/September 1993

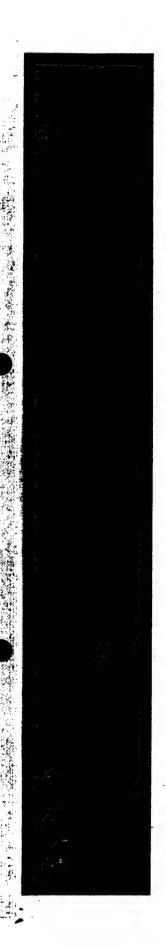


Transmission spectra taken at room temperature. $ZnGeP_2$ (L = 10 mm). Dashed curves, Fresnel losses.



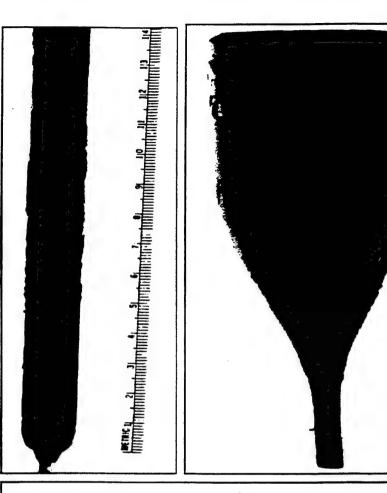


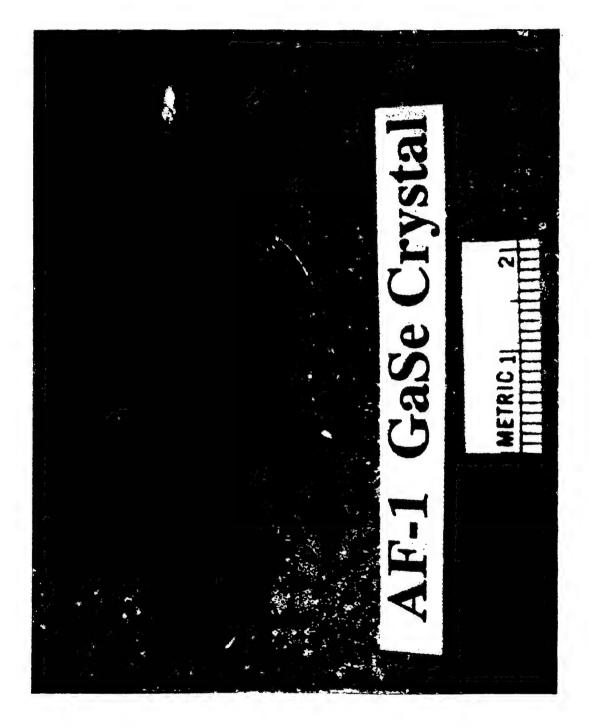


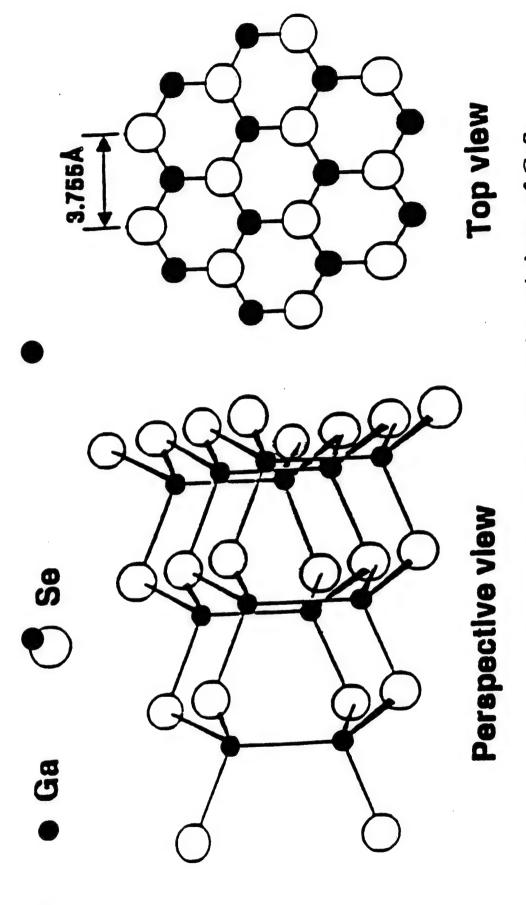


- GaSe has extremely high NLO coefficient (76 pm/V) and merit (d²/n³ 331) compared to ZGP, TAS and AgGaSe₂ crystals.
- GaSe transmits between 0.65 to 20
 micrometer wavelength region without any absorption band.
- GaSe has very high damage threshold and did not damage up to 180 MW/cm² power

NORTHROP GRUMMAN

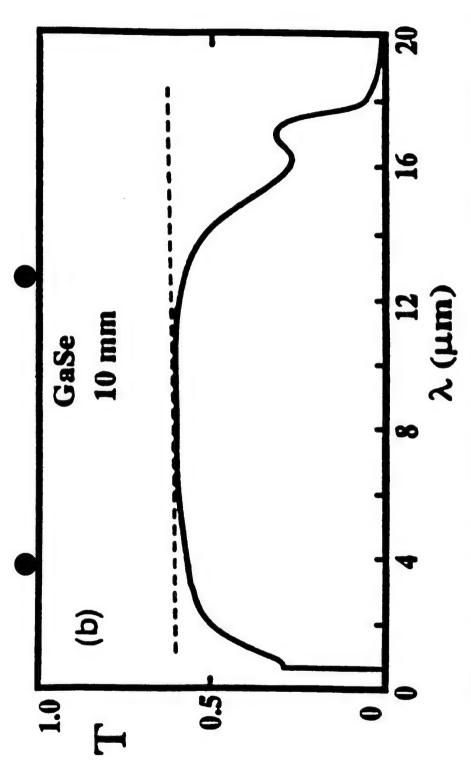






Perspective and top views of a unit layer of GaSe.

Uneo,Abe, Suiki & Koma, Jap.J.Appl.Phys.Lett., <u>30</u> L1352 (1991)



Transmission spectra taken at room temperature. GaSe (L = 10 mm). Dashed curves, Fresnel losses.

K. L. Vodopyanov

RECENT GaSe USES

W.C. Eckhoff, R.S. Putnam, S. Wang, R.F. Curl, F.K. Tittel A continuously tunable long-wavelength cw IR source for high-resolution spectroscopy and trace-gas detection Appl. Phys. <u>B</u> 63, 437-441 (1996)

Difference frequency generation (DFG) of two synchronously pumped Ti:sapphire lasers yields continuosly tunable light over 8.8-15.0 µm region.

K.L. Vodopyanov & V. Chazapis
Extra-wide tuning range optical parametric generator
Optics Communications 135, 98-102 (1997)
Optical parametric generator (OPG) yields continuously tunable light over 3.3-19 μm range.

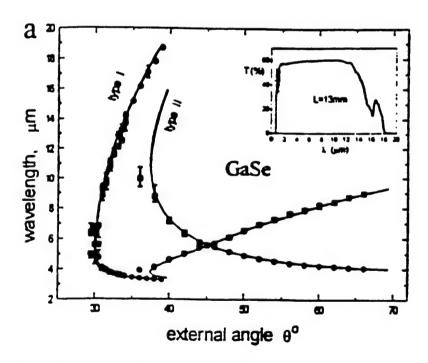
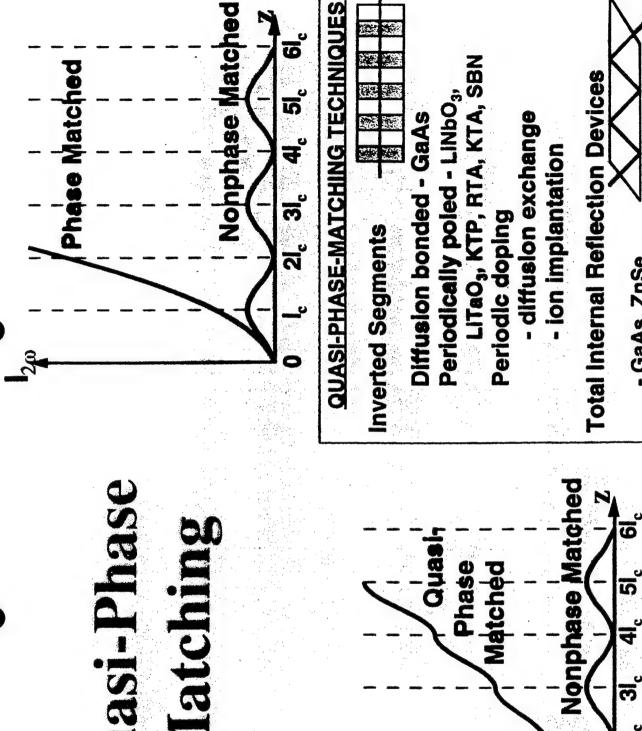


Fig. 2. GaSe and ZnGeP₂ angular tuning curves at $\lambda = 2.8~\mu$ m pump for the two types of phase-matching. Vertical bars correspond to experimental half-maximum linewidths. Solid lines – calculated tuning curves. Insets show linear transmission spectra for the two crystals;

uasi-Phase Matching



- GaAs, ZnSe

THRUSTS OF BULK CRYSTAL PROGRAM QUASI-PHASE-MATCHING TECHNIQUES:

INVERTED SEGMENTS

DIFFUSION BONDED -

PERIODICALLY POLED- 3-5µm: LINBO3 (PPLN),

LiTaO₃ {PPLT},

KTP, RTA, KTA

Pb_xBa_{1-x}Nb₂O₆ (PBN) 8-12µm: CsGeCl₃, CsGeBr₃ Tl₃PbBr₅, Tl₄Pbl₆, Tl₄Hgl₆

PERIODIC DOPING - diffusion exchange

ion implantation

PERIODIC PRESSURE TO INVERT DOMAINS

TOTAL INTERNAL REFLECTION DEVICES - GaAs, ZnSe

Mid IR Multigrating PPLN

Tuning from ~1.4 - 4.8 µm

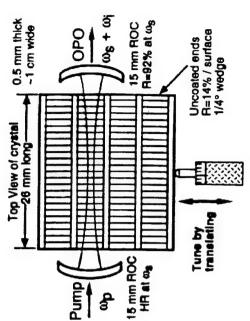
Multi -Watt Output Power

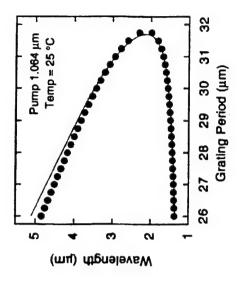
Suffers from Photorefractive Effects

Low Cost Material

Uses 1.06 µm Laser Pump







BEEN PERIODICALLY POLED MATERIALS WHICH HAVE

SroeBao.4Nb2O6 (SBN) (PPLN) (PPLT) (PPBT) (KTP) (RTA) (KTA) KTIOPO4 RbTioAsO4 KTIOASO4 LINDO3 LiTa03 BaTiO₃

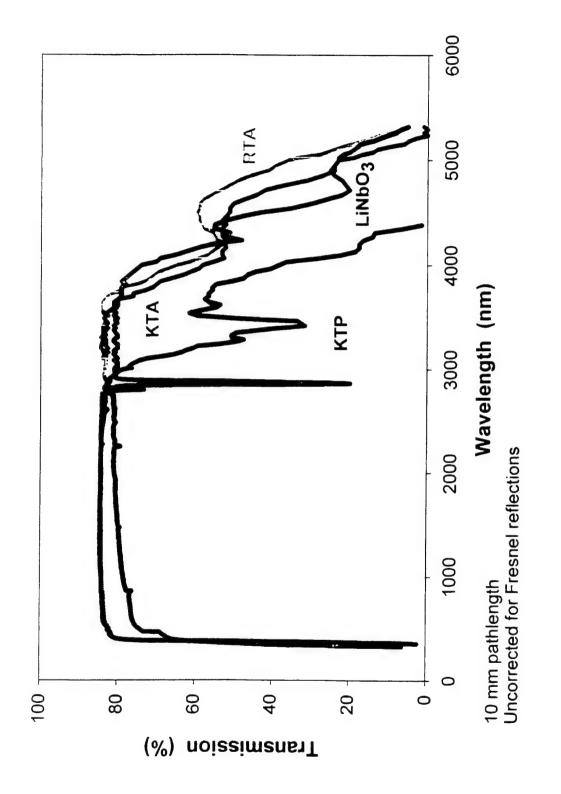
PERIODICALLY POLED LITHIUM NIOBATE-LINDO3 (PPLN)

GOOD POINTS:

USE d33= 42 pm/V INSTEAD OF d31= 5 pm/V AS IN IMPROVES FIGURE OF MERIT BY $_\sim$ BIREFRINGENT PHASE MATCHING CAN USE Nd:YAG 1.06 µm AS PUMP NO WALK OFF PROBLEMS

BAD POINTS:

SMALL INPUT APERTURE WHICH LIMITS POWER OUTPUT M2 PROBLEMS OF OUTPUT BEAMS EVEN WITH STACK HEAT SAMPLE IN OPERATION TO ANNEAL OUT SO FAR SAMPLES 0.5-1 mm THICK UNLESS DIFFUSION BOND A STACK PHOTOREFRACTIVE DAMAGE



MWIR (3-5 µm) THRUSTS

Switch Science Center to cover 4.5-5.5 µm band to cover 4.5-6 µm band (PMNT) to cover *... Library Clear. Rockwell PMNT : Pb{MgxNbyTi1-x-y}O3 Pb_xBa_{1-x}Nb₂O₆ (PBN)

KRTA: KxRb1-xTIOAsO4 Cr

Crystal Associates Best for x = 0

LWIR (8-12 µm) THRUSTS

CsGeCl₃ CsGeBr₃

Tl3PbBr5

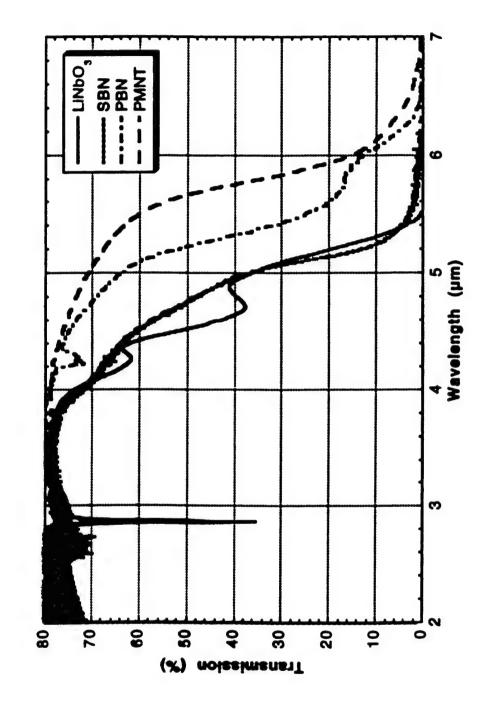
Tl4Pbl₆ Tl4Hgl₆

Northrop Grumman (Pittsburgh) → (Baltimore)

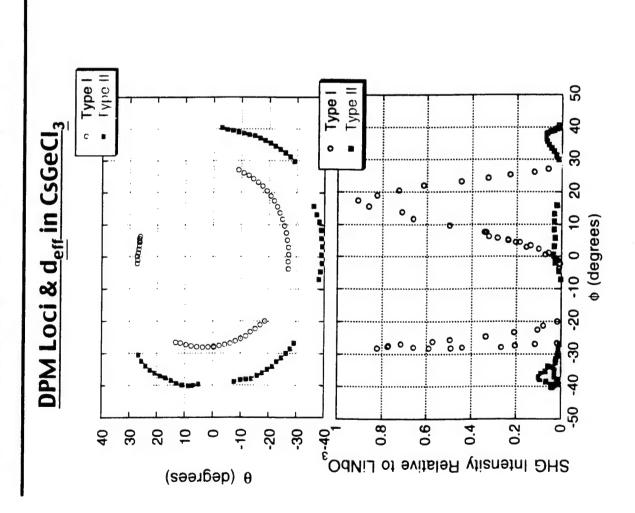
Science Center

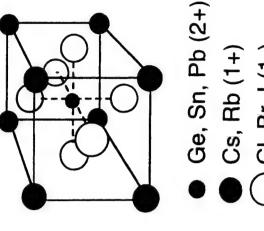
Rockwell

Comparison of Spectral Transparencies in Ferroelectric Oxides



New Family of NLO Materials: CGX





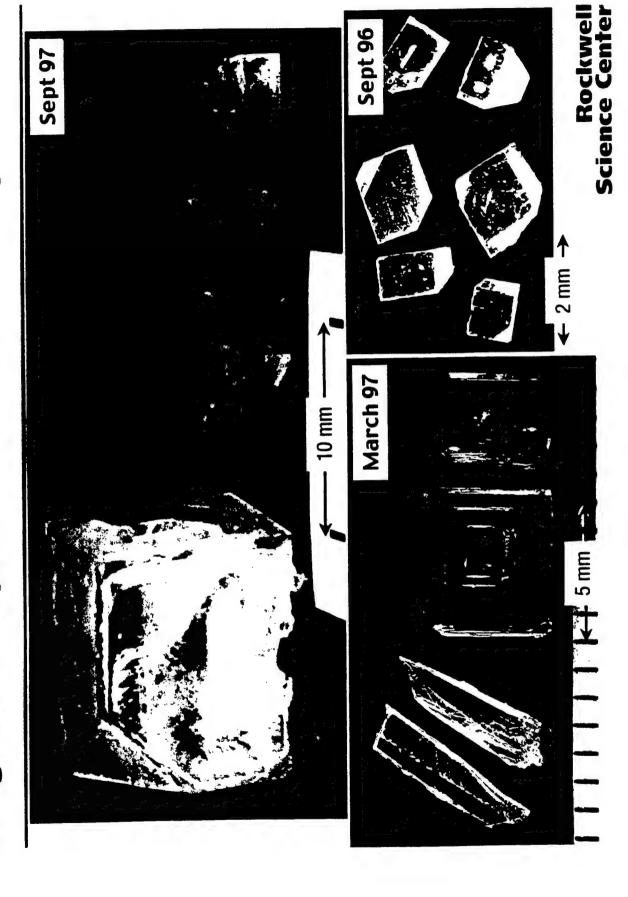
CI, Br, I (1-)

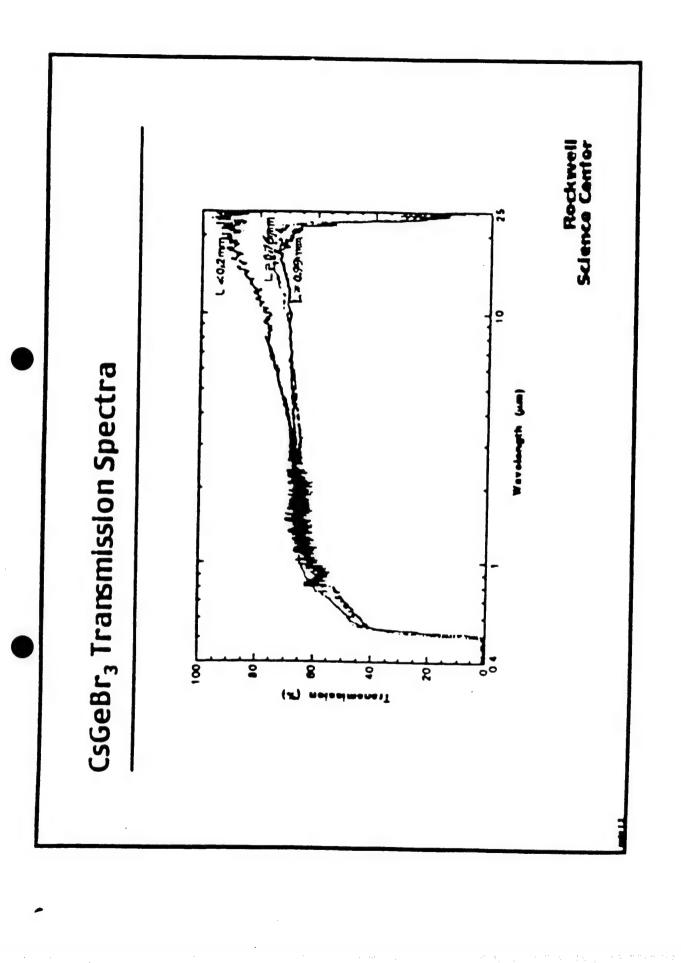
Ferroelectric Halides

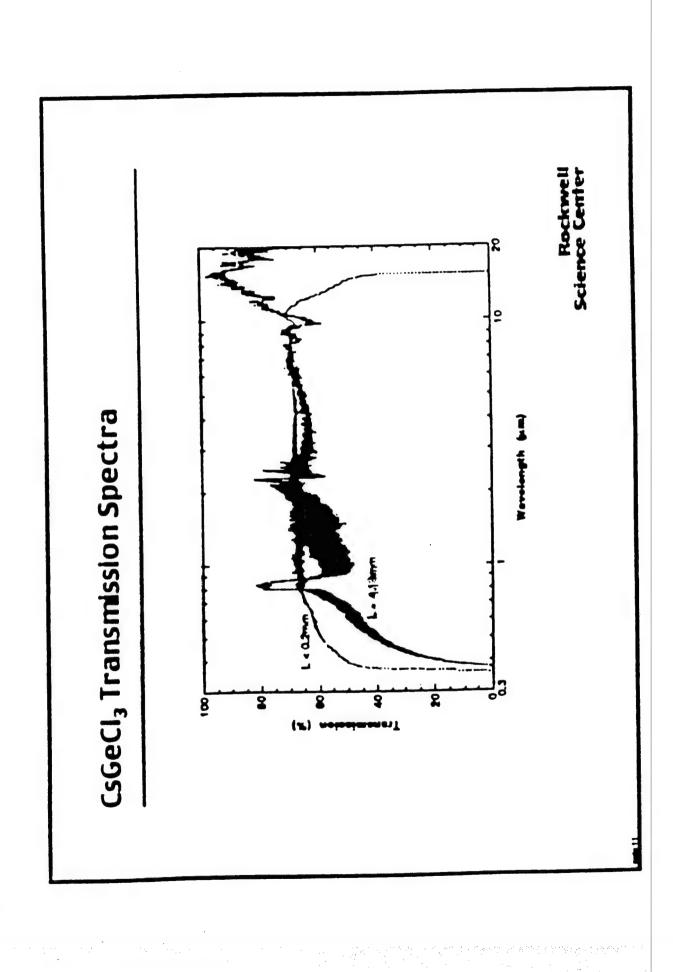
- Perovskite structure
- Wide IR transparency
- Solution-grown semiconductor
 - Mechanically robust
- Nonlinearity ~LiNbO₃
- Periodically poleable?

Rockwell Science Center

Progress in Crystal Growth of CsGeCl₃



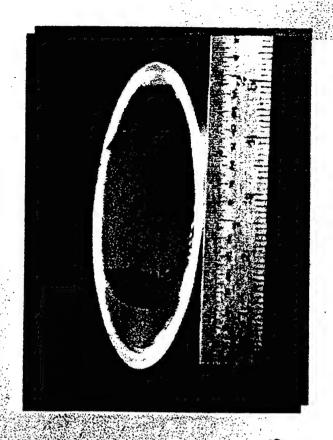




We disclose a novel class of binary halides for the tunability of dielectric experimentally demonstrated the growth feasibility of TI_3 PbBr_{5.}, TI_3 PbI₅ abricated in desired shape and sizes. The devices of these crystals will radar applications. These materials are combinations of A+ B++X (where and Tl₄ Hgl₆ stoichiometry. Many other compounds such as Rb₂ ZnCl₄ $\mathsf{K}_2\mathsf{ZnF}_4,\,\mathsf{K}_2\,\mathsf{ZnBr}_4$ and $\mathsf{K}_2\,\mathsf{ZnCl}_4$ also belong to this category. These compounds were grown by Bridgman method in large sizes and were constant. This will enable very efficient tunable devices suitable for provide high performance rf tunable filters for radar receivers and A is mono valent, B is divalent and X=F, Cl, Br and I). We have communications for receivers such as SC-21 and JSF.

OTAL INTERNAL REFLECTION QUASI PHASE

- GaAs TIR OPM Converter
- Couple Pump Into Plate With GaAs Prism
- Output Via Prism Also Allows Use Of High CHI Two Materials With Little Or No Birefringence



Non-linear for IR region in DTIM

L. I. Isaenko

Design & Technological Institute of Monocrystals SB RAS, 630090, Novosibirsk, Russia, E-mail: lisa@lea.nsk.su



Outlines

- I. Design & Technological Institute of Monocrystals SB RAS:
- field of activity, main crystals;
- contacts and collaborators;

II. Crystal real structure.

1. Investigation techniques;

2. Pyroelectric properties effect on processes of crystallization and defect formation (on example of KTA, LiInS₂);

3. Defects, appearing at deviation from stoichiometry (KTA, A₁6- S₂);

III Structural investigation

- 1. Structural features responsible for spontaneous polarization P_s , in KTA, LiInS₂
- 2. Structural simulation of doping process:
- KTA, doped by Nd and Yb;
- LiInS2, doped by Nd;
- AgGaS2, doped by Yb
- IV. Spectroscopic parameters of polyfunctional crystals
- V. Double chlorides as active media for IR region
- VI. Conclusions

Design & Technological Institute of Monocrystals, Russian Academy of Sciences, Siberian Branch, founded in 1978

The main trends of the scientific research:

- 1 The complex physic-chemical study of the growth processes of the optic quality single crystals for the laser technique and optoelectronics.
- <u>2 Experimental</u> modeling of the diamond crystallization processes and the refinement of the methods of diamond instruments manufacturing.
- 3 Experimental modeling of the natural mineral formation processes and the improvement of the methods of gem crystals growth..

Main growth techniques:

TSSG, Czochralski, Bridgeman-Stockbarger, Kyropulos, low temperature growth from aqueous and organic solutions

The main groups of crystals under consideration:

- 0xides; halogenides, chalcogenides (Tables);

Foreign collaborators:

- 1. The Lawrence Livermore National Laboratory, U.S.A.;
- 2. Tohoku University, Japan;
- 3. Observatory of Paris, Bureau of Metrology, Paris, France;
- 4. University of Bourgogne, Dijon, France,

Financial support:

- 1. Grant of the Civil research and Development Foundation (CRDF);
- 2. INCO-Copernicus grant;
- 3. Contracts with the LLNL beginning from 1992;
- 4. Contracts with other universities/ companies all over the world.

Table 2. SOME CHARACTER STICS OF OFFICE PROPERTY SINGLE CRYSTALS

				,		
Crystal	I ransparency	Max size of choment (mass)	SHC cut off	Ho Mail	Optical damage threshold	Conversion efficiency (%)
-					(MATACOLI)	70/1 064um 20nc 50Hz 2110
LBO	0.16 - 2.6	10 x 10 x 20	554	0.43(I)	>10 000	30(0.8 mm. 20ms 50Hz 2 W)
				0.22(II)	(1.064 µm, 20 ns, 50 Hz)	55(1.064um, quasi CW, 2W)
Odd						50(1.064µm 20ns 3W)
Dea	0.19 - 2.6	4×4×20	411	4.80	>2000 (1.064 µm 10 ns)	20(1 064 20 2015)
CLBO	0.18 - 2.8	5x5x15	471	1.83	>10 000	1 064 2W. 5W
						50/1 06411m 20ns 50Hz 2WA
FEEG	0.28 - 5.6	30 x 30 x 30	630	4.0	500 + 100 (1.064µm, 20ns)	35(0.780µm, 20ns, 10Hz,2W)
W.T.D	0.35 4.5					20(1.064µm, 20ns, 50Hz, 3W)
nir	0.33 - 4.3	5 x 5 x 15	066	90.0	500 (1.064µm, 20ns)	60(1.064µm 10ns 50Hz 2un
KTA	0.35 - 5.5	5 x 5 x 20	1083	90.0	10,000,010	OPO pumping by 20-30
				000	/10 000 (1.004 µm, /0 ps)	(1.064µm, 20ns) to 3-511m
PON	0.44 - 2.1	8 x 8 x 8	1000		2000(1.064µm,15ns)	20(1.32µm, 10ns, 10MW/cm ²
Per A P	0.72 1.05				75(0.53µm,15ns)	L=4mm
Tarret 1	0.23 - 1.95	10 x 10 x 10	532	2.0	>10 000 (1.064µm, 20ns)	*
T. I. C.	0.4 - 12	5 x 5 x 10			>100 (1.064um, 10 ns)	OPO to to 10
Literace	0.6 - 15	5x5x5			>50(1.064, 10 ns)	TIM OF OR OF STATE
AgGaS2	0.46 - 12	$10 \times 10 \times 20$	1736		8000(1.06µm, 15ps, 10Hz)	OPO up to 10 um
					75(1.06µm, 10ns, 20Hz	(1.064µm, 20ps, 10mJ)
AgGaSe ₂	0.65 - 18	-5x5x5			>50	OPO up to 10 µm
					c	DFG up to 18 µm
Care Care	0.7 - 18	5x5x5			3.7 J/sm ² (9.25 µm)	1 (OPO 2.94 µm, 100 ps)
					.0.5 (cw 10.6 µm)	DFG up to 18 µm

Specific effects at crystallization/cooling of pyroelectric (ferroelectric) crystals

1. A strong anisotropy in growth rates along and across polar axis;

2. Self-organization of extended defects structure directed to lower or compensate completely the large pyroelectric fields inside crystal appearing at crystallization or cooling:

• Formation of twin or domain structures from several blocks with different (opposite) direction of spontaneous polarization vector P_s.

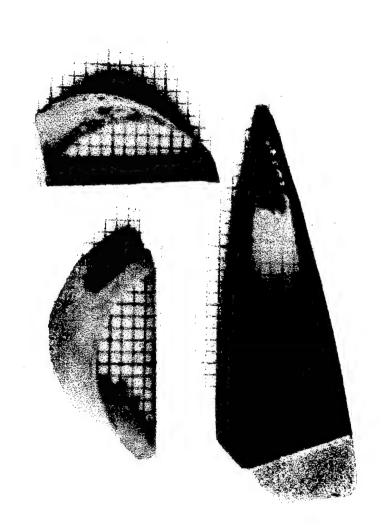
 Formation of channel type defects extended along polar axis and filled by different phases with lower melting temperature which operates as a conductor removing the fields appearing in the «ideal» pyroelectric lattice.

3. Cracking of the crystals is particularly dangerous in temperatures where pyroelectric coefficient γ has maximum.

4. Pyroelectric fields stimulate migration of alkali cations and formation of defects in the cation sublattice.

5. The electric discharge as a result of huge pyroelectric fields inside crystals is one of the mechanisms of their mechanical damage at cooling or dúring operation in laser schemes.







Single crystals

KTiOAsO₄

pyroelectrics ferroelectrics LiInS₂

pyroelectrics

AgGaS₂

nonpyroelectrics

Symmetry

(point group)

mm2

mm2

42m

Lattice parameters

a = 13.103 A

a = 6.887 A

a = 5.757 A

b = 6.558 A

b = 8.05 A

c = 10.746 A

c = 6.474 A

c=10.305 A

density (G/cm³)

d=3.45

d = 3.5

d=4.56

Growth techniques

 $(T_{cryst.}=850-1000 C)$

TSSG

with pulling from selfflux in K₂O-As₂O₅--TiO₂ system

Bridgeman-

Stockbarger

from melt

Bridgeman -

Stockbarger

from melt

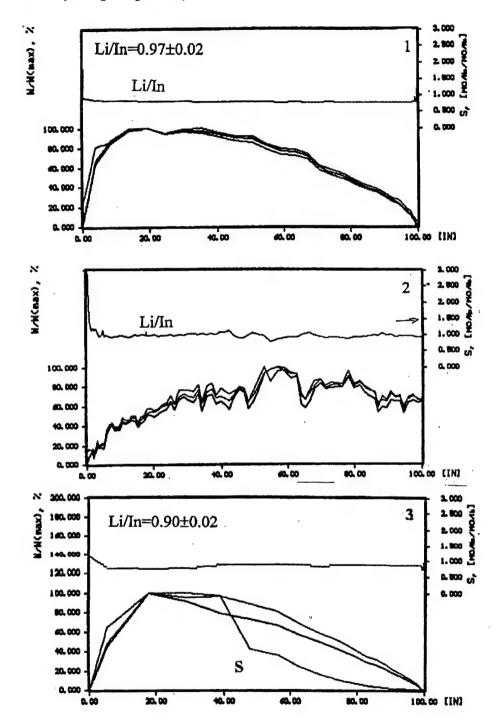
Boule size (mm³)

50x55x45

20x20x50

25x25x100

The technique of differential dissolving combined with the ICP analysis (inductively coupled plasms)



Kinetic curves of dissolving, Li/In stoichiogramms for: 1, 2- grown samples, 3- annealed in S_2 sample

	IXIA			AgGa	\mathfrak{S}_2
Dopant	Yb	Nd	Nd	Yb	Nd
Segregation coefficient C_{cryst}/C_{melt}	0.2	10 ⁻³ -0.1*	0.02	0.02-0.3**	<10-3
Possible position of dopant ion in the lattice	Distorted TiO ₆ prism, two sites: Ti(1),Ti(2)	K-O(8,9) polyhedral Formation of NdO ₇	Octahedral cavity	Octahedral cavities Distorted octahedral	
Absorption cross-section, cm ² (300K)	1.2 x10 ⁻²⁰		2x10 ⁻²⁰		

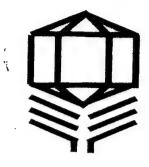
LiInS. AgGaS.

KTA

Necessary conditions for dopant stability in the crystal structure:

- Coordination number ≥6;
- Similarity of sizes for dopant ion and host site;
- Charge compensation

Notes: * for KTA:Me²⁺ for milky as grown AgGaS₂ sample



Design & Technological Institute of Monocrystals SB RAS

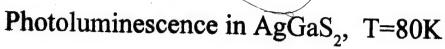
43 Russkaya str., Novosibirsk 630058 Russia E-mail: alex@elis.nsk.ru

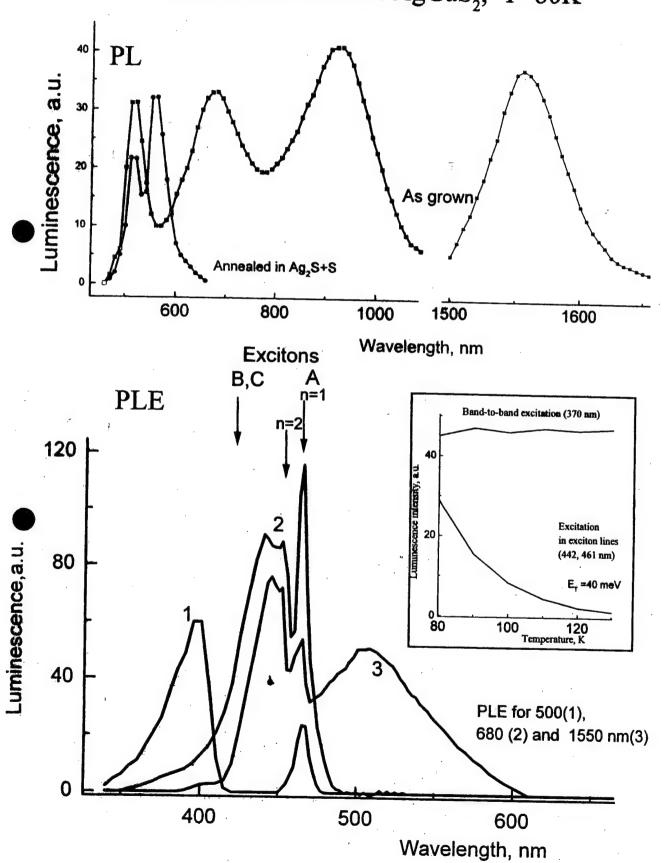
Spectroscopic properties of pure and Rare Earth-doped nonlinear crystals for the mid-IR

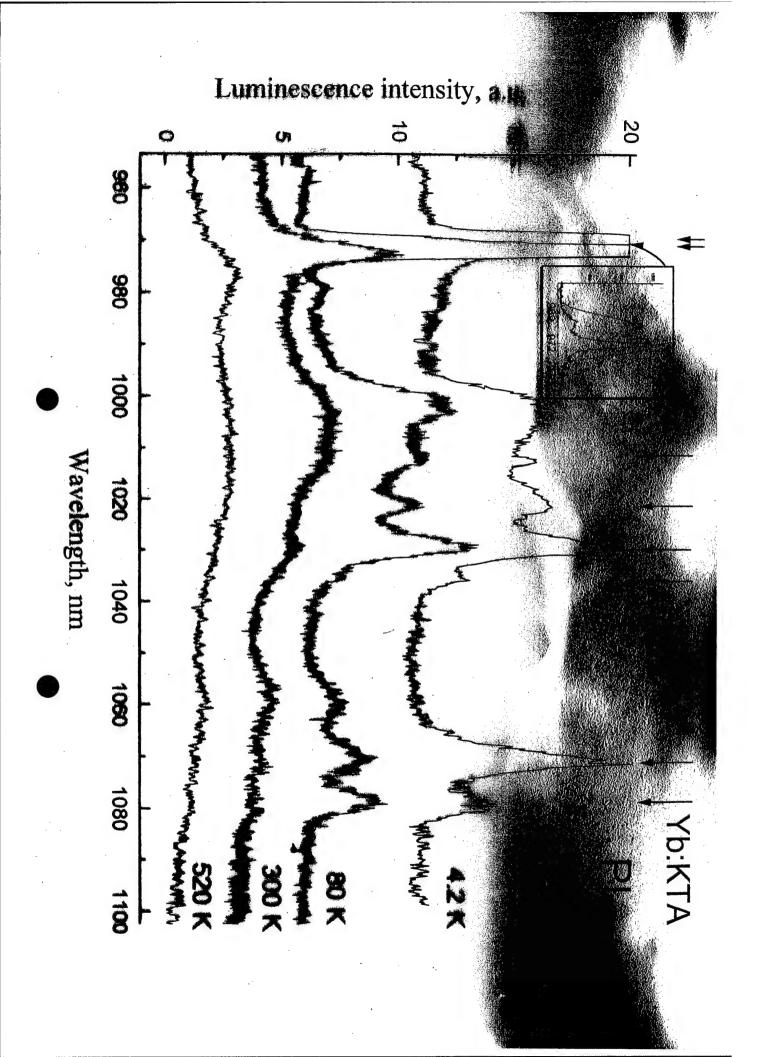
A.Elisseev

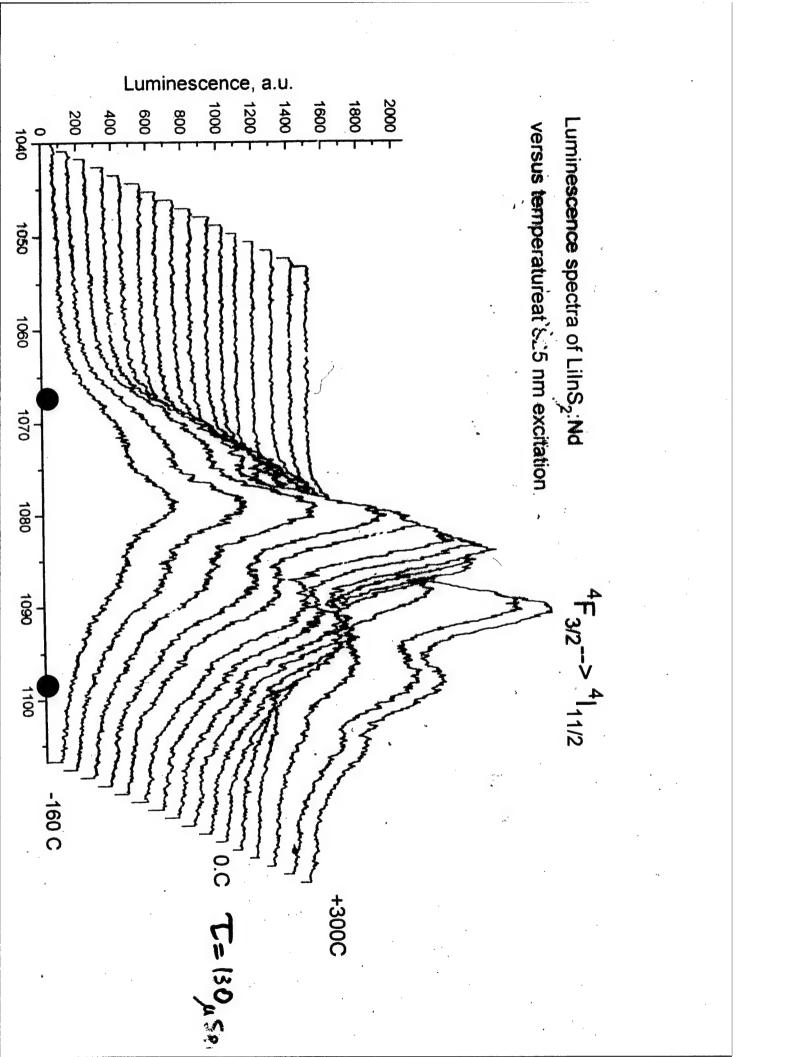
Outline:

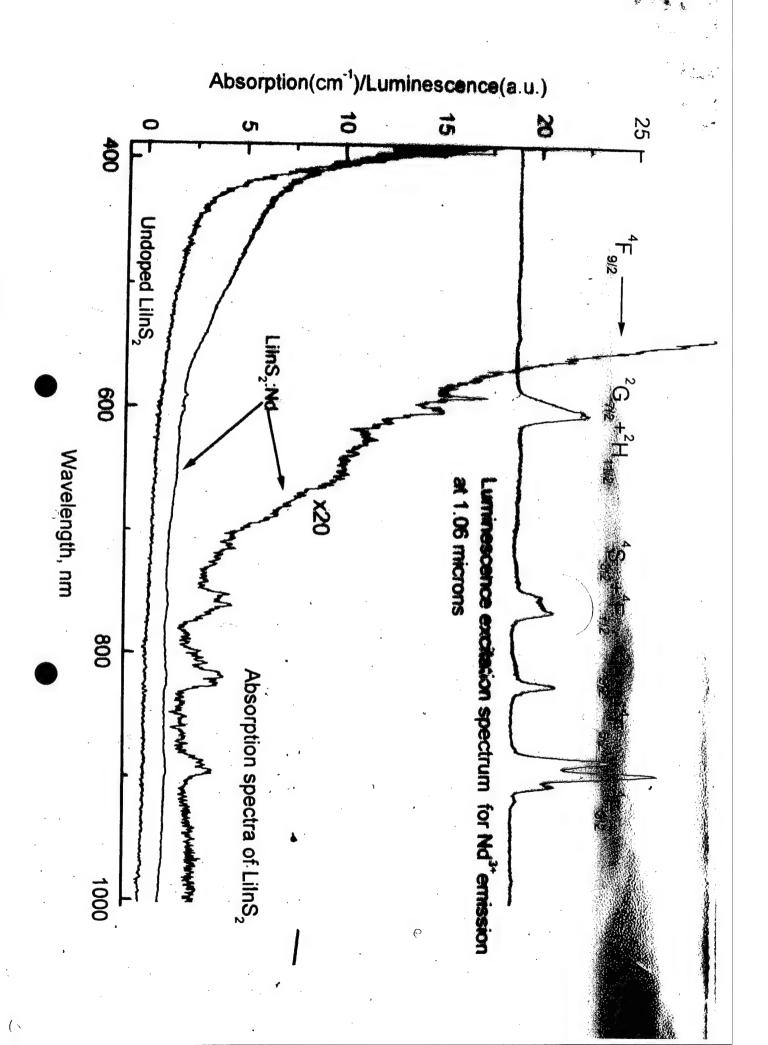
- A. Spectroscopic features of pure nonlinear crystals
- 1. Absorption /luminescence of pure nonlinear single crystals for the mid -IR: excitation mechanisms
- KTiOAsO₄ (KTA);
- AgGaS₂;
- LiInS₂.
- B. Spectroscopic properties of RE-doped crystals
- 1. Option of RE dopants for nonlinear crystals as
- Polyfunctional laser elements;
- Chalcogenides as an active media for the mid IR;
- 2. Spectroscopy of Nd and Yb: spectra, decay times,
- 3. Radiation and radiationless multiphonon relaxation, stimulated emission in the mid-IR











Growth and Optical Properties of LiNbO₃-WO₃ and LiNbO₃-MoO₃ solid solutions

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Glasgow G1 1XN, Scotland, UK

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Crystal Growth

- Method: Czochralski
- Composition: X < 10 mol%

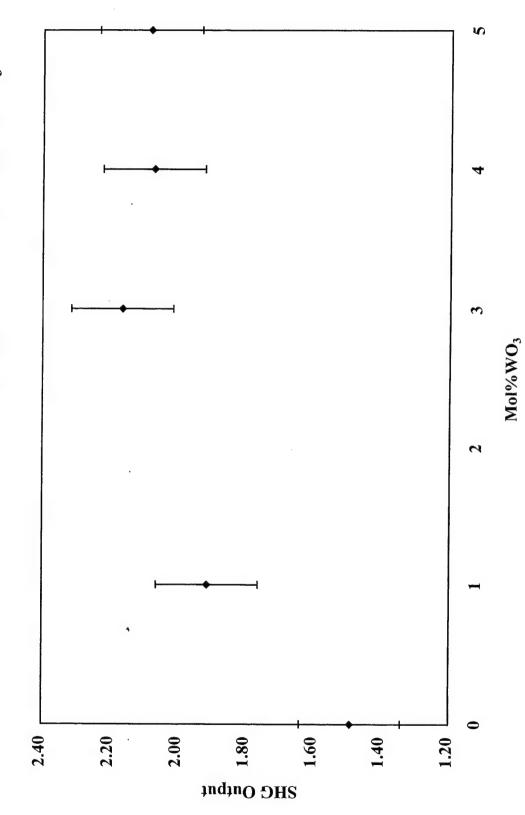
At
$$T = 860$$
 °C, $X = 0 - 50$ mol%

At
$$T = 750$$
 °C, $X = 0 - 20$ mol%

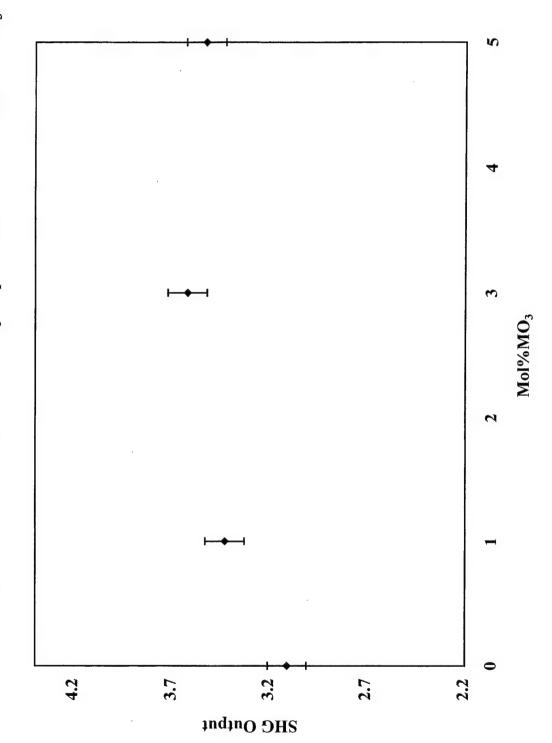
At
$$T = 860$$
 °C, $X = 0 - 30$ mol%

• Poling: 1 -2 mA/cm² at 1200 °C

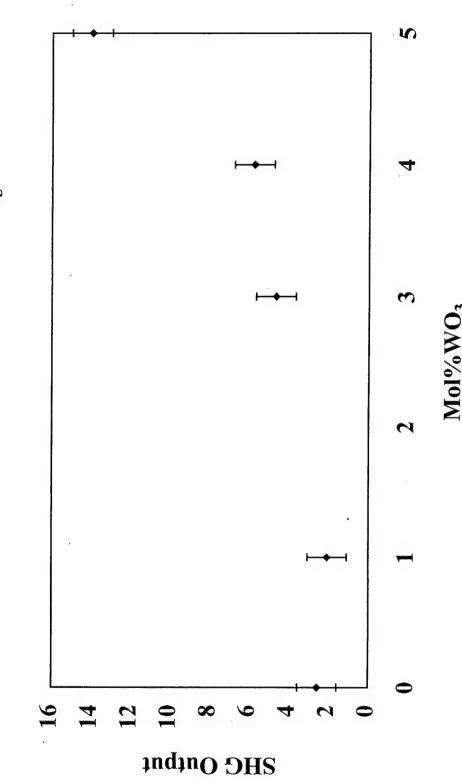
Variation in Powder SHG for LiNbO₃ Doped with Various Concs. of WO₃



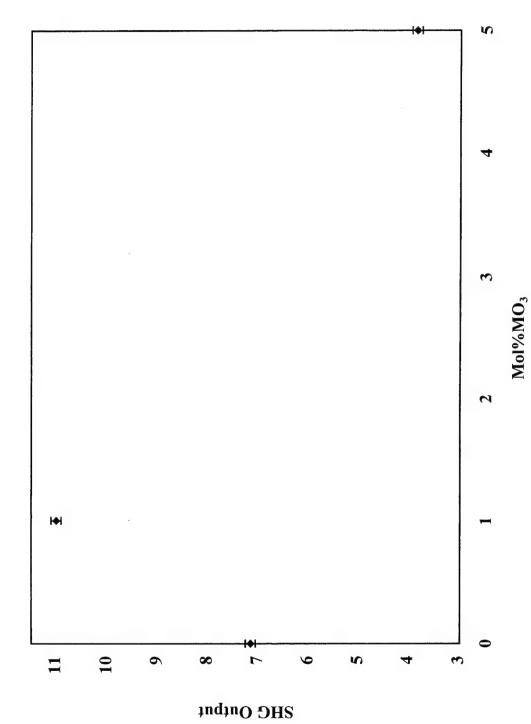
Variation in Powder SHG for LiNbO₃ Doped with Various Concs. of MO₃



Variation of d₃₃ Coefficient for LiNbO₃ Doped with Various Concentrations of WO3



Variation of d₃₃ Coefficient for LiNbO₃ Doped with Various Concs. of MO₃



Conclusions

- The solid solution range for growth of Li_{1-x}Nb_{1-x}W_xO₃ and Li_{1-x}Nb_{1-x}Mo_xO₃ crystals is limited to x = 0.5 due to cracking and constitutional cooling, respectively
- Optical properties vary (linearly?) with concentration of WO₃ and MoO₃
- Further work is required to refine growth conditions and eliminate optical defects
- More detailed optical characterisation is necessary

Growth and Characterisation of Photorefractive Materials

Craig.J. Finnan, H.G. Gallagher, T.P.J. Han.

Optical Materials Research Centre (OMRC),

University of Strathclyde

G. Cook, D. Jones

DERA Malvern

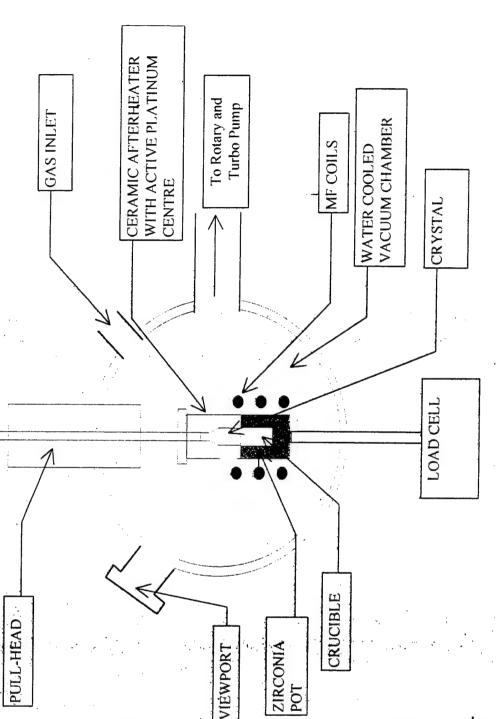


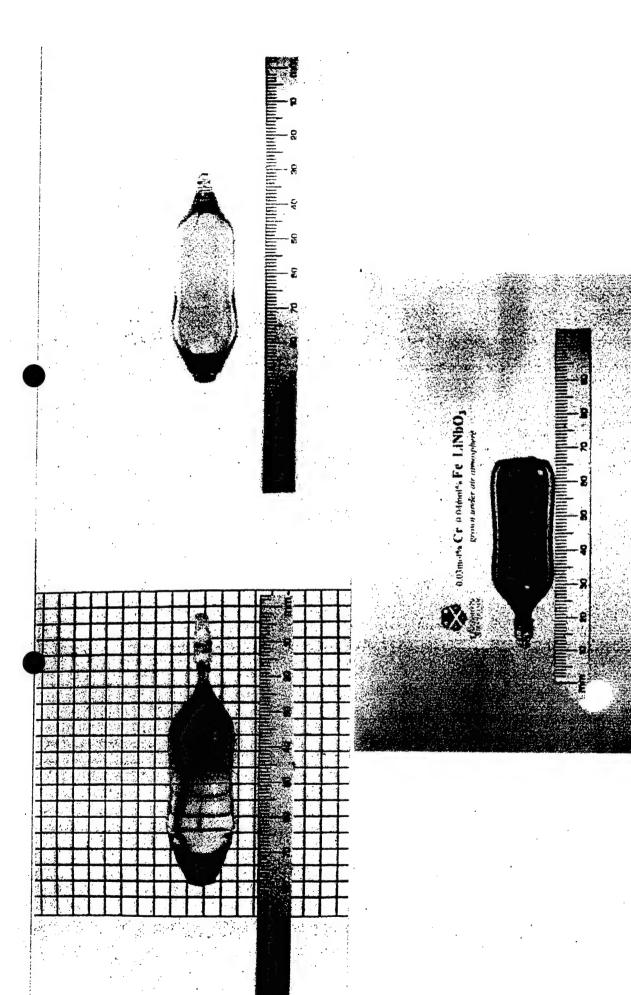




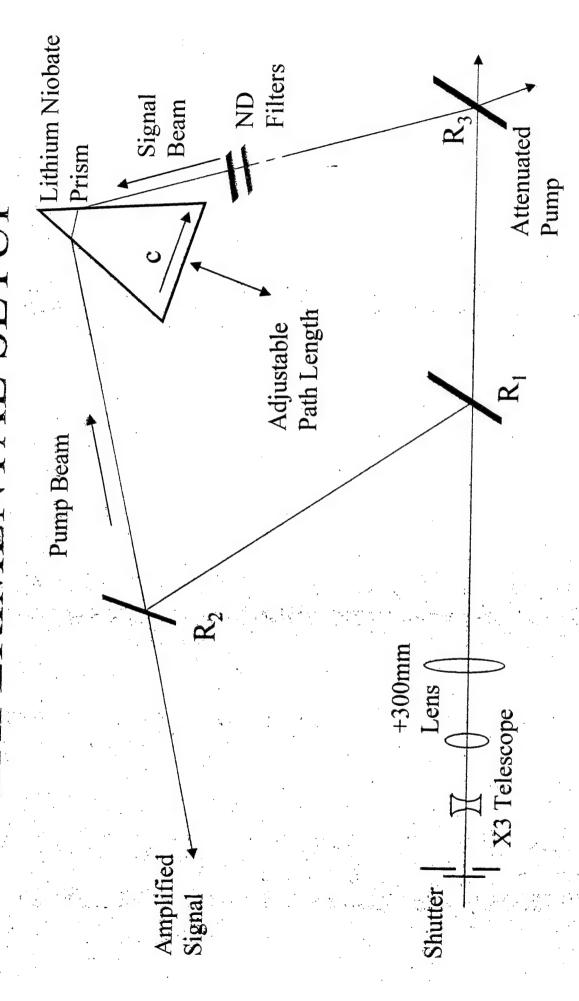
Zochralski Growth Technique

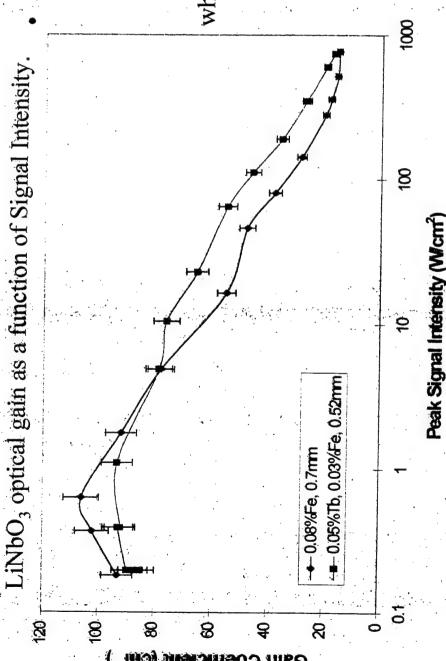
- Both single and co-doped Fe:LiNbO₃ samples have been grown.
- Congruent Lithium Niobate is best grown from a melt by the Czochralski technique.
- ◆ Congruent composition is 48.6mol% Li₂O, 51.4mol% ZIRCONIA Nb₂O₅.
- To reduce thermo-Mechanical Strain, a Platinum Afterheater must be used.
- Surface cracking can occur due to Li,O evaporation.





CPERIMENTAL SET



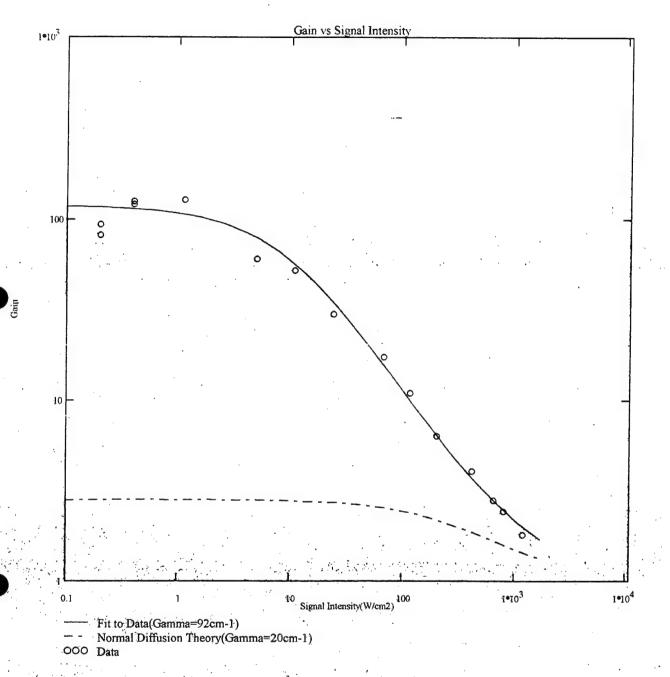


Pump intensity is constant at 1kW/cm².

Gain Coefficient is calculated from,

$$G = \frac{\ln\left[\left(I_{A} - I_{B} \right) \right]}{I_{S}}$$

absence of the pump, and intensity with no pump beam, I_S and I_A are the intensities of the l is the sample thickness transmitted signal beam where I_B is the background in the presence and



Developments in PPLN Fabrication at the ORC

Dr. Peter G.R. Smith

Dr R.W. Eason, Dr. Graeme Ross, Dr. Neil Broderick Prof. D.C. Hanna, Prof. D.J. Richardson Dr. H.L. Offerhaus

Paul Britton, Cowin Gawith, Joyce Abernethy, Ian Barry

- PPLN Fabrication 1mm materialPPLN OPOs and fibre lasers
- Etched PPLN microstructuring
 - HeXLN

PPLN Fabrication 1mm material

DERA Supported Project

Constructed a current controlled poling rig for 1mm samples

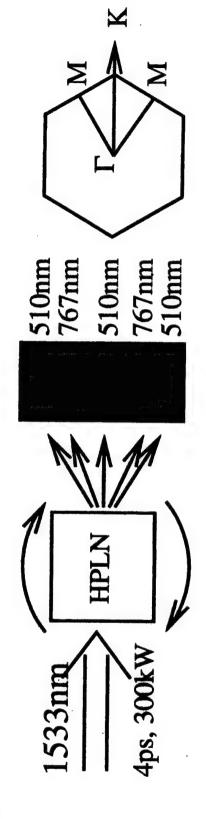
Successfully fabricated 1mm thick PPLN at coarse periods >25 µm.

Issues are breakdown through the material, electrode design, yield.

• Future - how to improve quality, how to improve yield? Can push to 2mm?



Experimental Setup



- A schematic of the experimental setup is shown above. The pulse source is a high power all-fibre CPA source.
- ullet The input pulses were \sim 3ps long with a bandwidth of 2nm and a maximum peak power of 300kW.



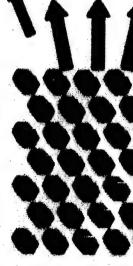
2D patterned PPLN

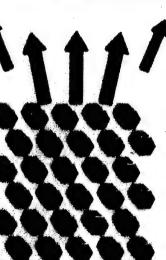


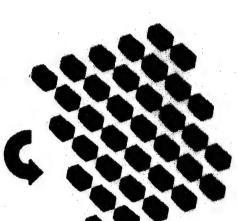
Inverted domains

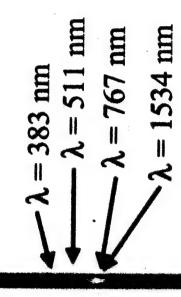


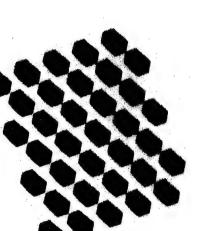
 $\lambda = 1.534 \, \mu m$ 4ps, 300kW

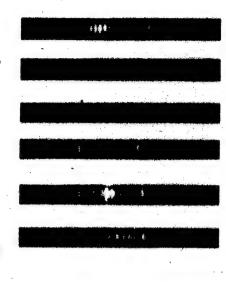












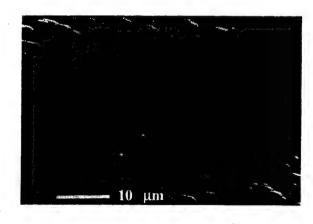


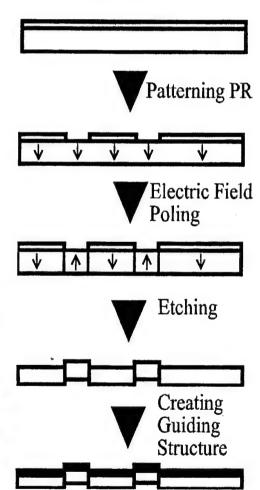
Introduction

- Recently V. Berger [Phys. Rev. Lett. 81, 4136 (1998)] developed the idea of a nonlinear photonic crystal in which the linear refractive index is constant but the nonlinear suspectibility varies periodically.
- We have fabricated such a crystal in Lithium Niobate. Due to the crystal symmetry of LiNO3 our crystal has hexagonal symmetry - hence HeXLN.
- Such a crystal is able to phase-match nonlinear interactions in any direction where there is a suitable reciprocal lattice vector (RLV).
- For certain angles of incident this should result in multiple output beams for a single input beam. Or it could phase-match multiple wavelengths at different angles simultaneously.

Lithium Niobate: differential etching

- +z untouched
- -z etches700nm/hr(room temp.)





Applying PR





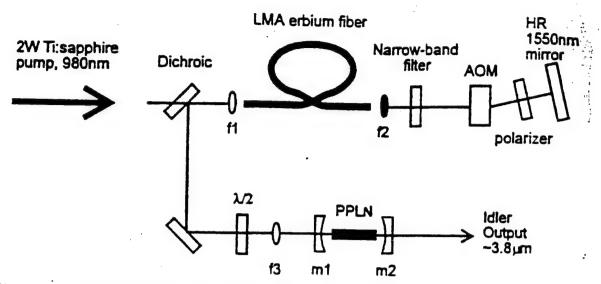


Fig. 1. Schematic of the setup: LMA, large-mode-area AOM, acousto-optic modulator; HR, highly reflecting.

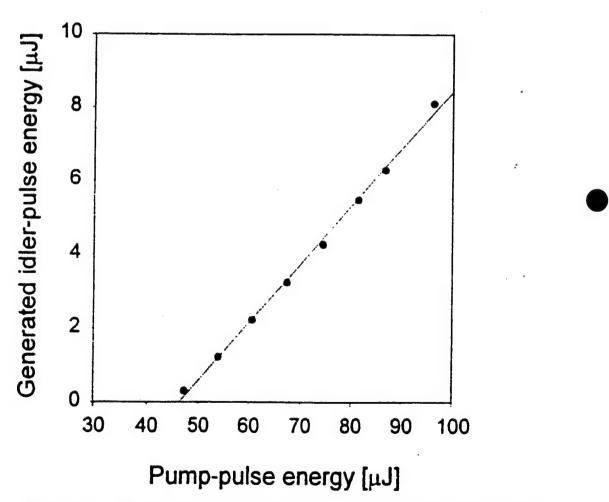


Fig. 2. Energy characteristics of the generated idler output at 2.61 μm .

Oxford Crystal Growth Group



Growth of phosphates and arsenates for periodic poling

K.B.Hutton and R.C.C.Ward

Clarendon Laboratory, Parks Road, Oxford OX1 3PU

- Properties of phosphates and arsenates
- Material requirements for periodic poling
- Growth programme using self fluxes
- Assessment of results

Collaborators

P.A.Thomas, Warwick Univ.

D.C.Hanna, P.Smith, Southampton ORC

M.H.Dunn, St.Andrews Univ.

Acknowledgements

EPSRC, DERA Fort Halstead

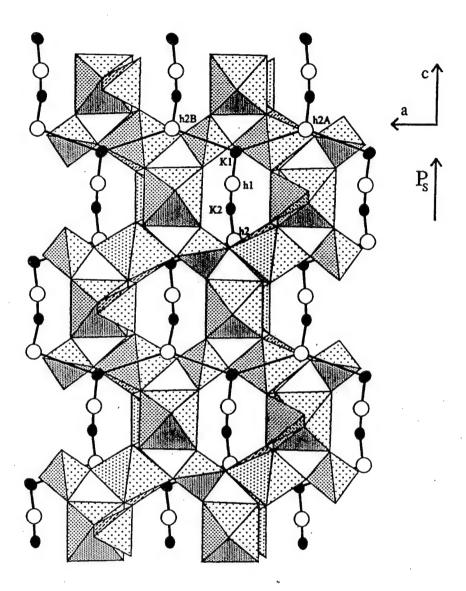
Optical and electrical properties of KTP isomorphs

		КТР	RTP	KTA	RTA
-	Curie point (°C)	946	785	873	750
	Trans. range (μm)	0.35 - 4.3	0.35 - 4.3	0.35 - 5.3	0.35 - 5.3
)	SHG NCPM y cut-off (nm)	994	1038	1075	1138
	1.06 μ m PM φ°	25	60	-	-
	d ₃₃	16.9	17.1	16.2	15.8
	d _{eff} type II, 1.06μm	3.3	2.4	-	-
	ionic conduc ^y 0.1kHz (S/cm)	5x10 ⁻⁷ *	2x10 ⁻⁸	2x10 ⁻⁷	10 ⁻¹¹

^{*} Can be reduced to 2x10⁻⁹ by doping with trivalent ions

Sources:

Cheng et al, J.Crystal Growth 137 107 (1994) Cheng & Bierlein, Ferroelectrics 142 209 (1993)



Crystal structure of K+Ti4+OP5+O4

(from P.A.Thomas & A.M.Glazer, J.Appl. Cryst. 24 968 (1991))



TiO₆ octahedra



PO₄ tetrahedra



Electric field poling of KTP and analogues

- Electric field poling of hydrothermal KTP
 Q.Chen & W.P.Risk, Electron.Lett. 30 1516 (1994)
- Periodic poling of RTA
 H.Karlsson, F.Laurell et al, Electron. Lett. 32 556 (1996)
- Periodic poling of flux-grown KTP with Rb-exchanged layer
 H.Karlsson & F.Laurell, Appl.Phys.Lett. 71 3474 (1997)
- Low-temperature poling of flux-grown KTP
 G.Rosenman et al, Appl.Phys.Lett. 73 3650 (1998)

Advantages of KTP analogues for periodic poling

- Lower poling voltage than LiNbO₃
- Highly anisotropic crystal structure inhibiting domain broadening
- Stable device operation due to small dn/dT

Growth of KTP analogues for periodic poling

Objectives

- 1. Production of high-quality, flux-grown KTP for poling trials
- Investigate methods of lowering conductivity of KTP
 Doping Ga³⁺ (ref: Morris et al, J.Cryst.Growth 109 367 (1991))
 Ce⁴⁺ (correlation with increased transmission?)
 Rb⁺ (ref. RTP properties)
- 3. Establish UK source of KTA and RTA

 Extended IR transmission and inherently low conductivity (RTA)
- 4. Investigate in-situ poling techniques

Growth methods

TSSG method using self fluxes $NH_3H_2P(As)O_4 + K(Rb)_2CO_3 + TiO_2$

Synthesis of high-purity arsenate starting material

Production of arsenate seed crystals by spontaneous nucleation

Optimisation of growth conditions

flux composition, growth temperature, doping

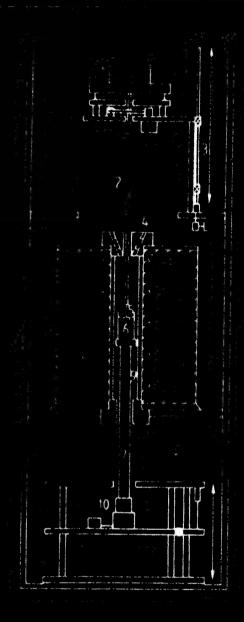


Fig. 1 Top Weighing TSSG Furnace

- Electronic Balance
- Piectronic Balance
 Seed Rod
 Vertical Adjustment Stages
 Optical Windows
 Seed Crystal
 Platinum Crucible
 Alumina Crucible Support Rod
 Three Zone Furnace
 Silien Linux

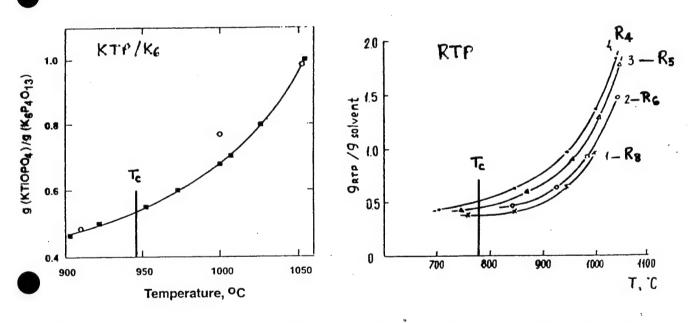
- Silica Liner
 ACRT Motors

Self fluxes for KTP and analogues

Polyphosphate K₂O − P₂O₅ solvents :

K_2O / P_2O_5	Flux	·
2	K4P2O7	Corresponding
1.67	K5P3O10	Rb and As analogues.
1.5	K6P4O13	
1.33	K8P6O19	

Solubility curves for KTP/K₆ and RTP/R_n



Ref: Angert et al, J.Cryst.Growth 137 116 (1994)

Ref: Oseldchik et al, J.Cryst.Growth 125 639 (1992).

Viscosity

KTP/K₆ – viscosity increases from 75cP at 950°C to 300cP at 800°C
 High viscosity and flat solubility curve set limits for very low temperature growth

Results to date of growth programme

- Undoped KTP, Ga:KTP, Ce:KTP
 Routine production of large crystals (≈100g) established
- Rb-doped KTP

5, 10, 20 mol% concentrations, growth temp. $\approx 860^{\circ}\text{C}$ Growth rate low along a-axis Quality appears higher than undoped KTP

RTP crystals

Growth along a-axis enhanced (a:b:c≈1:1:1)
Melt very viscous at 830°C - higher temp. under test

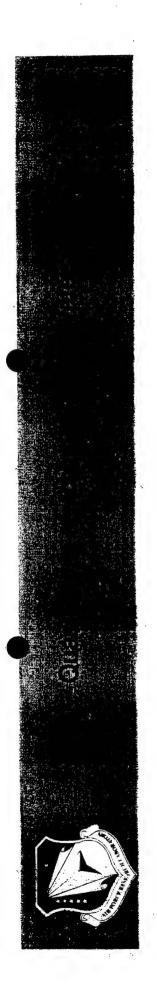
Arsenates

Synthesis of starting materials established

KTA run in progress (886°C using K₆ flux) Volatility of solution higher than KTP

RTA - small crystal grown at 893°C(R₅) to provide seeds Evidence that *a*-axis growth enhanced in arsenates

NLO 99



Shekhar Guha and Chris Reyerson*
AFRL/MLPJ
Wright Patterson Air Force Base, OH 45433-7702
* Anteon Corporation

shekhar.guha@afrl.af.mil

NLO99 Workshop, DERA, Malvern, UK, 20 - 21 September, 1999



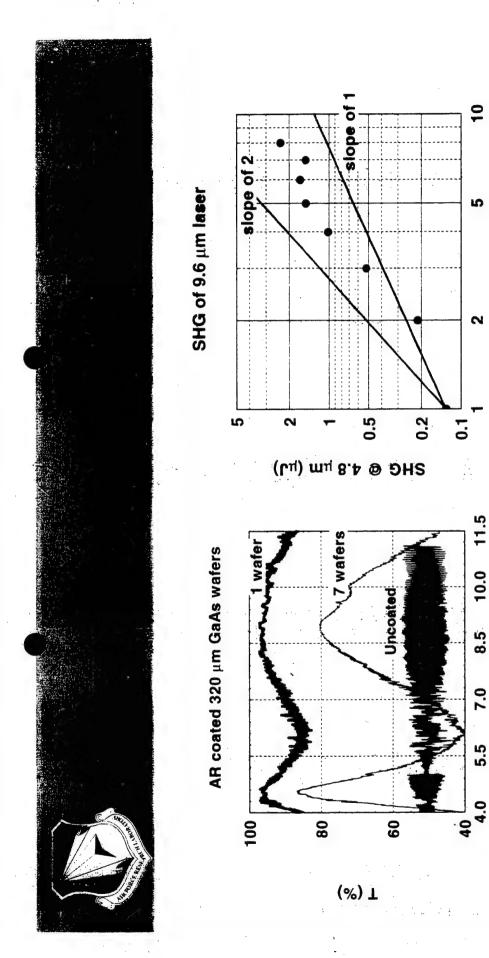
AR coating wafers:

- 1. Coating 2 inch diameter single wafer, dicing in oriented pieces and stacking three coherence length thickness 320 micrometers
- 2. Growing 100 wafers 1 inch diameter, three coherence length thick Then IR AR coating at 5.3 and 10.6 micrometer

Results:

- Up to 5 μJ of MWIR energy generated
- 2. Saturation of generated power observed

Possible causes of saturation being investigated



SHG is not increasing quadratically

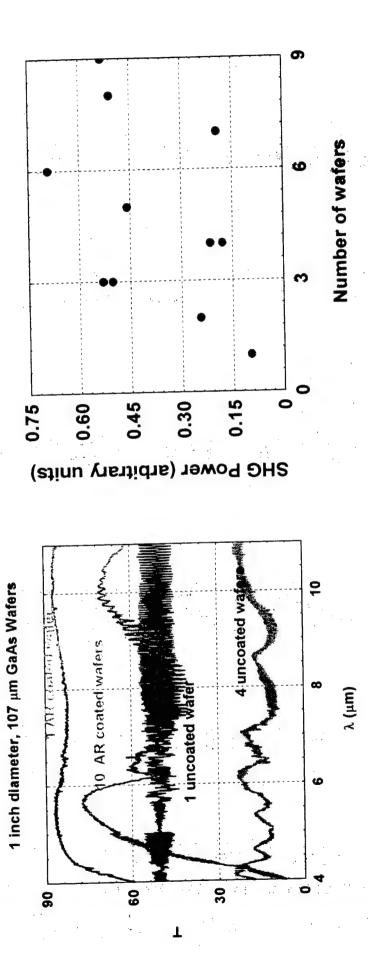
Number of wafers in the stack

γ (hm)

Saturation of generated signal



1 Coherence length each



Worse SHG performance



FOM ₁ FOM ₂	2.5 633	2.4 9333	1 867
dn/dT	1.5	0.64	0.5
α	0.01	5 x 10 ⁻⁴	0.001
¥	55	18	6.3
2	3.3	2.4	2.7
qett	61	37	28
	GaAs	ZnSe	CdTe

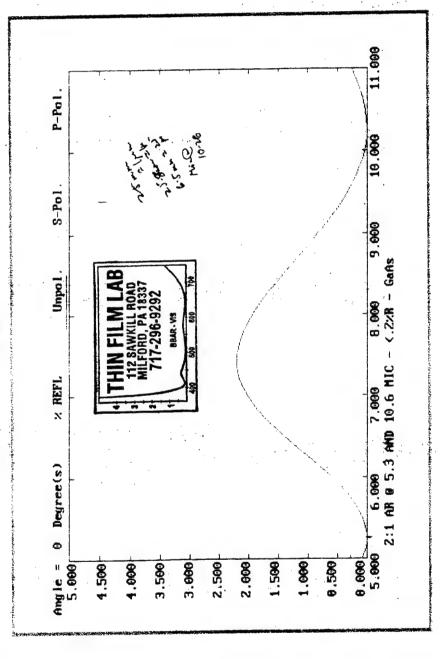
ZGP	70	3.1	35	0.1 (1996)	1.7	4	55
CGA	154	3.5	4.2	0.2 (1996)	5	13.5	ro
AgGaSe ₂	27	2.6	-	0.01	0.7	-	

FOM₁ =

d: pm/V K: W/m/K α: cm⁻¹ dn/dT: 10⁻⁴ K⁻¹

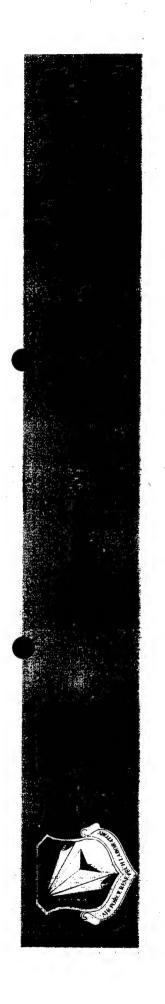
 $FOM_1 = \frac{d^2}{n^3} \times \frac{K}{\alpha \text{ (dn/dT)}}$

1 coherence length (106 \pm 10 μ m)



Very low reflectivities shown at 5.5 and 10.26 μm





AR coating GaAs for efficient QPM SHG of CO_2 laser was attempted

Coating performance still not adequate

Material: Periodically-Poled A New Nonlinear Optical Barium Titanate (PPBT)

P. G. Schunemann, S. D. Setzler, T. M. Pollak

SANDERS

A Lockheed Martin Company

Workshop, (NLO 99), DERA, Malvern, UK, Sept. 21, 1999 Presented at the 1999 Nonlinear Optical Materials

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Periodically-Poled Barium Titanate

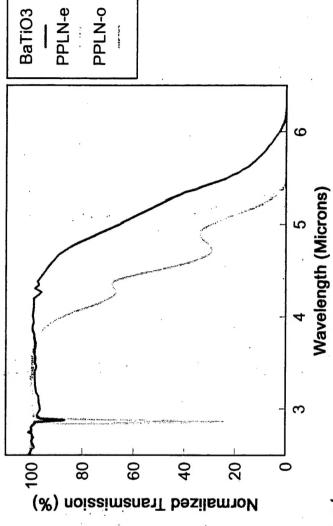


Advanced Engineering and Technology Division

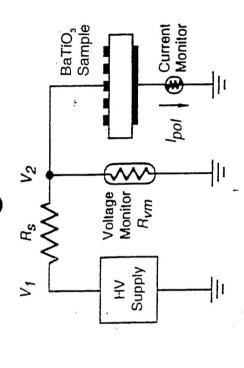
BaTiO₃ Offers Very Attractive Properties for Periodically-Poled OPOs

- Longer IR cut-off than PPLN (allowing full 3-5 micron coverage)
- Low Coercive Field (100V/mm, 200x lower than PPLN)

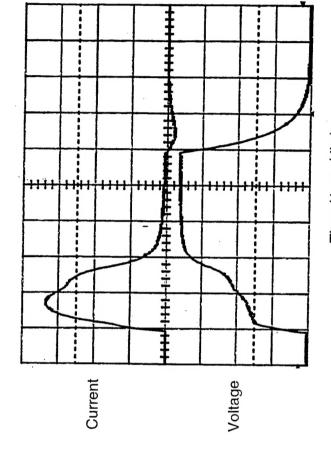




Large Nonlinear Coefficient d₁₅=17pm/V



Liquid Electrolyte

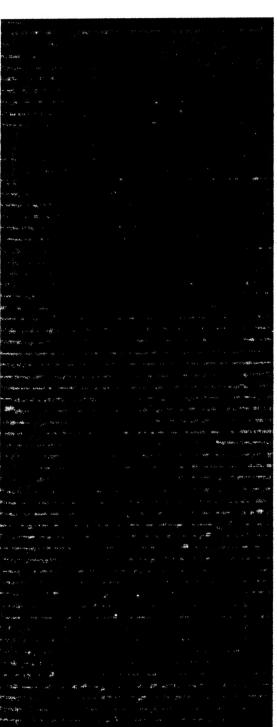


BaTiO, Sample +z

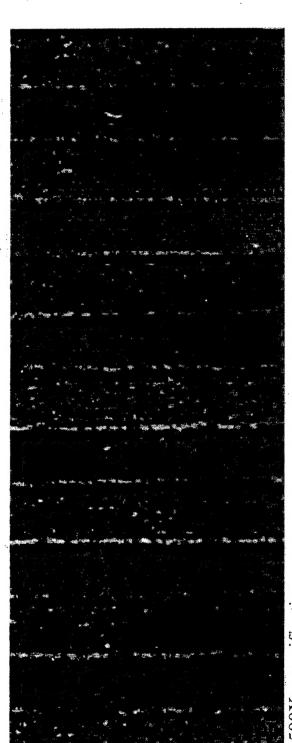
O-Ring.

Time (1 sec/div.)

Images of sample #296G (Total poling depth ~0.5 mm)



150X magnification



1500X magnification



Periodically-Poled Barium Titanate



Summary

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- Barium Titanate single crystals were grown by the TSSG technique
- New refractive index measurements revealed insufficient birefringence for phase-matching, allowed determination of QPM grating spacings
- Periodic poling of bulk BaTiO₃ successfully demonstrated for the first time
- Wafers survived photoresist patterning and bake-out
- Domain reversal achieved at low E-fields (200X lower than for PPLN)
- Mask grating pattern reproduced on wafer (no spreading of domains under photoresist unless overpoled)
- Large thickness (1.4 mm) poled in first trial
- Quasi-phase-matched SHG demonstrated in PPBT
 10W of 2.05um input (10kHz, 10ns) produced 360mW at 1.025um from an uncoated, 8mm-long sample at ~55˚C (4% conv. eff. after refl. loss)
- No evidence of photorefractive damage or thermal lensing was observed